

- [54] **SPEED PATTERN GENERATOR FOR
ELEVATOR SYSTEMS**
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- [73] Assignee: **Westinghouse Electric Corporation**,
Pittsburgh, Pa.
- [22] Filed: **May 17, 1972**
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- [52] U.S. Cl. **187/29 R**
- [51] Int. Cl. **B66b 1/30**
- [58] Field of Search **187/29**

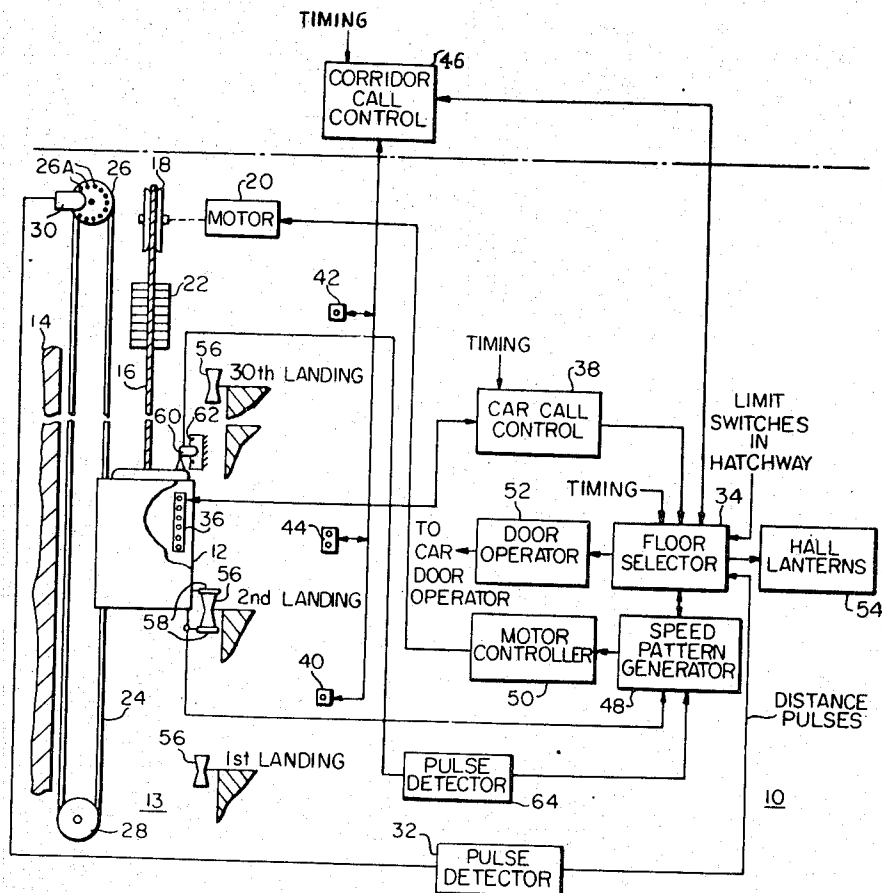
- [56] **References Cited**
- UNITED STATES PATENTS**
- | | | | |
|-----------|---------|----------------------|--------|
| 3,523,232 | 8/1970 | Hall et al. | 187/29 |
| 3,526,300 | 9/1970 | Ferrot | 187/29 |
| 3,627,080 | 12/1971 | Yuminaka et al. | 187/29 |

Primary Examiner—Bernard A. Gilheany
Assistant Examiner—W. E. Duncanson, Jr.
Attorney—A. T. Stratton et al.

[57] **ABSTRACT**

A speed pattern generator for elevator control which provides a time dependent speed reference pattern, with control over maximum jerk directly incorporated into the pattern itself. The speed pattern is developed by starting with a step signal whose two magnitudes determine maximum jerk. The specific magnitude of the step signal which is selected, and time spent at each magnitude of the step signal is determined by acceleration and speed feedback circuits. The step or jerk signal is integrated to provide an acceleration signal, and the acceleration signal is integrated to provide a speed pattern signal which, regardless of how fast the elevator system responds thereto, positively limits the maximum jerk.

17 Claims, 23 Drawing Figures



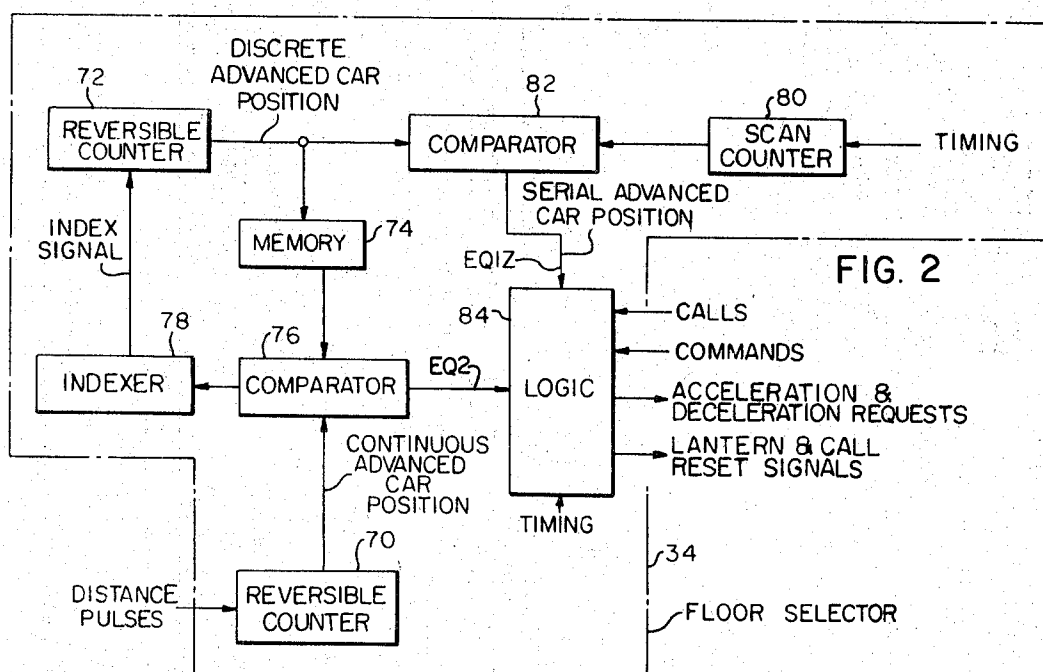
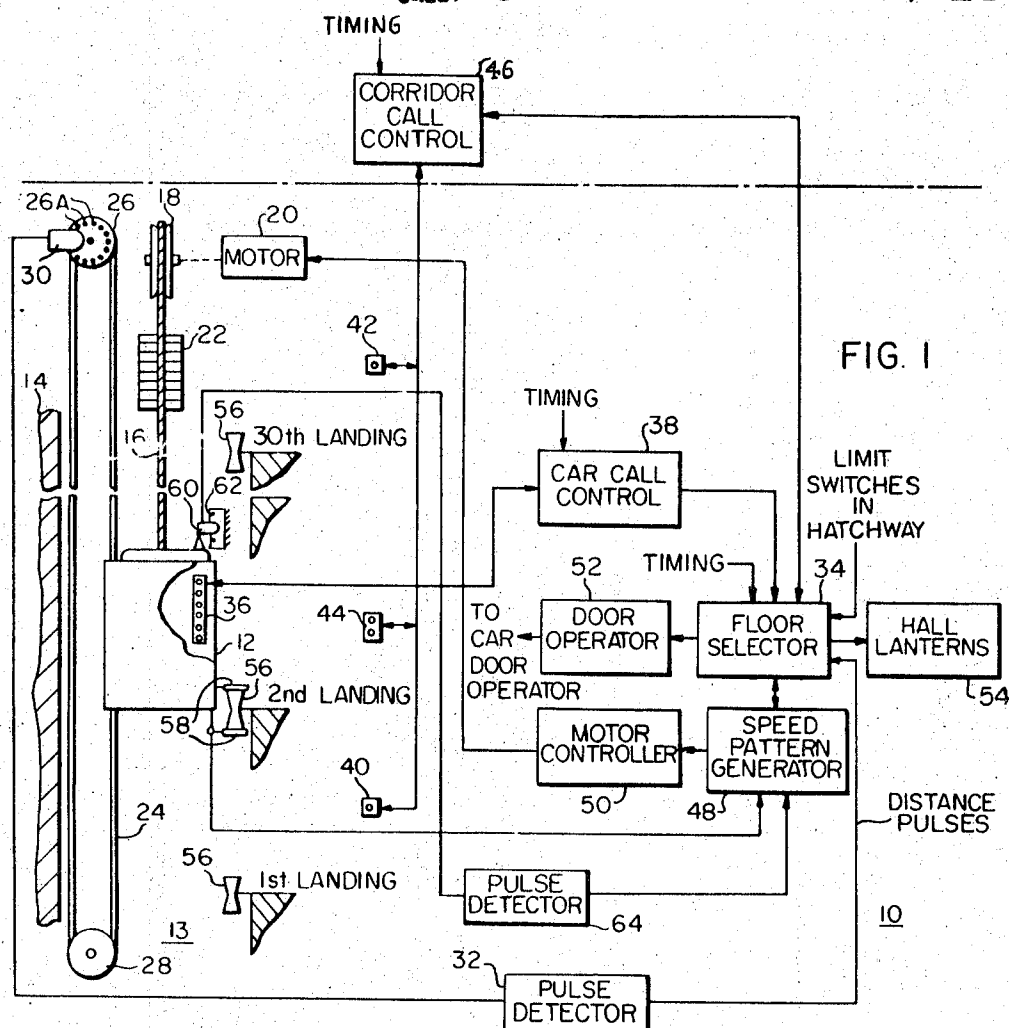
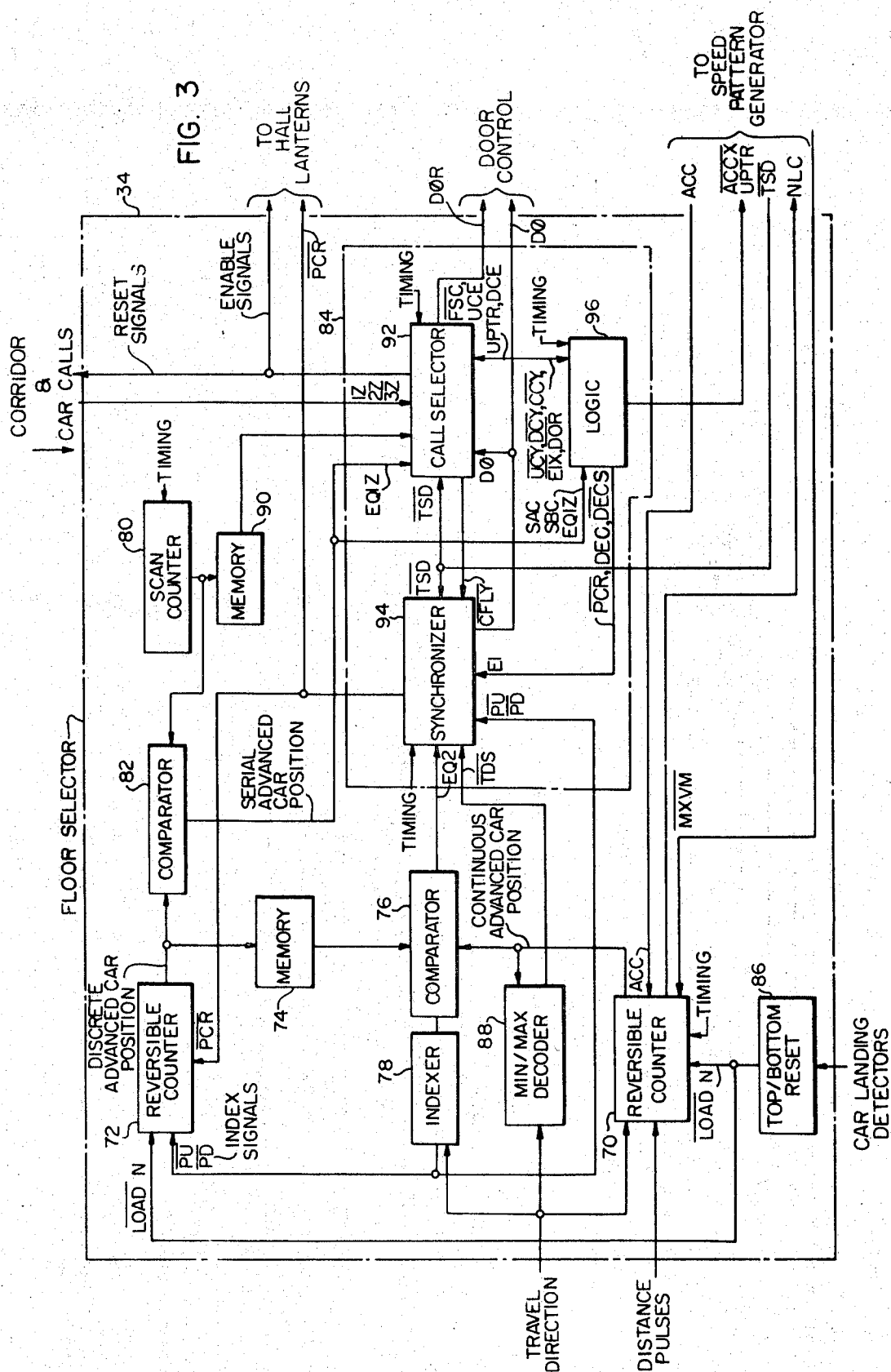


FIG. 3



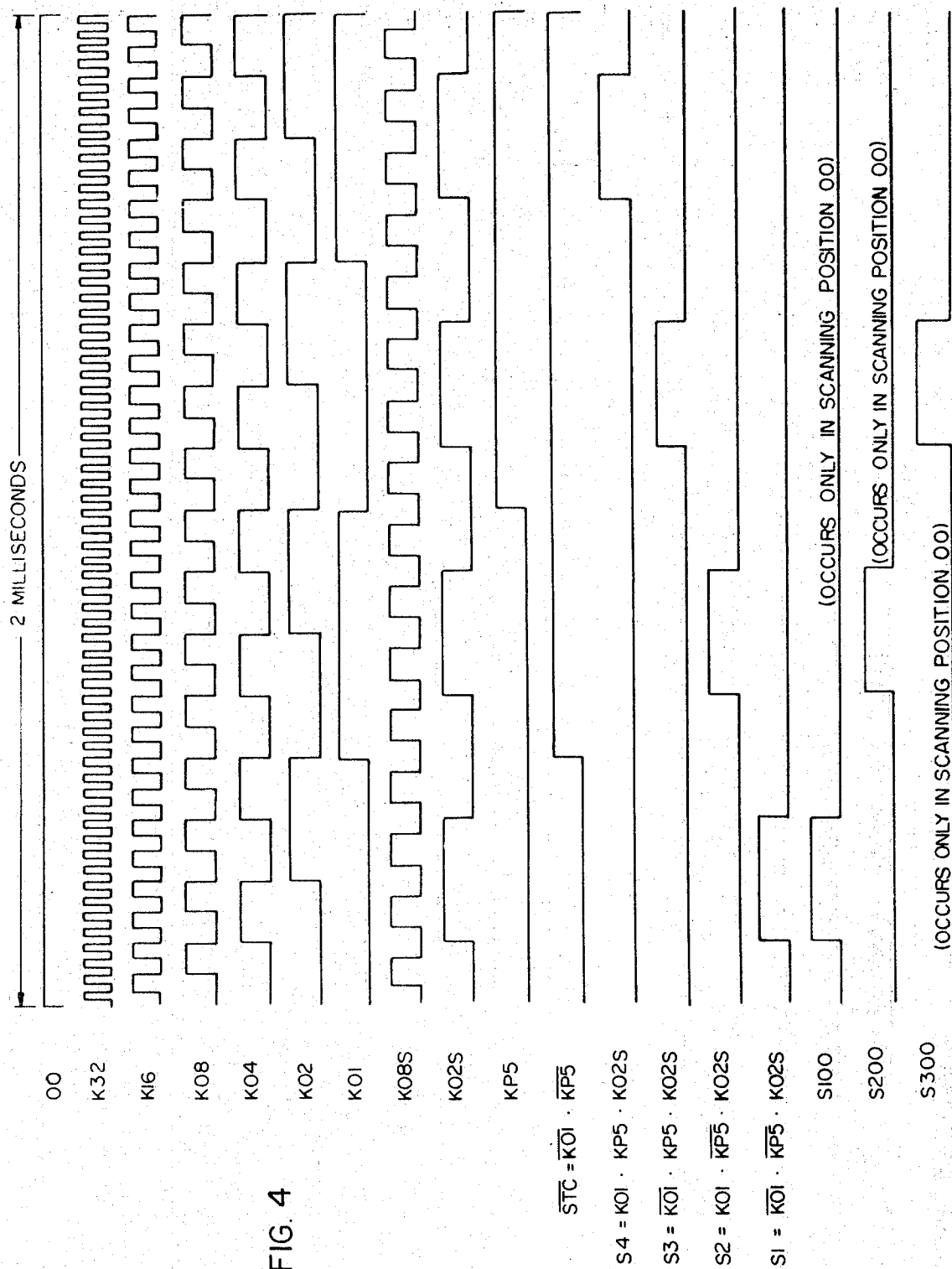
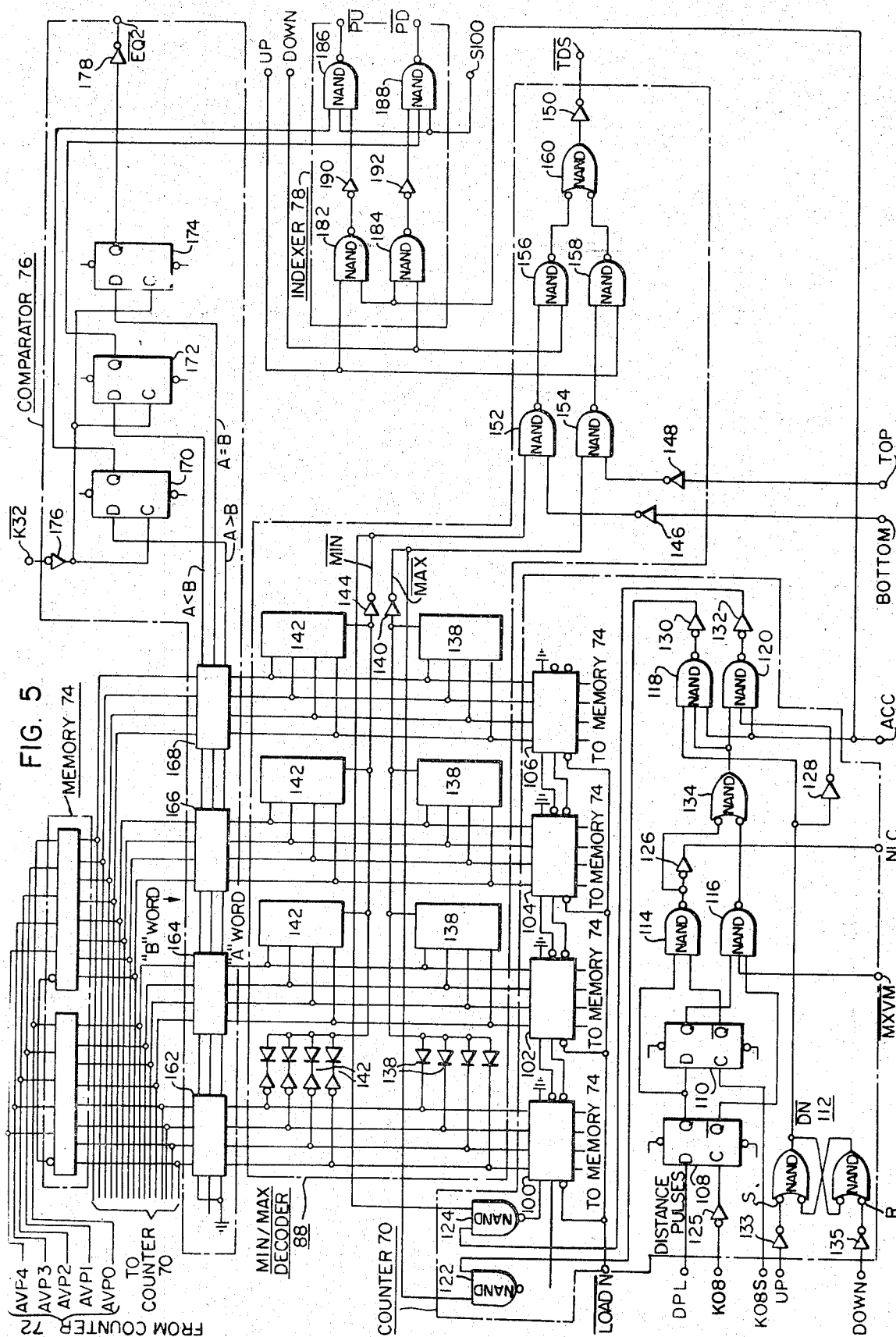


FIG. 4



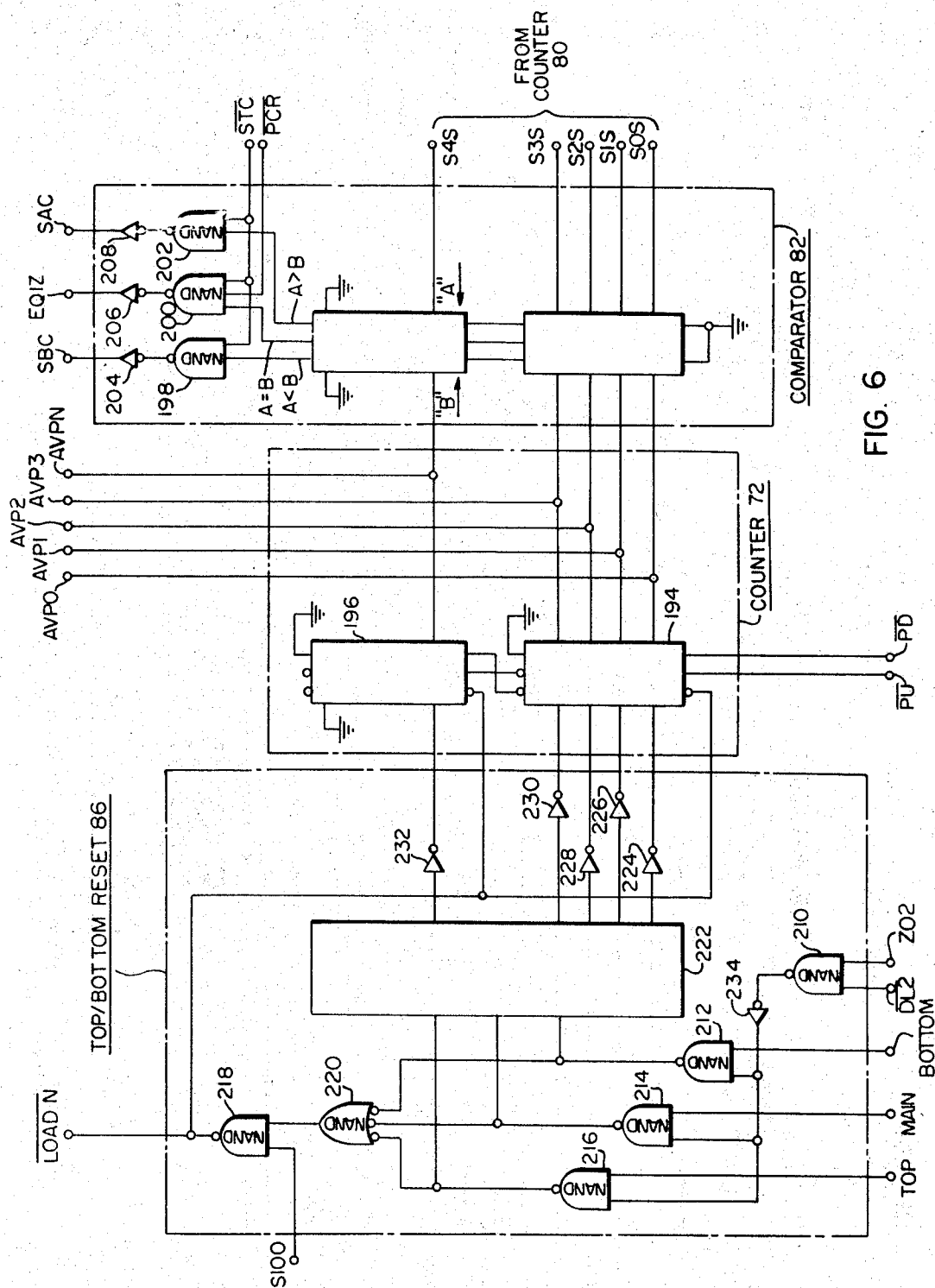
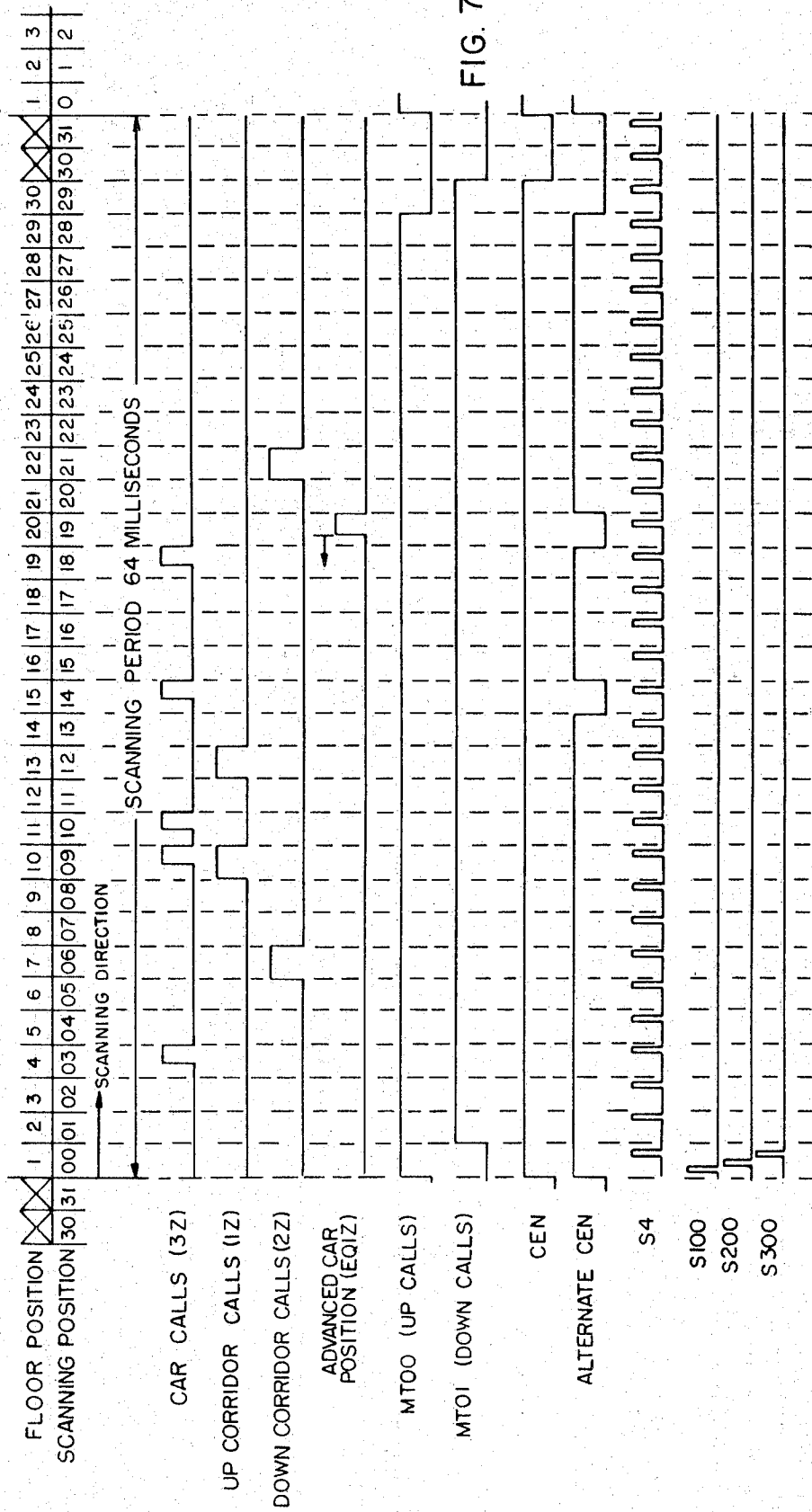


FIG. 6

TIMING DIAGRAM FOR 30 FLOOR BUILDING



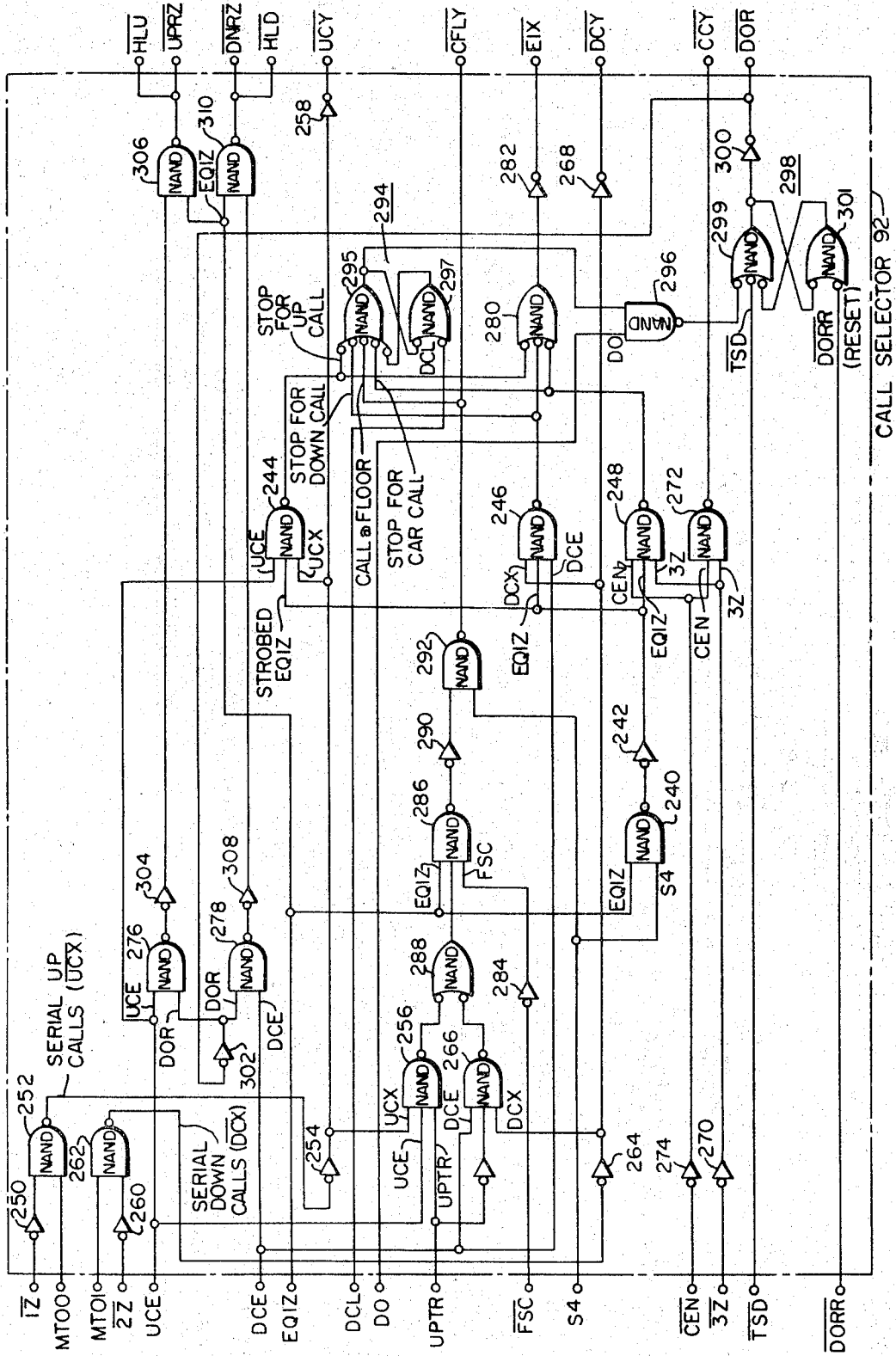
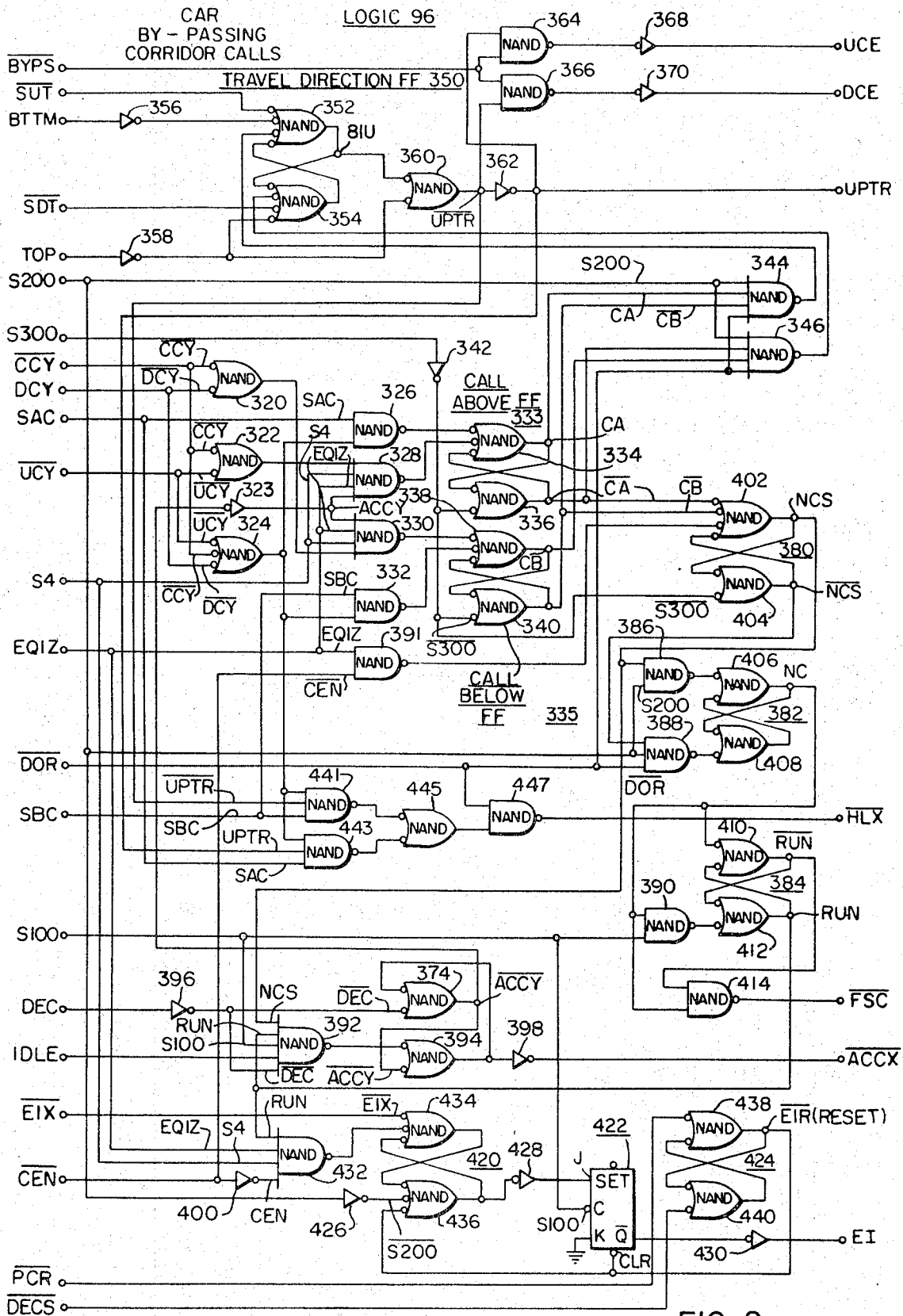


FIG. 8



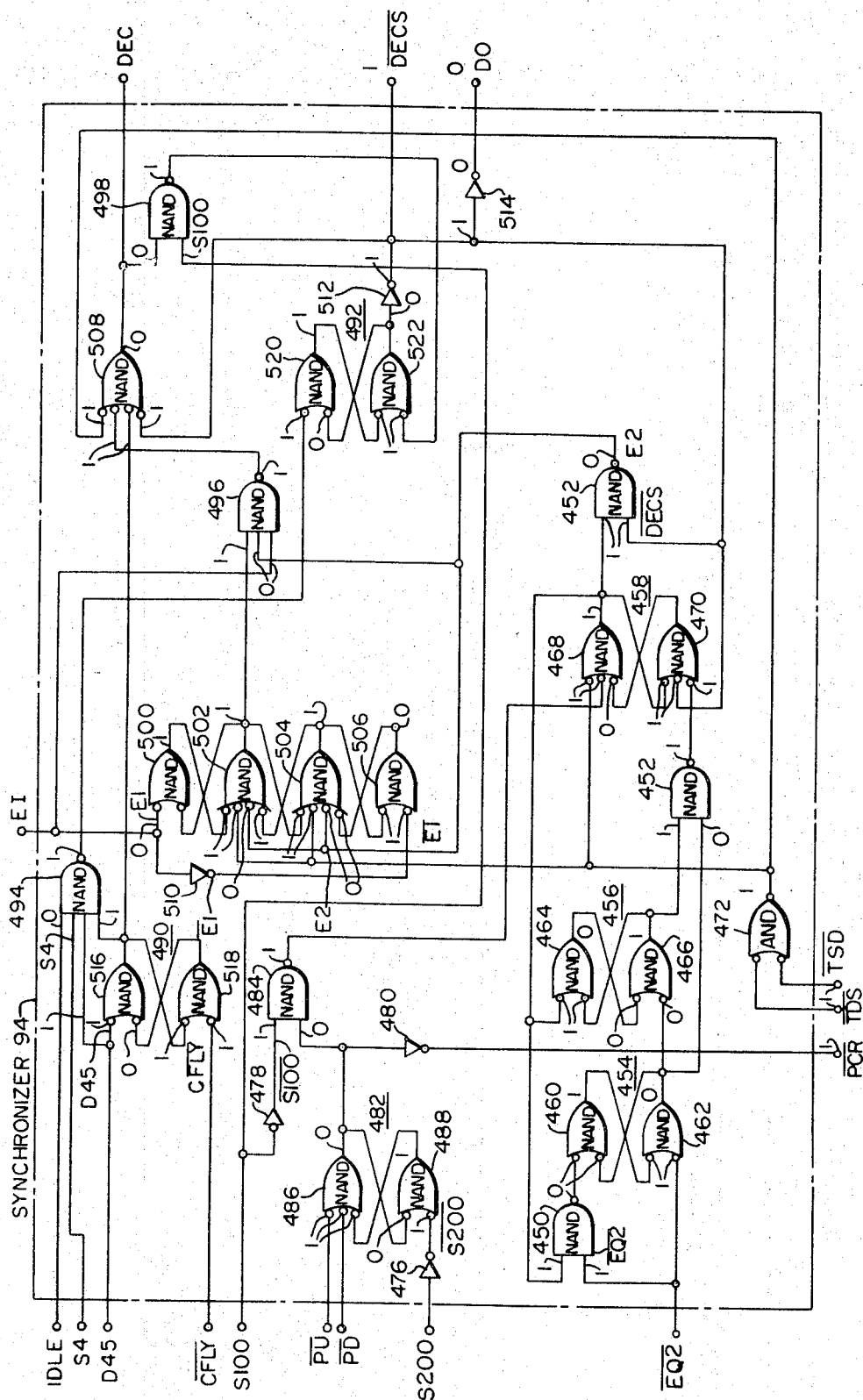
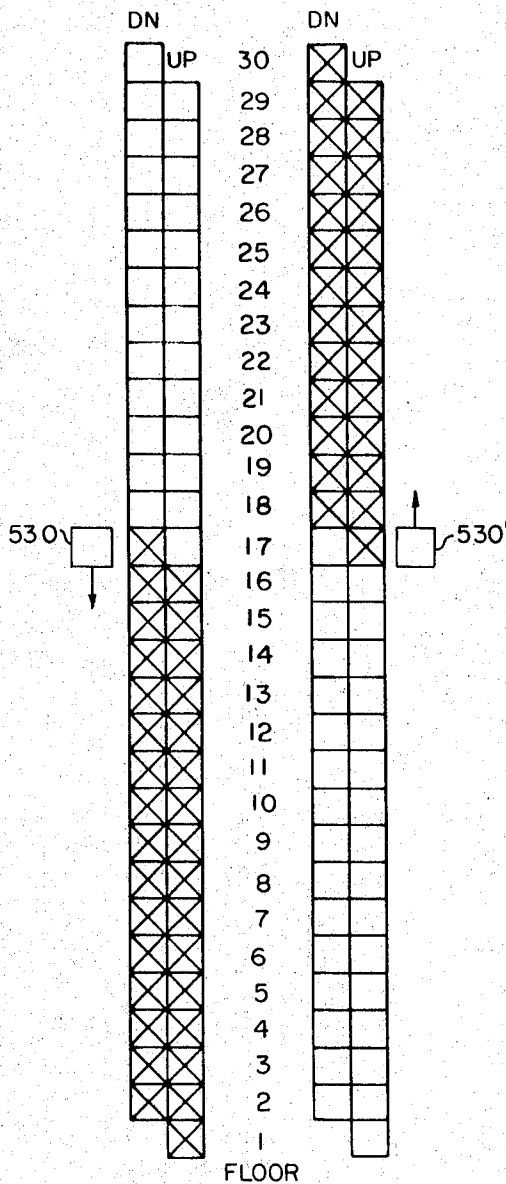


FIG. 10



CORRIDOR CALLS CAR CAN
CONSIDER WHEN TRAVELLING
IN A GIVEN DIRECTION

FIG. 11

FIG. 12

SPEED PATTERN GENERATOR 48

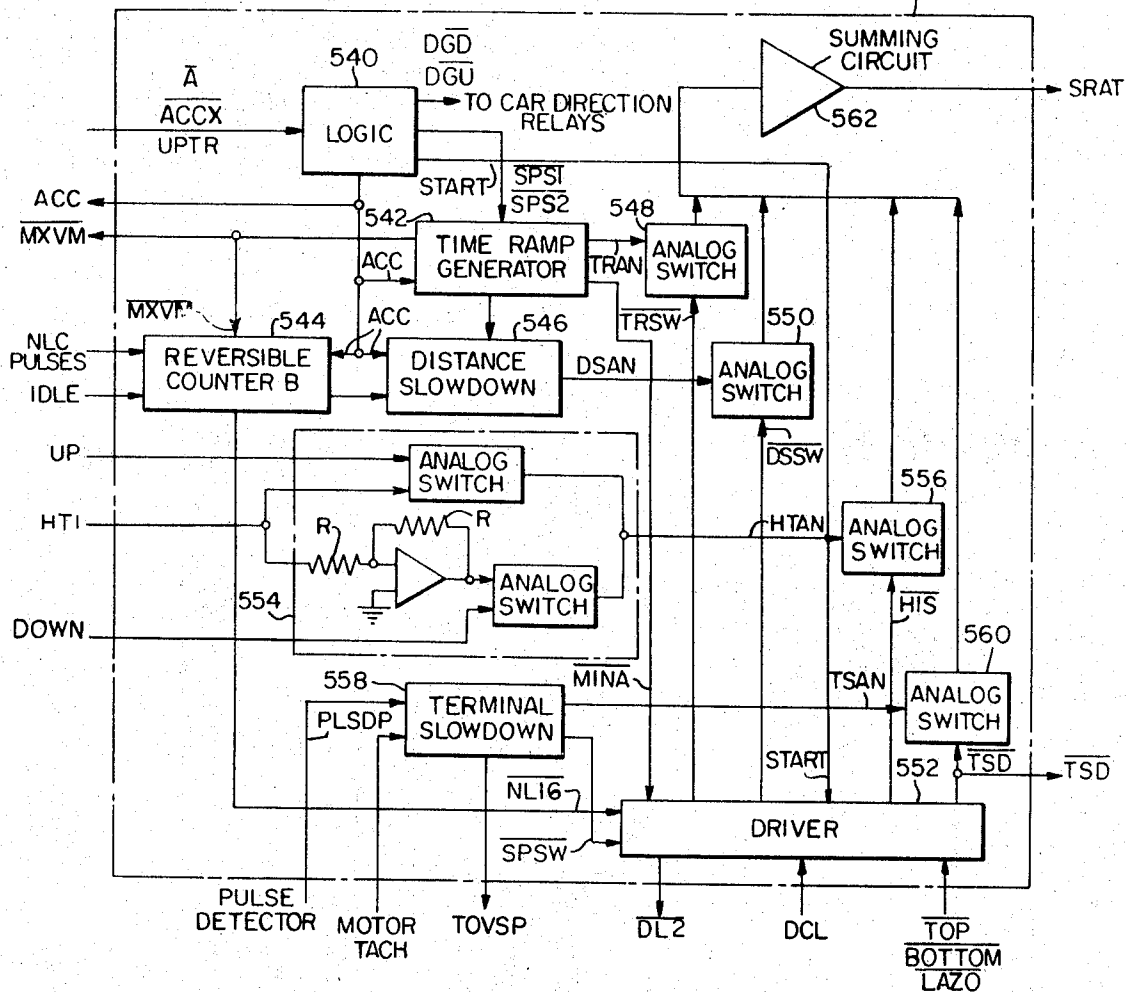
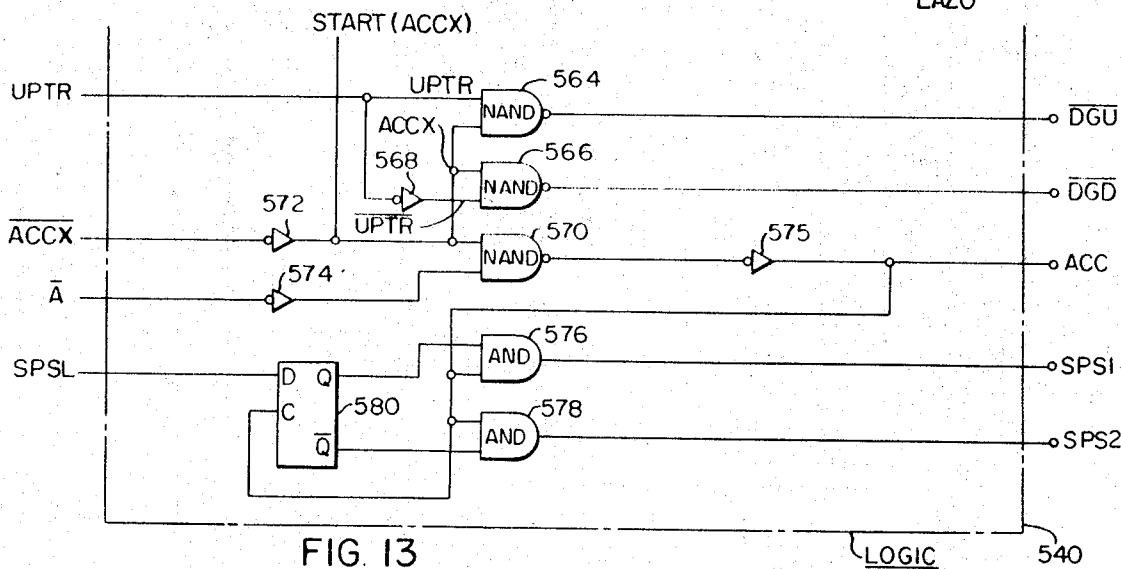
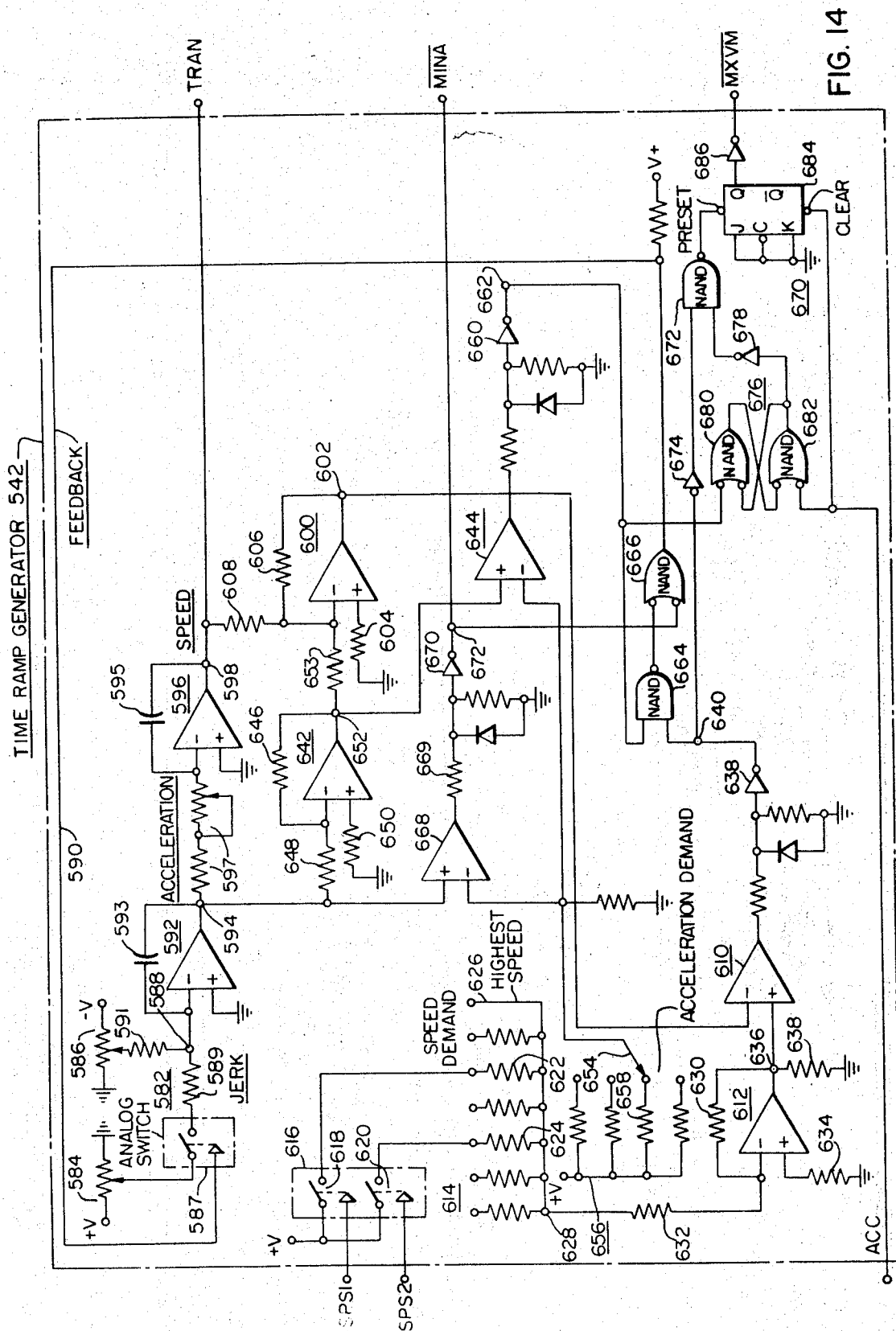


FIG. 13

LOGIC

540





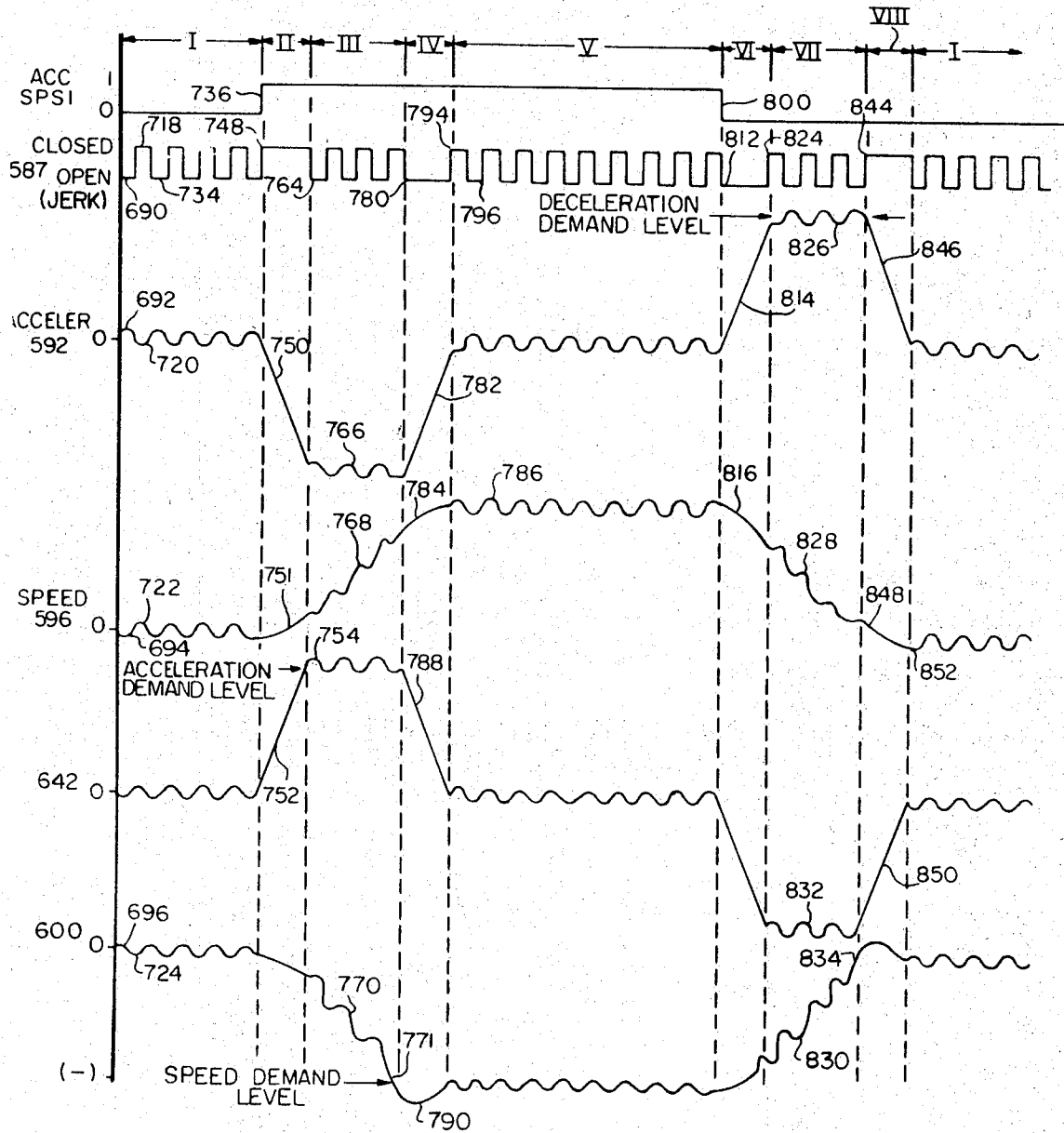


FIG. 15A

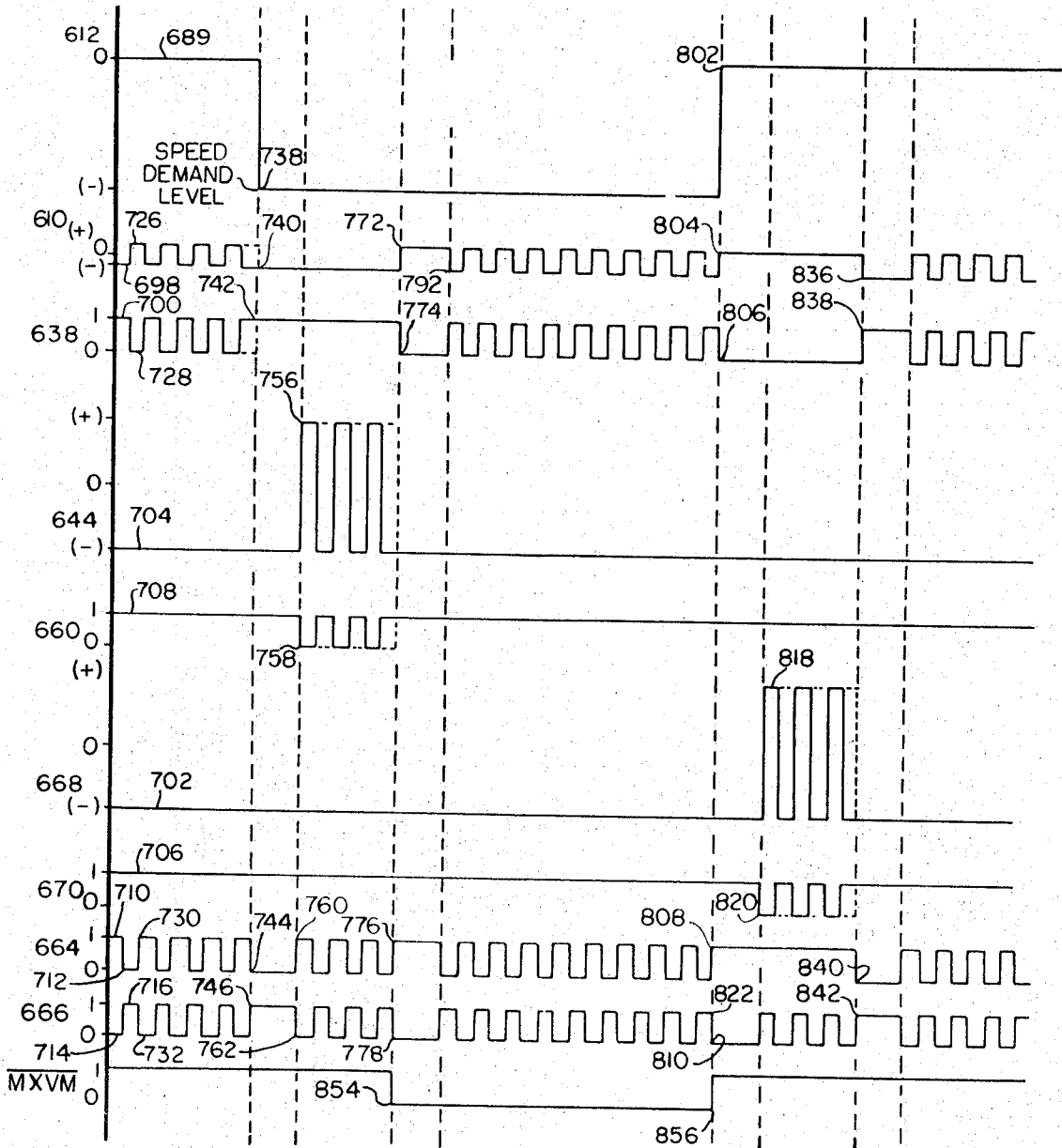


FIG. 15B

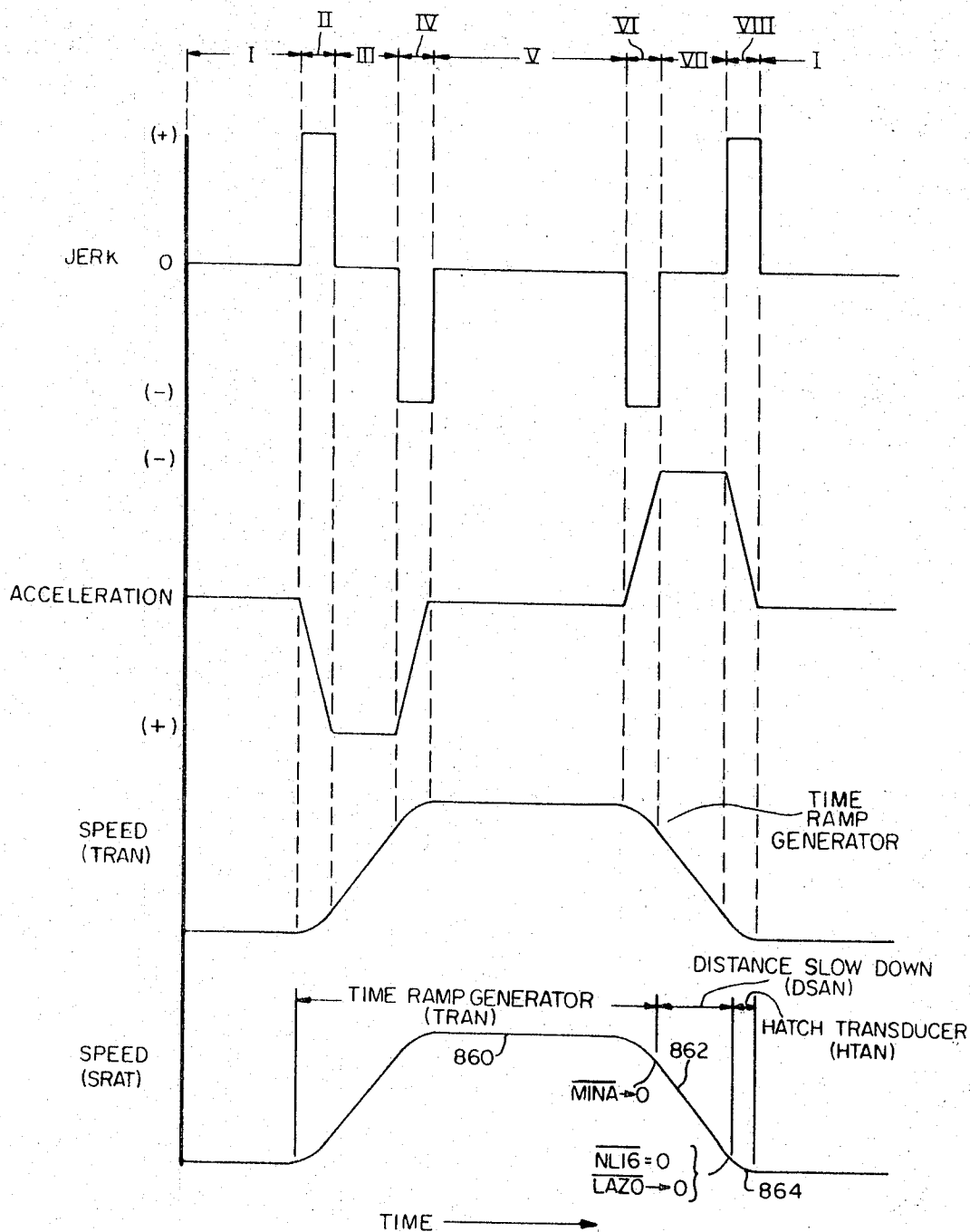


FIG. 16

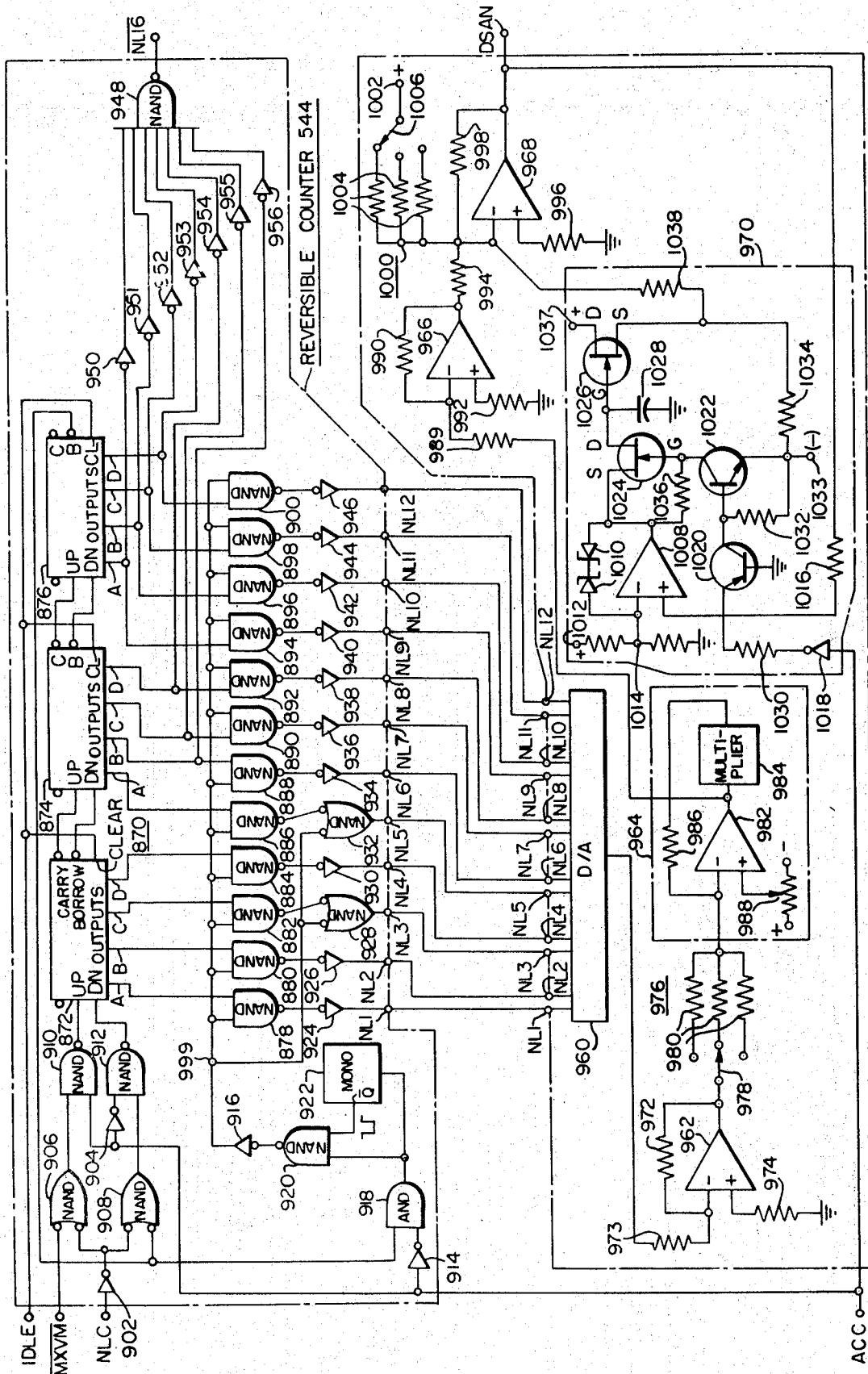
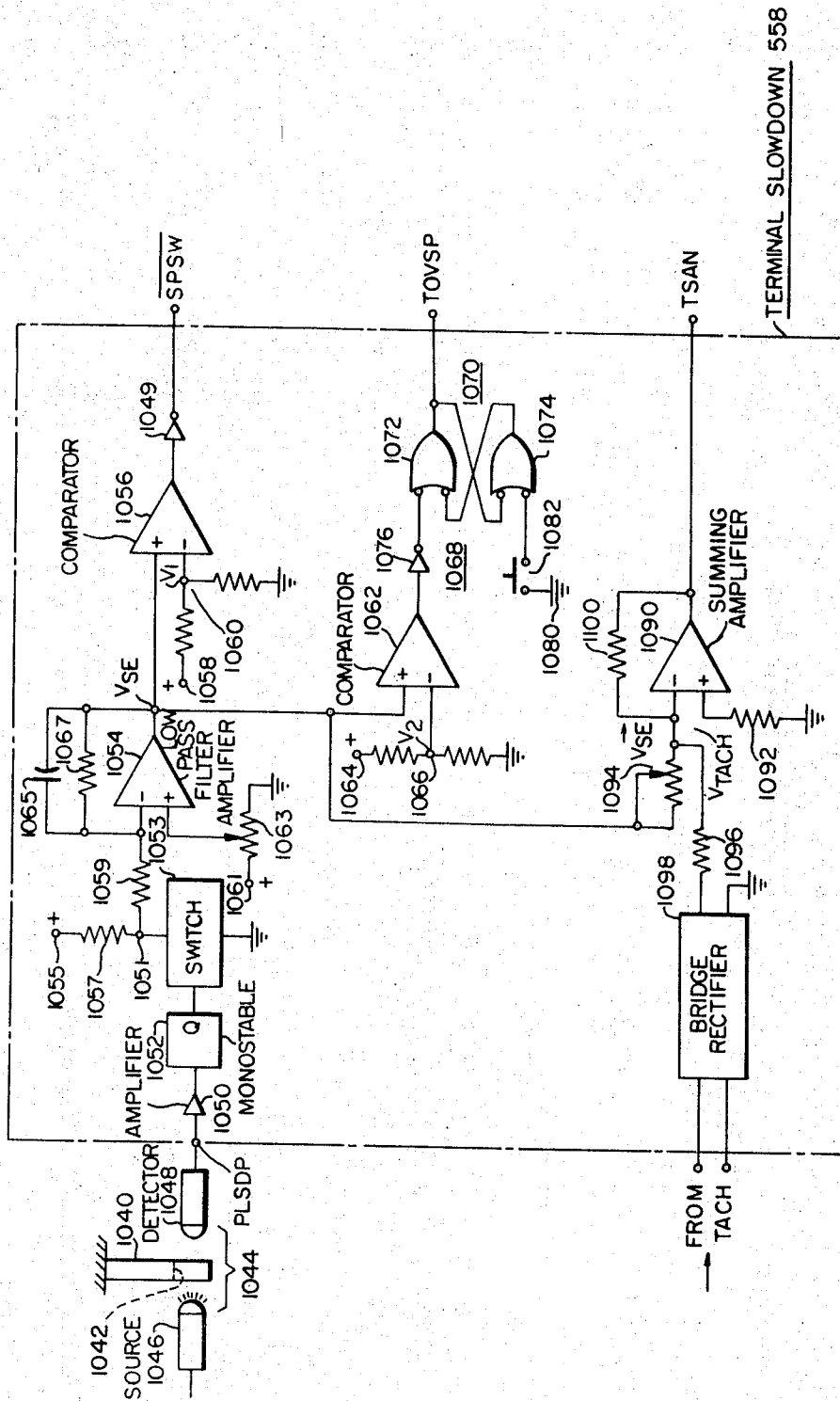


FIG. 17

DISTANCE SLOW DOWN 546



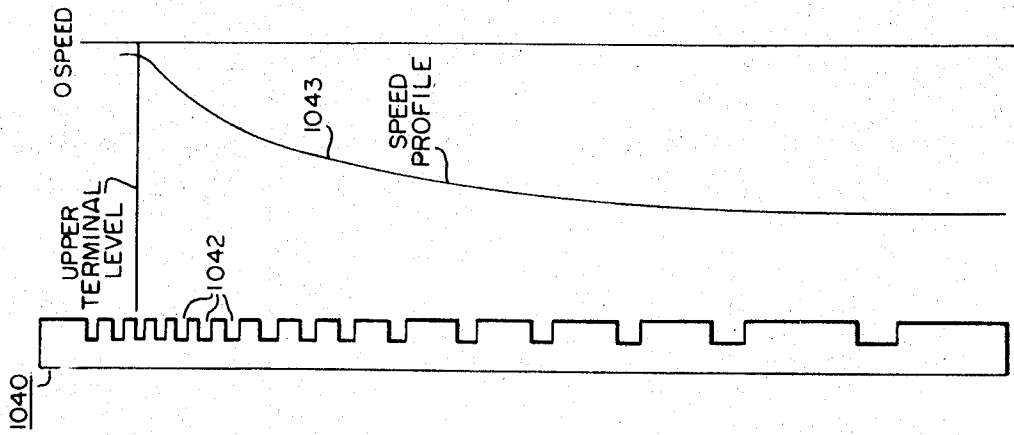


FIG. 19

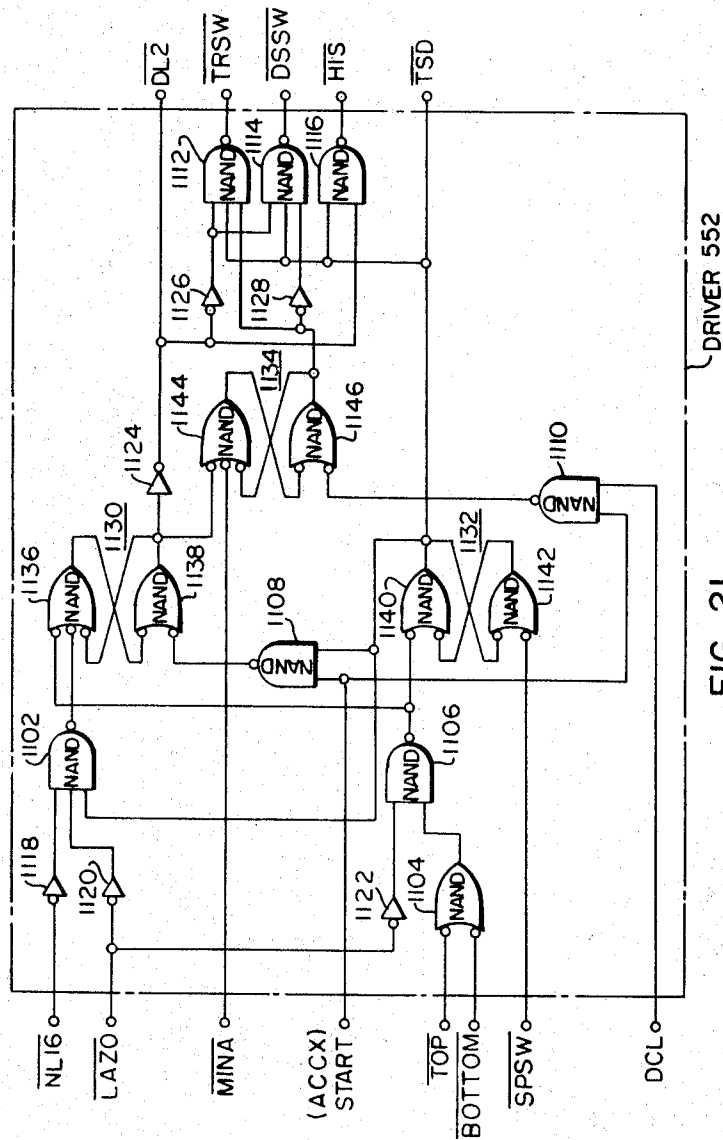


FIG. 21

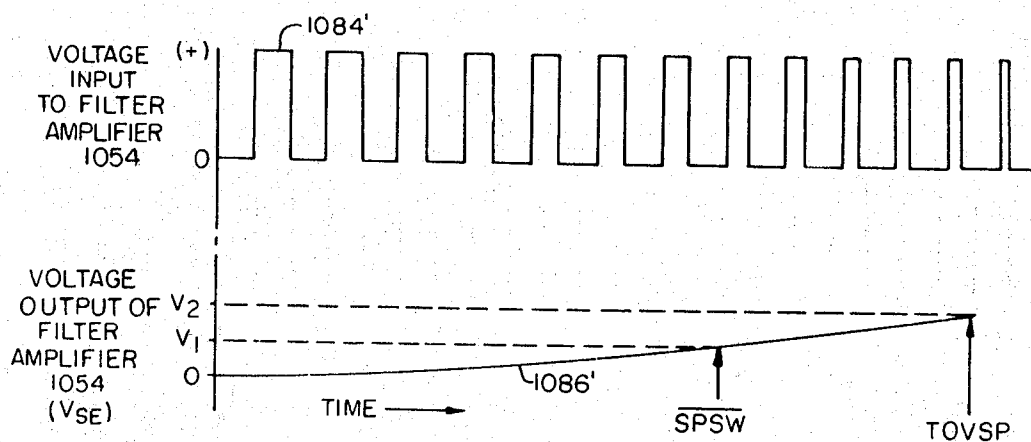
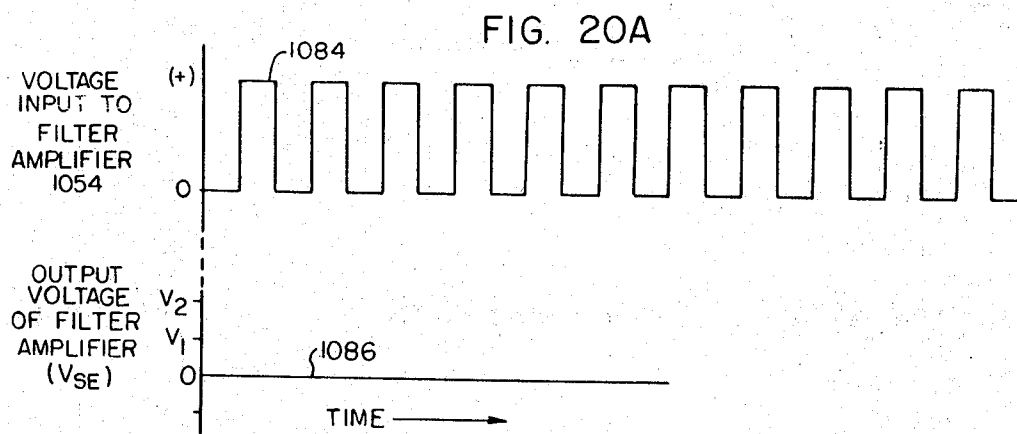


FIG. 20B

SPEED PATTERN GENERATOR FOR ELEVATOR SYSTEMS

CROSS-REFERENCES TO RELATED APPLICATIONS

Certain of the apparatus disclosed but not claimed in the present application, is claimed in the following concurrently filed, copending applications:

Application Ser. No. 254,007, filed May 17, 1972, entitled "FLOOR SELECTOR FOR AN ELEVATOR SYSTEM," which application is assigned to the same assignee as the present application.

Application Ser. No. 254,119, filed May 17, 1972, entitled "DISTANCE SLOWDOWN CONTROL FOR ELEVATOR SYSTEMS," which application is assigned to the same assignee as the present application.

Application Ser. No. 254,005, filed May 17, 1972, entitled "TERMINAL SLOWDOWN CONTROL FOR ELEVATOR SYSTEMS," which application is assigned to the same assignee as the present application.

BACKGROUND OF THE INVENTION

1. Field of the Invention

The invention relates in general to elevator systems, and more specifically to a speed pattern generator for elevator systems.

2. Description of the Prior Art

Elevator systems which utilize electromechanical controllers provide no direct control of jerk via the speed pattern, but depend upon other factors to limit jerk. The design of the car dynamic controller is a compromise between a plurality of criteria, such as system response time, landing characteristics, and value of deceleration during the slowdown phase. During installation of the elevator system, the system is carefully adjusted to provide the required jerk limitation, which again involves compromise between factors such as deceleration overshoot, landing overshoot, and oscillations in car speed during acceleration. Further, the system may require periodic readjustment of jerk, if the parameters of the dynamic system drift due to aging, temperature and wear.

Elevator systems with solid state controllers may provide control over maximum jerk in the speed pattern itself. For example, U.S. Pat. No. 3,523,232 discloses a position versus time pattern generator, which develops an acceleration signal and then superposes jerk constraint on the acceleration signal via an integrator. This jerk constraint acceleration signal is integrated twice to obtain the command position signal with respect to time. U.S. Pat. No. 3,350,612 uses a capacitor to smooth the transitions between the various portions of a pattern signal.

SUMMARY OF THE INVENTION

The present invention is a new and improved speed pattern generator of the solid state type, which provides a time optimum speed pattern signal with controlled jerk incorporated into the speed pattern. Further, the maximum jerk is directly controlled, and adjustable.

More specifically, an on-off type signal or step signal is provided which represents the value of jerk, or rate of change of acceleration. The step signal is switchable between first and second magnitudes, with the actual jerk to which the elevator car will be subjected being determined by the signal magnitudes.

The first and second magnitudes of the step or jerk signal provide currents of opposite polarity. The current responsive to the magnitude selected is integrated to provide a signal representing car acceleration, or deceleration, and the acceleration signal is integrated to generate the time dependent speed reference signal for the motor controller.

Acceleration and speed feedback loops select one of the two magnitudes of the jerk signal, to incorporate the jerk constraint during the transition periods between: (1) zero car speed and maximum acceleration, (2) maximum acceleration and maximum velocity, (3) maximum velocity and maximum deceleration, and (4) maximum deceleration and zero car speed. During the period when the car is at rest, and during the periods of constant acceleration and constant velocity or speed, the feedback circuits switch the jerk signal between its two magnitudes such that jerk is averaged to zero, with the switching rate being faster than the response time of the elevator car.

The time dependent speed pattern provides a pattern for a complete run, and may be used to control a complete run on relatively low speed elevator systems. On higher speed elevator systems, the time dependent speed pattern may be used for certain phases of the run, with the time dependent signal being replaced by distance dependent reference signals for other phases of the run. For example, the time dependent speed pattern may be used to accelerate the car and for the full speed phase, switching to a distance dependent slowdown signal when maximum deceleration is reached during the slowdown phase.

In the disclosed speed pattern generator, the value of jerk is not dependent upon system transfer functions, there is no need for field adjustment, and since there is no interaction between jerk control and other parameters, the other parameters may be optimized independently of the jerk control.

BRIEF DESCRIPTION OF THE DRAWINGS

The invention may be better understood, and further advantages and uses thereof more readily apparent, when considered in view of the following detailed description of exemplary embodiments, taken with the accompanying drawings, in which:

FIG. 1 is a partially schematic and partially block diagram illustrating an elevator system which may utilize the teachings of the invention;

FIG. 2 is a block diagram of a floor selector which embodies the basic concepts of the invention;

FIG. 3 is a block diagram of a floor selector which embodies the basic concepts of the invention, and additionally illustrates a preferred embodiment thereof;

FIG. 4 is a timing diagram for scanning position zero of the scan counter, which illustrates the development of certain of the timing signals used in the floor selector;

FIG. 5 is a schematic diagram of a counter, decoder, memory, comparator and indexer suitable for use in the floor selector shown in FIG. 3;

FIG. 6 is a schematic diagram of a counter, comparator, and top/bottom reset suitable for use in the floor selector shown in FIG. 3;

FIG. 7 is a timing diagram for a 30 floor building which illustrates certain signals explanatory of the operation of the floor selector shown in FIG. 3;

FIG. 8 is a schematic diagram of a call selector suitable for use in the floor selector shown in FIG. 3;

FIG. 9 is a schematic diagram of logic circuitry suitable for use in the floor selector shown in FIG. 3;

FIG. 10 is a schematic diagram of a synchronizer suitable for use in the floor selector shown in FIG. 3;

FIG. 11 is a diagram which illustrates which corridor calls a car can consider when it is set for up and down travel;

FIG. 12 is a block diagram of a speed pattern generator which may be used in the elevator system shown in FIG. 1;

FIG. 13 is a schematic diagram of logic circuitry suitable for use in the speed pattern generator shown in FIG. 12;

FIG. 14 is a schematic diagram of a time ramp generator suitable for use in the speed pattern generator shown in FIG. 12;

FIG. 15 is a graph illustrating the waveforms at various circuit points of the time ramp generator shown in FIG. 14;

FIG. 16 is a graph illustrating time dependent jerk, acceleration, and speed signals for the speed pattern generator shown in FIG. 12;

FIG. 17 is a schematic diagram of a distance slow-down circuit suitable for use in the speed pattern generator shown in FIG. 12;

FIG. 18 is a schematic diagram of a terminal slow-down circuit suitable for use in the speed pattern generator shown in FIG. 12;

FIG. 19 illustrates a terminal slow-down blade of the type which may be used in conjunction with a pulse generator to provide pulses for the terminal slow-down circuit shown in FIG. 18;

FIGS. 20A and 20B are graphs which illustrate the operation of the terminal slow-down circuit shown in FIG. 18; and

FIG. 21 is a schematic diagram of a driver circuit which may be used in the speed pattern generator shown in FIG. 12.

DESCRIPTION OF PREFERRED EMBODIMENTS

FIG. 1

Referring now to the drawings, and FIG. 1 in particular, there is shown an elevator system 10 wherein a car 12 is mounted in a hatchway 13 for movement relative to a structure 14 having a plurality of landings, such as 30, with only the first, second and 30 landings being shown in order to simplify the drawing. The car 12 is supported by a rope 16 which is reeved over a traction sheave 18 mounted on the shaft of a drive motor 20, such as a direct current motor as used in the Ward-Leonard drive system. A counterweight 22 is connected to the other end of the rope 16. A governor rope 24, which is connected to the top and bottom of the car 12, is reeved over a governor sheave 26 located above the highest point of travel of the car in the hatchway 13, and over a pulley 28 located at the bottom of the hatchway. A pickup 30 is disposed to detect movement of the car 12 through the effect of circumferentially spaced openings 26A in the governor sheave 26. The openings in the governor sheave are spaced to provide a pulse for each standard increment of travel of the car, such as a pulse for each 0.5 inch of car travel. Pickup 30, which may be of any suitable type, such as optical or magnetic, provides pulses in response to the movement of the openings 26A in the governor sheave.

Pickup 30 is connected to a pulse detector 32 which provides distance pulses for a floor selector 34. Distance pulses may be developed in any other suitable manner, such as by a pickup disposed on the car which cooperates with regularly spaced indicia in the hatchway.

Car calls, as registered by pushbutton array 36 mounted in the car 12, are recorded and serialized in car call control 38, and the resulting serialized car call information is directed to the floor selector 34.

Corridor calls, as registered by pushbuttons mounted in the corridors, such as the up pushbutton 40 located at the first landing, the down pushbutton 42 located at the thirtieth landing, and the up and down pushbuttons 44 located at the second and other intermediate landings, are recorded and serialized in corridor call control 46. The resulting serialized corridor call information is directed to the floor selector 34.

The floor selector 34 processes the distance pulses from pulse detector 32 to develop information concerning the position of the car 12 in the hatchway 13, and also directs these processed distance pulses to a speed pattern generator 48 which generates a speed reference signal for a motor controller 50, which in turn provides the drive voltage for motor 20.

The floor selector 34 keeps track of the car 12, the calls for service for the car, provides the request to accelerate signal to the speed pattern generator 48, and provides the deceleration signal for the speed pattern generator 48 at the precise time required for the car to decelerate according to a predetermined deceleration pattern and stop at a predetermined floor for which a call for service has been registered. The floor selector 34 also provides signals for controlling such auxiliary devices as the door operator 52, the hall lanterns 54, and controls the resetting of the car call and corridor call controls when a car or corridor call has been serviced.

Landing, and leveling of the car at the landing, is accomplished by a hatch transducer system which utilizes inductor plates 56 disposed at each landing, and transformer 58 disposed on the car 12.

The motor controller 50 includes a speed regulator responsive to the reference pattern provided by the speed pattern generator 48. The speed control may be derived from a comparison of the actual speed of the motor and that called for by the reference pattern by using a drag magnet regulator, such as disclosed in U.S. Pat. Nos. 2,874,806 and 3,207,265, which are assigned to the same assignee as the present application. The precision landing system using inductor plates 56 and transformer 58 is described in detail in U.S. Pat. No. 3,207,265.

An overspeed condition near either the upper or lower terminal is detected by the combination of a pickup 60 and slowdown blades, such as a slowdown blade 62. The pickup 60 is preferably mounted on the car 12, and a slowdown blade is mounted near each terminal. However, a single slowdown blade mounted on the car could cooperate with pickups disposed near each terminal. The slowdown blade has spaced openings, such as a toothed edge, with the teeth spaced to generate pulses in the pickup 60 when there is relative motion between them, which pulses are processed in pulse detector 64 and directed to the speed pattern generator 48 where the pulses are used to detect overspeed.

FIG. 2

FIG. 2 is a block diagram of floor selector 34, which embodies the basic concepts thereof. The distance pulses from the pulse detector 32 are applied to a reversible counter 70, which starts with ZERO count at the lowest or first landing, counts up when the car is travelling upwardly, and counts down when the car is travelling downwardly. Counter 70 is forcibly reset to ZERO at the bottom landing, in the event it is a few counts off, and it may also be reset to the count representing the uppermost landing when it arrives at that floor, to correct any error in the count. Counter 70 is preferably a binary counter having the number of bits necessary to count to the binary number determined by the standard increment used to generate a pulse, and the height between the lowest and uppermost floors.

Counter 70 is arranged to output a binary number which continuously changes as the car moves relative to the structure, to continuously indicate the advanced car position, as opposed to the actual position of the car in the hoistway. This continuous advanced car position is the point at which the car could be brought to a stop from its current velocity under a predetermined deceleration schedule. The continuous advanced car position is more important than the actual position of the car in high speed elevator systems, as several floors are needed to bring the car to a smooth stop without unnecessary stress on the passengers.

As disclosed in the hereinbefore mentioned U.S. Pat. No. 3,589,474, the continuous advanced car position may be generated directly in the reversible counter 70 by generating pulses at twice the rate of the distance pulses when the car is accelerating, and at the same rate as the distance pulses when the car is travelling at constant speed. When deceleration is initiated, the counting of the distance pulses is discontinued such that when the car comes to a stop, the count in the counter reflects the actual car position.

A second reversible counter 72 provides a signal which indicates the discrete advanced car position in terms of floor number. The second reversible counter 72 is also preferably a binary counter, having the number of bits necessary to provide a binary word for the uppermost floor. Counter 72 may be reset at one or both of the terminals, and it is indexed up or down, as required, as the count of the continuous advanced car position changes, as will be hereinafter described.

A read only memory 74 is provided, which, when addressed by the binary word of counter 72, which represents the discrete advanced car position with a floor number, outputs a binary word having the number of bits necessary to describe the exact location of that floor relative to the structure, with a resolution of the same standard increment used to generate pulses, such as 0.5 inch. The read only memory is preferably a matrix of fused diodes, with the presence of a diode corresponding to a logical ONE, while a missing diode, i.e., one in which its fuse has been blown, represents a logical ZERO. A diode may be disconnected from the matrix by discharging a charged capacitor across it and blowing the fuse in series with it. Thus, the read only memory may be precisely set for each floor of the structure it is associated with, during field installation. For example, the elevator car is leveled at the bottom floor, the counter 70 is reset to all ZERO's, the floor selector for the read only memory 74 is set to the bot-

tom floor and the bits of counter 70 are each connected to a bit of the read only memory through an inverter and a switch, which when actuated, discharges a capacitor through the associated diode of the read only memory if the inverted bit of counter 70 is a logical ONE. Thus, when counter 70 registers all ZERO's at the bottom landing, the inverted bits are all ONE's and all of the diodes of the read only memory 74 would be disconnected from the circuit for floor position one. The car is then moved by a hand operation to the next landing and leveled exactly with the floor without overshooting. The count of counter 70 thus describes the exact location of this floor relative to the structure, and the word or floor selector of the read only memory is set to the second word. Depressing the switch will set the second word of the memory to the count in the counter 70. This sequence is repeated until the exact location of all of the floors have been preset into the read only memory. Thus, addressing memory 74 with a word from counter 72 containing the number of bits necessary to describe the number of a floor, causes the memory 74 to output a word having the number of bits necessary to accurately describe the location of the floor in the structure, with the same resolution used in counter 70 to describe the continuous advanced car position. For example, a 5 bit input word describing a floor number may output a 16 bit word describing the location of that floor in the structure.

A bit-by-bit comparator 76 is provided which compares the binary output words of counter 70 and memory 74. When the binary words of counter 70 and memory 74 are equal, comparator 76 outputs an equality signal EQ2. Thus, when the car is travelling upwardly, when the binary words of counter 70 and memory 74 are equal, the equality signal EQ2 is generated. The equality signal EQ2 indicates slowdown must be initiated at this time or the car cannot stop at the discrete advanced car position. If deceleration is not initiated at that point, counter 70 will continue to count up in response to the distance pulses, the binary word of counter 70 will exceed the binary word of memory 74, and comparator 76 provides a signal for indexer 78. Indexer 78 provides a signal for counter 72 which increments the counter 72 to output the binary word for the next higher floor.

When the car is travelling downwardly and the binary word of counter 70 becomes equal to the binary word of memory 74, the equality signal EQ2 is generated. If deceleration is not initiated at this time, counter 70 will continue to count down in response to the distance pulses and as soon as the binary word of counter 70 is less than the binary word of memory 74, comparator 76 provides a signal for indexer 78, which in turn provides an index signal for counter 72, decrementing counter 72 by one floor to indicate the floor number of the next lower floor. The output of memory 74 is thus changed to the address of that floor.

A third counter 80 is provided which is a continuous scan type counter, preferably of the binary type, which starts at ZERO, counts to a predetermined binary number in a predetermined period of time, and starts the next predetermined period of time at ZERO again, thus dividing each succeeding predetermined period of time into a plurality of intervals or time slots. The location of the same interval in any predetermined period of time is thus identified by the same binary number. The number of intervals in each scanning period is deter-

mined by the number of floors in the structure, with the number of intervals being at least as large as the number of floors. A five bit scan counter, for example, will provide 32 intervals before automatically resetting to ZERO and starting the next scanning period. If the number of floors is greater than 32, a six bit counter will provide 64 intervals, etc. The length of time for each interval is determined by the rate at which call information can be gathered from the car and corridor pushbuttons, which rate is limited due to noise pickup in the travelling cable. A time interval of 2 milliseconds has been found to be satisfactory. Thus, with a five bit scan counter, a predetermined scan period would be 32 times 2 or 64 milliseconds, with each of the 32 intervals occupying 2 milliseconds of the period. The scan counter 80 is controlled by a master system clock.

A second bit-by-bit comparator 82 is provided which compares the binary output word of counter 72, which describes the floor number of a discrete advanced car position, with the binary output of the scan counter 80. Comparator 82 provides a signal EQIZ during each predetermined period of time when the binary number of the scanning position of the scan counter 80 is equal to the binary word of counter 72. Signal EQIZ may thus be termed the serial advanced car position signal, as it locates the advanced car position at the specific interval or time slot of the scan which identifies the floor of the advanced car position.

A logic circuit 84 receives car and corridor calls, with the car calls, up corridor calls, and down corridor calls each being in serial form, synchronized with the scan counter. Thus, a car call for a predetermined floor would appear in the time slot or interval for that floor, as developed by the scan counter. In like manner, up and down corridor calls from specific floors would appear in their associated intervals of each scan period. The logic circuit 84 detects coincidence of a call for service, which the car is conditioned to serve, for the floor of the advanced car position. If the car travel direction is up, the car is conditioned to consider car and corridor calls registered for the floors ahead of its travel direction. The car will handle all requests for up service ahead of it, and when there are no more requests for up service, it is conditioned to go to the highest registered call for down service, and then serve all requests for down travel registered ahead of it. Once no calls ahead of it request down service, the car is conditioned to go to the lowest call requesting up service, and handle all calls for up service ahead of it.

The coincidence of a call for service for the floor of the serial advanced car position signal is memorized by the logic circuit 84, and when the equality signal EQ2 is generated by the comparator 76, deceleration is immediately initiated, which prevents counter 70 from registering any further distance pulses. The count of counter 72 thus is not indexed, and when the car stops at the floor at which service was requested, the discrete advanced car position and the continuous advanced car position will both be the actual car position. If coincidence of a request for service for the floor of the discrete advance car position is not detected before the equality signal EQ2 is generated by comparator 76, the next distance pulse will cause the comparator to provide a signal for indexer 78, which indexes counter 72 to provide a binary number representing the number of the next floor at which the car can stop.

FIG. 3

FIG. 3 is a block diagram of floor selector 34, which presents a detailed functional view of a preferred embodiment of the invention, with like reference numerals in FIGS. 2 and 3 indicating like components, which will not be described in detail since they have already been described relative to FIG. 2.

More specifically, FIG. 3 includes a top/bottom reset means 86 which is responsive to car landing detectors at the top and bottom floors to provide a load signal, termed LOAD N for the counters 70 and 72. Memories addressed by the specific terminal location output a binary word describing the location, i.e., a floor number with respect to counter 72 and the location of the floor in the structure with respect to counter 70, which words are loaded into the counters when the LOAD N counter signal is generated.

A min/max decoder 88 is provided which detects arrival of the continuous advanced car position at the top and bottom floors and initiates terminal slowdown with a signal TDS in the event coincidence of the serial advanced car position signal EQIZ with a call for service for the approaching terminal does not occur before the generation of the equality signal EQ2.

A read only memory 90 is provided which is preset to identify which intervals, if any, are not assigned to floors, and to identify the intervals which do not have up and down corridor calls, i.e., the upper and lower floors, respectively.

The logic circuit 84 of FIG. 2 is shown in greater detail in FIG. 3. Logic circuit 84 includes a call selector circuit 92, a synchronizer circuit 94, and a logic circuit 96. The call selector circuit 92 receives the serial advanced car position signal EQIZ and detects any coincidence between signal EQIZ and the serial up and down corridor calls, and car calls, 1Z, 2Z and 3Z, respectively. When coincidence is detected, a coincidence signal EIX is generated which is synchronized in the logic circuit 96 and applied to the synchronizer 94 as signal EI. The synchronizer determines if the request to stop at the floor of the advanced car position signal EI occurs prior to the generation of the equality signal EQ2 by comparator 76. If the EI signal is received by the synchronizer 94 prior to its receiving the equality EQ2, a deceleration request signal DEC is generated which is processed by the logic circuit 96 to provide a signal ACCX for the speed pattern generator 48. If an EI signal is not received by the time the equality signal EQ2 is generated, comparator 76 provides a signal for indexer 78, and indexer 78 provides a pulse-up or pulse-down signal PU or PD, respectively, for indexing counter 72 to output the binary word representing the floor number where the car can stop according to the predetermined deceleration schedule. The remaining signals shown in FIG. 3 will be described when the circuits for performing the various functions are described.

FIG. 4

Before describing the circuits which may be used in the floor selector 34, it will helpful to illustrate the development of some of the timing signals used in the operation of the floor selector. FIG. 4 is a timing diagram which illustrates the signals generated during scanning position ZERO, termed 00, of the scan counter 30 shown in FIG. 2, which will be assumed to be a 2 milli-

second interval. The system or master clock is a 32 Khz. signal, termed K32, from which the other timing signals are derived. Signals K16, K08, K04, K02, K01 and KP5 are 16 Khz., 8 Khz., 4 Khz., 2 Khz., 1 Khz., and 500 hz. square wave timing or clock signals, respectively, developed by dividing the basic clock signal K32 in a binary counter.

Clock signals K08S and K02S are developed by shifting clock signals K08 and K02, respectively, forward by 90 degrees.

Clock signal STC is developed by inverting clock signals K01 and KP5 and using these inverted signals as inputs for a NAND gate ($STC = \overline{K01-KP5}$).

Clock signals S1, S2, S3 and S4 are developed in the first, second, third and fourth quadrants, respectively, of each scanning position, with signal S1 being equal to $\overline{K01-KP5-K02S}$, signal S2 being equal to $\overline{K01-KP5-K02S}$, signal S3 being equal to $\overline{K01-KP5-K02S}$, and signal S4 being equal to $\overline{K01-KP5-K02S}$.

All of the preceeding signals are developed during each scanning position of scan counter 80.

Clock signals S100, S200 and S300 are developed only during scanning position 00 of scan counter 80, with signal S100 being equal to $00-S2$, signal S200 being equal to $00-S2$, and signal S300 being equal to $00-S3$.

In order to better understand the following detailed description of circuits which may be used in the invention, the signals generated by the various circuits, and the functions thereof, are listed below. Timing signals are not listed, as they are shown in FIG. 4.

SIGNAL	FUNCTION
ACC	CAR TO ACCELERATE OR TRAVEL AT FULL SPEED
ACCX	ACCELERATION REQUEST
AVP0-AVP4	ADVANCED CAR POSITION IN BINARY
BOTTOM	CAR IS WITHIN 18" OF BOTTOM TERMINAL
BYP5	CAR BYPASSING CORRIDOR CALLS
CA	CALL ABOVE FLOOR OF ADVANCED CAR POSITION
CB	CALL BELOW FLOOR OF ADVANCED CAR POSITION
CCY	SERIAL CAR CALLS
CEN	CALL ENABLE
CFLY	CALL AT FLOOR DURING FIRST SCAN
DCE	DOWN CALL ENABLE
DCL	DOORS CLOSED
DCY	SERIAL DOWN CALLS
DEC	DECELERATION REQUEST
DECS	SYNCHRONIZED DECELERATION REQUEST
DGD	SIGNAL TO DRIVE "GO DOWN" INTERFACE RELAY
DGU	SIGNAL TO DRIVE "GO UP" INTERFACE RELAY
DL2	SIGNAL TO DRIVE LANDING INTERFACE
DO	DOOR OPEN REQUEST ENABLE
DOR	DOOR OPEN REQUEST
DORR	RESET-DOOR OPEN REQUEST
DOWN	SIGNAL WHICH IS TRUE WHEN CAR IS SET TO TRAVEL DOWN
DPL	DISTANCE PULSES
DNRZ	SERIAL DOWN CORRIDOR CALL RESET
DSAN	SPEED PATTERN FROM DISTANCE SLOWDOWN CIRCUIT
DSSW	DRIVING SIGNAL FOR DSAN SWITCH
D45	DOOR MASTER RELAY DRIVER
E1	CALL AT ADVANCED CAR POSITION
EIX	REQUEST FOR STOP
EQ1Z	SERIAL CAR POSITION
EQ2	ADVANCED CAR POSITION EQUAL TO FLOOR LEVEL
FSC	FIRST SCAN
Hld	ENABLE FOR DOWN HALL LANTERNS
HLU	ENABLE FOR UP HALL LANTERNS
HLX	HALL LANTERN ENABLE
HT1	SIGNAL FROM HATCH TRANSDUCER

HTAN	SIGNAL FROM HATCH TRANSDUCER CIRCUIT
HIS	DRIVER SIGNAL FOR HTAN SWITCH
IDLE	CAR IDLE, READY TO MAKE RUN
LAZO	CAR ± 10 INCHES FROM FLOOR LEVEL
LOAD N	LOAD CAR POSITION COUNTERS
5 MAIN	CAR WITHIN 18 INCHES OF MAIN FLOOR
MINA	MAXIMUM DECELERATION
MTOO	MEMORY TRACK
MTO1	MEMORY TRACK
MXVM	MAXIMUM VELOCITY
NC	LOGIC ZERO WHEN NO CALLS
10 NCS	LOGIC ZERO WHEN NO CALLS
NLC	INPUT PULSES TO COUNTER 544
NLI1	
NLI2	
NLI6	OUTPUT OF DISTANCE TO GO TO LANDING COUNTER 544
15 PCR	CAR IS WITHIN 16 INCHES OF LANDING ZONE
PD	INDICATES ADVANCED CAR FLOOR POSITION HAS CHANGED
PLSDP	PULSE ADVANCED CAR POSITION COUNTER DOWN
PU	PULSES FROM TERMINAL SLOWDOWN BLADE
20 SAC	PULSE ADVANCED CAR POSITION UP SCANNING ABOVE ADVANCED CAR POSITION
SBC	SCANNING BELOW ADVANCED CAR POSITION
SDT	SET SELECTOR FOR DOWN TRAVEL
SPSL	SPEED SELECTION SWITCH
SPSW	TERMINAL OVERSPEED DETECTED
25 SPS1	SPEED SELECTION NO. 1
SPS2	SPEED SELECTION NO. 2
SRAT	SPEED PATTERN SIGNAL FOR MOTOR CONTROLLER
START	SIGNAL TO START CAR IN RESPONSE TO ACCELERATION REQUEST
SUT	SET SELECTOR FOR UP TRAVEL
30 SOS-S4S	SCANNING SIGNALS
TDS	TERMINAL STOP SIGNAL
TOP	CAR WITHIN 18' OF TOP FLOOR
TOVSP	EXCESSIVE TERMINAL OVERSPEED
TSAN	AUXILIARY SPEED PATTERN USED DURING TERMINAL SLOWDOWN
35 TSD	CAR ON TERMINAL SLOWDOWN WHEN LOGIC 0
TRAN	TIME DEPENDENT SPEED PATTERN
TRSW	DRIVER SIGNAL FROM TRAN
UCE	UP CALL ENABLE
UCY	SERIAL UP CORRIDOR CALLS
UP	SIGNAL WHICH IS TRUE WHEN CAR IS SET TO TRAVEL UP
40 UPRZ	SERIAL UP CORRIDOR CALL RESET
UPTR	UP TRAVEL
ZO2	CAR WITHIN 2 INCHES OF FLOOR LEVEL
17	SERIAL UP CORRIDOR CALLS
22	SERIAL DOWN CORRIDOR CALLS
45 32	SERIAL CAR CALLS

FIGURE 5

FIG. 5 is a schematic diagram of a reversible counter, a decoder, a read only memory, a comparator, and an indexer, which may be used for the counter 70, min/-max decoder 88, the memory 74, the comparator 76, and indexer 78 shown in FIG. 3, with like reference numerals in FIGS. 3 and 5 indicating like components.

Counter 70 includes a plurality of 4 bit synchronous binary counters, with four counters 100, 102, 104 and 106 being illustrated. The actual number of bits, and thus the actual number of cascaded counters required, depends upon the standard increment used to provide the distance pulses, and the distance between the lowest and uppermost floors.

Counter 70 requires that the distance pulses, termed DPL pulses, which are generated by the governor sheave 26 and converted to logic level by the pulse detector 32 shown in FIG. 1, be generated at double rate during acceleration of the car, to establish a continuous advanced car position, at normal rate after the car reaches maximum velocity, and to be discontinued when the car initiates deceleration, in order for the ad-

vanced car position and actual car position to coincide as the car comes to a stop at a landing. The DPL pulses must be directed to the count-up or count-down inputs of counter 70, depending upon the direction of car travel. The speed pattern generator 48 requires that it receive the distance pulses at the rate they are generated at all times during car movement. All of these functions are provided by the circuit which includes first and second type D, positive edge triggered flip-flops 108 and 110, a cross-coupled NAND gate flip-flop 112, first, second, third, fourth fifth, sixth and seventh NAND gates 114, 116, 118, 120, 124 and 134, respectively, first, second, third, fourth, fifth, sixth and seventh NOT gates or inverters 125, 126, 128, 130, 132, 133 and 135, respectively.

The DPL distance pulses are applied to an input terminal which is identified with the same letters as the signal applied thereto, as are the input and output terminals in all of the various figures to be described herein. Input terminal DPL is connected to the D input of flip-flop 108. Clock signals K08 are connected to the C input of flip-flop 108 via inverter 125. The Q output of flip-flop 108 is connected to the D input of flip-flop 110 and to an input of NAND gate 114. The Q output of flip-flop 108 is connected to an input of NAND gate 116. Clock signals K08S are connected to the C input of flip-flop 110. The Q and $\bar{Q}$ inputs of flip-flop 110 are connected to inputs of NAND gates 116 and 114, respectively. Input terminal $\overline{MXVM}$ is connected to an input of NAND gate 116. Signal $\overline{MXVM}$, as will be hereinafter described, is generated by the speed pattern generator 48, with signal $\overline{MXVM}$ going to logical ZERO when the elevator car reaches maximum velocity.

The output of NAND gate 114 is connected to an input of NAND gate 134, and via inverter 126 to an output terminal NLC. Output terminal NLC provides distance pulses NLC when pulses are generated by the governor sheave, at the same rate that they are generated. The output of NAND gate 116 is connected to the other input of NAND gate 134.

The output of NAND gate 134 is connected to inputs of both NAND gates 118 and 120.

Flip-flop 112 is a travel direction flip-flop, with its set input S connected to an input terminal UP via inverter 133, and its reset input connected to an input terminal DOWN via inverter 135. Signals UP and DOWN are logic signals responsive to the direction of car travel, with signal UP being a logical ONE when the car is travelling up and signal DOWN being a logical ONE when the car is travelling down. The useful output of flip-flop 112 is termed $\overline{DN}$, and it is connected to an input of NAND gate 118, and to an input of NAND gate 120 via inverter 128.

An input terminal ACC is connected to the remaining inputs of both NAND gates 118 and 120. Signal ACC, which is provided by the speed pattern generator 32, becomes true or a logical ONE when the brake relay for the drive motor is picked up, and false or a logical ZERO when the car is requested to initiate deceleration.

The output of NAND gate 118 is connected to an input of NAND gate 122 via inverter 130. The output of NAND gate 120 is connected to an input of NAND gate 124 via inverter 132. The remaining inputs of NAND gates 122 and 124 are connected to the $\overline{MAX}$ and $\overline{MIN}$ outputs of min/max decoder 88, and, as will

hereinafter be explained, signal $\overline{MAX}$ becomes true, or logical ZERO when the output word of the continuous advanced car position (counter 70), is equal to the binary word describing the upper terminal floor, and signal $\overline{MIN}$ becomes true or logical ZERO when the output word of the continuous advanced car position is all ZERO's, describing the lower terminal floor.

In the operation of counter 70, it will be assumed that the car is set for up travel, with signal UP being true, and the car is starting to accelerate. Input terminal UP is at the logical ONE level and input terminal DOWN is at the logical ZERO level, which, when both are inverted, sets flip-flop 112. The output signal $\overline{DN}$ will be at the logic ONE level, applying a logic ONE to an input of NAND gate 118, and a logic ZERO to an input of NAND gate 120 via inverter 128. Thus, NAND gate 120 is blocked. When the brake relay is picked up, signal ACC will go to the logic ONE level, since the car is not decelerating. Thus, a pulse appearing at the output of NAND gate 134 will drive the output of NAND gate 118 low, and inverter 130 will apply a logic ONE to the input of NAND gate 122. As long as the continuous advanced car position is not at the upper terminal, $\overline{MAX}$ will be at the logic ONE level, and gate 122 will output a logic ZERO each time the output of NAND gate 134 goes low. The output of NAND gate 122 is connected to the "count up" input of counter 100.

NAND gate 134 is operated by the combination of flip-flops 108 and 110, and NAND gates 114 and 116, to output twice as many pulses as distance pulses received, until the car reaches maximum velocity, as signaled by $\overline{MXVM}$ going low. Flip-flop 108 receives distance pulses DPL at its D input from terminal DPL and it is clocked by timing signals K08 via inverter 125. The Q output of flip-flop 108 applies pulses at the rate of the distance pulses to NAND gate 114, and NAND gate 114 provides an input to NAND gate 134 and to the NLC output terminal. Thus, as long as distance pulses are received, they will be applied at the rate they are received to an input of NAND gate 134 and to output terminal NLC.

Flip-flop 110 has its D input connected to the Q output of flip-flop 108, and it is clocked by timing signals K08S, which is the K08 clock signal shifted forward by 90°. This arrangement causes flip-flop 110 to switch 90 degrees later than flip-flop 108 in the 8 KHz. clock signal, resulting in, for each distance pulse, output Q of flip-flop 108 and output $\bar{Q}$ of flip-flop 110 both being at the logic ONE level for 90 degrees, driving the output of NAND gate 114 low for 90 degrees. This overlapping occurs at the start of the positive Q output of flip-flop 108, and the termination of the $\bar{Q}$ output of flip-flop 110, which provides the pulse near the start of the DPL pulse.

This overlapping of logic ONE states also occurs between the $\bar{Q}$ and Q outputs of flip-flops 108 and 110, respectively, at the termination of the Q output of flip-flop 110 and at the start of the $\bar{Q}$ output of flip-flop 108, providing a pulse at the output of NAND 116 near the termination of a DPL pulse, which pulse is therefore spaced from the pulse provided at the output of NAND gate 114 in response to a DPL pulse.

Since the outputs of NAND gates 114 and 116 are high until driven low near the start and finish of a DPL pulse, respectively, the output of NAND gate 134 is driven high twice for each DPL pulse, thus providing pulses to the count-up input of counter 100 at twice the

DPL rate, while pulses are provided at the same rate as the DPL pulses at output terminal NLC.

When the car reaches maximum velocity, signal $\overline{MXVM}$ goes low, blocking gate 116, and the count-up input of counter 100 then receives pulses at the same rate as the distance pulses are received. When deceleration of the car is initiated, signal ACC goes low, blocking gate 118 from sending any further pulses to counter 100, enabling the count of counter 70 to coincide with the actual car position as the car comes to a stop at a landing.

When the car is travelling downwardly, the direction flip-flop 112 blocks NAND gate 118 and enables NAND gate 120, directing the output of NAND gate 134 to the count-down input of counter 100 via NAND gate 124, as long as $\overline{MIN}$ is high.

The min/max decoder 88 forces deceleration of the car when the continuous advanced car position, indicated by the count of counter 70, reaches either terminal, and it also blocks counter 70 from registering any further distance pulses when this situation occurs. The $\overline{MAX}$ output of decoder 88 is responsive to a plurality of diodes 138 connected to the output of counter 70 which are at the logic ONE level when the continuous advanced car position is equal to the binary word describing the position of the upper terminal floor. When these diodes all have their cathode electrode connected to a logical ONE, the input side of an inverter 140, which is connected to the anode electrodes of the diodes, goes high, and the output of inverter 140 is driven low to provide a true $\overline{MAX}$ signal.

The $\overline{MIN}$ output of decoder 88 is responsive to a plurality of serially connected inverter/diode combinations, referred to generally with reference numeral 142, which are connected to the outputs of counter 70. When the outputs of counter 70 are all at the logic ZERO level, indicating that the continuous advanced car position is the lowest floor, the input side of an inverter 144, which is connected to the anode electrodes of the diodes, is high, due to the inverters, and the output of inverter 144 is at the logic ZERO level.

The $\overline{MIN}$ and $\overline{MAX}$ outputs are used to terminate the counting of counter 70, as hereinbefore described, and they are also used to initiate terminal slowdown via the circuit which includes input terminals BOTTOM, TOP, UP and DOWN, inverters 146, 148 and 150, NAND gates 152, 154, 156, 158 and 160 and output terminal TDS.

Input terminals BOTTOM and TOP are connected to limit switches in the hatchway, which cause the BOTTOM and TOP input terminals to be at a logical ONE level when the car is within 18 inches of the bottom and top floors, respectively. Thus, NAND gates 152 and 154 are enabled as long as the car is not within 18 inches of either terminal. NAND gates 156 and 158 are responsive to car direction, with NAND gate 156 being enabled when the car is set to travel downwardly, and NAND gate 158 being enabled when the car is set to travel upwardly.

In the operation of the min/max decoder, assume that the car is travelling upwardly. Signals $\overline{MIN}$ and $\overline{MAX}$ are both at the logic ONE level, as are the inverted BOTTOM and TOP signals. Thus, the outputs of NAND gates 152 and 154 are at the logic ZERO level, the outputs of NAND gates 156 and 158 are both at the logic ONE level, the output of NAND gate 160 is at the logic ZERO level, and the output of inverter 150 is a

logic ONE, providing a high or false $\overline{TDS}$ signal. When the output of counter 70 reaches the binary word which describes the upper floor, signal $\overline{MAX}$ goes low, the output of NAND gate 154 goes high, the output of NAND gate 158 goes low, the output of NAND gate 160 goes high, and the output of inverter 150 goes low, the true level for the terminal slowdown signal $\overline{TDS}$. Signal $\overline{TDS}$ is applied to the synchronizer 94, as will be hereinafter explained.

In a similar manner, when the car is travelling downwardly and signal $\overline{MIN}$ goes low, indicating that the continuous advanced car position has arrived at the lower terminal, the output of NAND gate 152 goes high, the output of NAND gate 156 goes low, the output of NAND gate 160 goes high, and the output of inverter 150 goes low.

Memory 74, which may be a read-only memory such as Intersil No. IM 5600, is arranged, at the time of the installation of the elevator, to output a binary number which is the exact binary address of the floor relative to the structure, using the standard increment, represented by the binary number which is responsive to the floor of the discrete advanced car position, as determined by counter 72.

Comparator 76 includes a plurality of bit-by-bit comparators 162, 164, 166 and 168, having an input for the "A" word connected to outputs of counters 100, 102, 104 and 106, and an input for the "B" word connected to the output of memory 74. Memory 74 is of the type which has three outputs. An $A < B$ output which is at the logic ONE level when the word A is less than the word B, an $A = B$ output which is at the logic ONE level when the words are equal, and an $A > B$ output which is a logical ONE when the word A is larger than the word B. The $A < B$ output is connected to the D input of a type D positive edge triggered flip-flop 170, the $A = B$ output is connected to the D input of flip-flop 174, and the $A > B$ output is connected to the D input of a flip-flop 170. The clock inputs of these flip-flops is connected to receive clock signals $\overline{K32}$ via an inverter 176. The Q outputs of flip-flops 170 and 172 are connected to indexer 78, while the Q output of flip-flop 174 is connected to output terminal $\overline{EQ2}$ via inverter 178. Output terminal $\overline{EQ2}$ provides the equality signal $\overline{EQ2}$ when the continuous advanced car position arrives at the floor level of the discrete advanced car position.

In the operation of comparator 76, it will first be assumed that the car is travelling upwardly. Word A will thus be less than word B, and the $A < B$ output will be at the logic ONE level, while the other outputs are at the logic ZERO level. Flip-flop 172 thus outputs a logical ONE signal while the outputs of flip-flops 170 and 174 are low. When input words A and B are equal, indicating the car must now initiate slowdown if it is to stop at the floor of the discrete advanced car position according to a predetermined deceleration schedule, the $A = B$ output goes to logical ONE, flip-flop 174 outputs a logical ONE, and signal $\overline{EQ2}$ goes low or true. If deceleration is initiated, signal ACC goes low and the counter 70 remains at the count of the discrete advanced car position, and word A will continue to equal word B until the car stops, and then starts to move away from the floor. If deceleration is not initiated when the $A = B$ output is high, the first distance pulse after equality will cause the $A > B$ output of the comparator to go high, and flip-flop 170 outputs a logical ONE.

The indexer 78 is responsive to the outputs of flip-flops 170 and 172, to index the discrete advanced car position to represent the next floor at which the car can stop. Indexer 78 includes NAND gates 182, 184, 186 and 188, inverters 190 and 192, it is responsive to input terminals UP, DOWN, ACC, and S100, and it is connected to output terminals $\overline{PU}$ and $\overline{PD}$ which are connected to counter 72, and to synchronizer 94. NAND gates 182 and 184 have inputs connected to the UP and DOWN input terminals, respectively, and each have inputs connected to input terminal ACC. Thus, when the car is travelling upwardly and the car is not decelerating, NAND gate 182 outputs a ZERO, which is inverted to enable NAND gate 186. NAND gate 184 outputs a logic ONE which is inverted to block NAND gate 188. In a similar manner, when the car is travelling downwardly, NAND gate 186 is blocked and NAND gate 188 is enabled. Thus, when the car is travelling upwardly, the $A < B$ output of comparator 176 and its associated flip-flop 172 have no circuit affect, as NAND gate 188 is blocked. As soon as the $A > B$ output goes to the logic ONE level, the output of flip-flop 170 goes high and the S100 strobe, which occurs only during scanning interval 00 of the scan counter 80, drives the output of NAND gate 186 low, which is the true level for signal $\overline{PU}$. When signal $\overline{PU}$ goes low, it advances counter 72 to indicate the next higher floor number, and the output of memory 74 changes to indicate the floor address of that floor, which number is again higher than the continuous advanced car position. The $A < B$ output of comparator 76 thus goes high while its other outputs are low.

When the car is travelling downwardly, the A word responsive to the continuous advanced car position is larger than the B word responsive to the discrete advanced car position, and the $A < B$ output of comparator 76 is high, which has no circuit affect since gate 186 is blocked. When the continuous advanced car position reaches the discrete advanced car position, the $A = B$ output goes high and signal $\overline{EQ2}$ goes low. If deceleration is initiated the counter 70 is blocked by signal ACC going low. If deceleration is not initiated, counter 70 continues to count down, and as soon as the $A < B$ output goes high, flip-flop 172 goes high and the output of NAND gate 188 will go low upon receiving the S100 strobe during scanning slot 00, to index the counter 72 with a true or low $\overline{PD}$ signal to represent the next lower floor. When the counter 72 is indexed, the comparator 76 will output a logical ONE at the $A > B$ output, and the above sequence is repeated.

FIGURE 6

FIG. 6 is a schematic diagram of a reversible counter, a top/bottom reset, and a comparator, which may be used for counter 72, top/bottom reset 86, and comparator 82 shown in FIG. 3. Like reference numerals in FIGS. 6 and 3 indicate like components.

Counter 72 includes the necessary number of cascaded synchronous 4-bit binary counters required to represent the number of the floors in the associated structure, with two counters 194 and 196 being illustrated. The count-up input of counter 194 is connected to input terminal $\overline{PU}$, which receives index pulses from indexer 78, and the count-down input of counter 194 is connected to input terminal $\overline{PD}$, which receives index pulses from indexer 78. The output of counter 72 is connected to memory 74, hereinbefore described,

via output terminals AVPO, AVP1, AVP2, AVP3 and AVP4, and to one input of comparator 82. Comparator 82 is a bit-by-bit comparator, which has its other input connected to the scan counter 80. Comparator 82 has three outputs, an $A < B$ output which is high when the output of scan counter 80 is less than the binary output word of counter 72, an $A = B$ output which is high when the scan counter is at the time slot of the discrete advanced car position, and an $A > B$ output which is high when the output word of the scan counter 80 exceeds the output word of counter 72.

The outputs of comparator 82 are used to develop the serial advanced car position signal EQ1Z, the scanning below the discrete advanced car position signal SBC, and the scanning above the discrete advanced car position signal SAC. These signals are developed by a circuit which includes an input terminal $\overline{STC}$, which receives a strobe signal $\overline{STC}$ which occurs during each scanning slot of scan counter 80, as represented in FIG. 4, an input terminal $\overline{PCR}$, which receives a $\overline{PCR}$ signal which is low or true each time the indexer 78 provides an index signal $\overline{PU}$ or $\overline{PD}$, as will be explained when the synchronizer 94 is described, NAND gates 198, 200 and 202, inverters 204, 206 and 208, and output terminals SBC, EQ1Z and SAC.

In the operation of comparator 82, when the scan counter 80 is scanning (counting) below the floor of the discrete advanced car position, the $A < B$ output is high, which is strobed by signal $\overline{STC}$ during each scanning slot to provide a low output from NAND gate 198, which is inverted by inverter 204 to provide a high or true SBC signal.

When the scan counter 80 reaches the count which represents the floor of the advanced car position, the $A = B$ output goes high, and the output of NAND gate 200 goes low when $\overline{STC}$ goes high, as long as the counter 72 is enabled by a high $\overline{PCR}$ signal (counter 72 not being indexed). The low output of NAND gate 200 is inverted by inverter 206 to provide a true EQ1Z serial advanced car position signal in the proper scanning slot of scan counter 80. When the scan counter 80 passes the count of the discrete advanced car position, the $A > B$ output goes high and NAND gate 202 outputs a logical ZERO when strobe $\overline{STC}$ goes high during each scanning slot. The low output of NAND gate 202 is inverted by inverter 208 to provide a high or true SAC signal, which indicates scanning above the discrete advanced car position.

The top/bottom reset 86 resets both of the reversible counters 70 and 72 with the proper count at both the top and bottom floors, to start the elevator car from either terminal with the proper count, prior to a run which is initiated from these floors.

The top/bottom reset 86 includes NAND gates 210, 212, 214, 216, 218 and 220, a read only memory 222, inverters 224, 226, 228, 230, 232 and 234, input terminals TOP, BOTTOM, MAIN, DL2, Z02 and S100, and an output terminal $\overline{LOAD N}$.

NAND gate 210 has its inputs connected to input terminals DL2 and Z02, with signal $\overline{DL2}$ being a signal developed by the speed pattern generator 48 when the car is going to stop at a landing. When $\overline{DL2}$ is at the logic ZERO level, it corresponds to "run," and when $\overline{DL2}$ is at the logic ONE level it corresponds to "land." Signal Z02 is developed by a limit switch in the hatchway, with signal Z02 being a logic ONE when the car is within 2 inches of the landing level. The signals TOP,

BOTTOM and MAIN are developed by switches in the hatchway, and are at the logic ONE level when the car is within 18 inches of the top, bottom and main floors, respectively. If the bottom floor is the main floor, the MAIN input terminal and NAND gate 214 may be eliminated. The S100 input terminal receives clock pulse S100 generated during scan slot 00 of the scan counter 80. The output of NAND gate 218 is connected to counter 72, and also to the LOAD N output terminal, which terminal is connected to counter 70 shown in FIG. 5.

Read-only memory 22 is set to output the floor number in binary of the specific floor addressing the memory. For example, when the output of NAND gate 212 goes low, memory 222 will output the floor number of the bottom floor, which is 00001. When the output of NAND gate 216 goes low, memory 222 will output the number of the top floor, which in our 30 floor example, would be 11110.

When the elevator car is at a floor other than a floor at which the counters are reset, the inputs to NAND gate 220 will all be high and its output will be low, blocking NAND gate 218. When the car arrives at one of the reset floors, NAND gate 210 enables the NAND gates 212, 214, and 216, and depending upon which reset floor the car is located at, one of these NAND gates addresses the read-only memory 222 and enables NAND gate 220. Clock signal S100 in scanning slot 00 of the scan counter drives the output of NAND gate 218 low, which loads the proper floor number into counter 72. Counter 72 is thus forced to the correct output number, and this output addresses memory 74 of FIG. 5. Memory 74 provides the exact location of the floor relative to the structure, in terms of the standard increment. In addition to the output of memory 74 being used by comparator 76, the output of memory 74 is also connected to the load input of counter 70, as illustrated in FIG. 5. The LOAD N signal from the top/bottom reset 86 is connected to the LOAD N input of terminal 70, and when the LOAD N signal goes low, the output of memory 74 is loaded into counter 70, to always start counter 70 with the correct count at each reset floor. This resetting of counters and memories at the selected reset floors occurs automatically during the operation of the elevator car. If power is lost during the operation of the elevator, causing the counters to lose their count, normal system operation is achieved, following power return, by running the car manually to one of the reset floors.

FIG. 7

FIG. 7 is a timing diagram for a thirty floor building, illustrating the various scanning slots or intervals of the scan counter 80, and the relationship of selected signals thereto, such as car calls and up and down corridor calls. Since the building of the example has thirty floors, the scan counter 80 may be a 5-bit counter, which provides 32 intervals or slots for each scan. Since it is assumed that each interval is 2 milliseconds, the scan time for each scanning period is 64 milliseconds. If the building has more than thirty-two floors, a 6-bit counter would be used to handle structures with 33 through 64 floors, and a 7-bit scan counter would handle structures with 65 through 128 floors. The other counters and memories would be selected accordingly.

The car calls, referred to as signals 3Z are serialized and synchronized with the scan counter 80 to appear

in the time slot for the floor which they request the car to travel to. For example, each of the car pushbuttons may be connected by a wire to a gate, with the gates being sequentially enabled by the output of the scan counter, such that scanning slot 00 would enable the gate associated with the first floor, etc. The outputs of the gates would be collected to present the car call information in serial form. For purposes of example, it will be assumed that the car is travelling downwardly, the discrete advanced car position, represented by signal EQ1Z, is at the 20th floor, and the car has car calls (signal 3Z) for the 19th, 15th, 11th, 10th and fourth floors.

The up and down corridor calls, represented by signals 1Z and 2Z, respectively, may also be gated by the scan counter 80 to serialize and synchronize the calls into the scanning slots associated with the floor number from which they are registered. As illustrated in FIG. 7, up corridor calls 1Z are separately serialized, with calls for up service being registered from the 10th and 13th floors. Down corridor calls 2Z are registered for the seventh and 22th floors.

Signals MTOO and MTO1 shown in FIG. 7 are provided by read-only memory 90 shown in FIG. 3, and are used as enabling signals to insure that the scanning slots of the scan counter not used to represent floors are disregarded, as well as disregarding the scanning slots for the uppermost and lowermost floors when considering up and down corridor calls, respectively. Thus, memory track MTOO, which is used to enable up corridor calls 1Z, is a logic ONE for scanning slots 00 through 28, representing floors 1 through 29, and a logic ZERO for scanning slots 29, 30 and 31. Memory track MTO1 is used to enable down corridor calls 2Z, and is thus a logic ONE for scanning slots 01 through 29, representing floors 2 through 30, and a logic ZERO for scanning slots 00, 30 and 31.

Signal CEN is a call enable signal, for car calls, provided by a read-only memory track, such as from read-only memory 90. Signal CEN may simply be used to insure that the scanning slots not used to represent floors are disregarded by the car call circuits; or, as illustrated by the alternate CEN signal in FIG. 7, it may be used to prevent the car from going to specific floors in response to a car call, such as floors 15, 20 and 30.

The remaining signals shown in FIG. 7 are clock signals developed in FIG. 4, and hereinbefore described.

In the timing diagram of FIG. 7, the car, which is travelling downwardly, would stop at the floors for which car calls 3Z are registered, and it would stop at the seventh floor to serve the registered down call 2Z for that floor. When the car has served its last call in the down direction, it will proceed to the lowest registered up corridor call, and then handle all of the registered up calls. Upon handling the last call for service in the up direction, the car will proceed to the highest registered down call. The circuitry for operating the car in this manner will be hereinafter described.

FIG. 8

FIG. 8 is a schematic diagram of a call selector which may be used for the call selector 92 shown in FIG. 3. The primary function of the call selector 92 is to detect coincidence between the floor of the discrete advanced car position signal EQ1Z and a request for service for that floor, and to provide a request to stop signal EIX when such coincidence is detected. Auxiliary functions

of the call selector 92 are the resetting of corridor calls, the enabling of the hall lanterns, providing the door open request, and detecting a call at the floor at the start of each run.

More specifically, call selector 92 includes input terminals 1Z, 2Z and 3Z for receiving the serial up and down corridor calls and car calls, respectively, input terminals TM00, MT01 and CEN for receiving the memory track signals MT00, MT01 and CEN, respectively, input terminals UCE and DCE for receiving up and down call enable signals, respectively, for logic circuit 96, input terminals DCL, DO and DORR for receiving door closed, door open enable, and door reset signals, respectively, input terminal UPTR which receives a signal from logic circuit 96 which indicates direction of car travel, input terminal FSC which receives a signal from logic circuit 96 when the first scan is initiated at the start of a run, and input terminal S4 for receiving timing pulses during each scanning slot.

The serial advanced car position signal EQ1Z appears at input terminal EQ1Z in the scanning slot allocated to its specific floor position, and it is strobed by clock signal S4 through NAND gate 240, inverted by inverter 242, to appear at the logic ONE level at the input of each of the NAND gates 244, 246 and 248.

Serial up corridor calls which appear at input terminal 1Z are inverted by inverter 250, screened by memory track signal MT00 through NAND gate 252, inverted to the logic ONE level by inverter 254, applied to an input of each of the NAND gates 244, 256, and also via inverter 258 to output terminal UCY, which provides serial up corridor calls as screened by memory track MT00.

Serial down corridor calls which appear at input terminal 2Z are inverted by inverter 260, screened by memory track signal MT01 through NAND gate 262, inverted to the logic ONE level by inverter 264, applied to an input of each of the NAND gates 246 and 266, and also via inverter 268 to output terminal DCY, which provides serial down corridor calls, as screened by memory track MT01.

Serial car calls which appear at input terminal 3Z are inverted by inverter 270 and applied to an input terminal of each of the NAND gates 272 and 248. The car call enable signal applied to input terminal CEN is inverted by inverter 274 and applied to another input on each of the NAND gates 272 and 248. Car calls for floors for which the car is enabled appear at the output of NAND gate 272 and at the output terminal CCY.

When the up call enable signal at input terminal UCE, which is received from logic circuit 96, is at the logic ONE level, NAND gates 244, 256 and 276 are enabled. At this time, the down call enable signal at input terminal DCE will be at the logic ZERO level, blocking NAND gates 246, 266 and 278. When the down call enable signal at input terminal DCE, which is also received from logic circuit 96, is at the logic ONE level, signal UCE will be at the logic ZERO level, NAND gates 246, 266 and 278 will be enabled, and NAND gates 244, 256 and 276 will be blocked.

The outputs of NAND gates 244, 246 and 248 are normally high when no coincidence of the discrete advanced car position and a call for service for that floor is detected, and since these outputs are all connected to an input of NAND gate 280, the NAND gate 280 outputs a logic ZERO in the absence of coincidence, which is inverted to the logic ONE level by inverter

282. Thus, the signal at output terminal EIX, which is the request to stop signal, is false or at the ONE logic level in the absence of coincidence.

When a corridor or car call is registered for the floor of the discrete advanced car position, signal EIX goes true or low in the following manner. If the coincidence detected is an up corridor call, and the car is enabled for up calls, the input signals to NAND gate 244, i.e., UCE, strobed EQ1Z, and UCX, with the latter indicating screened up corridor calls, will all be at the logic ONE level simultaneously during the scan slot of the floor of the discrete advanced car position, driving the output of NAND gate 244 low, the output of NAND gate 280 high, and the output terminal EIX low via inverter 282.

If the coincidence detected is a down corridor call, and the car is enabled for down calls, the input signals for NAND gate 246, i.e., DCE, strobed EQ1Z and DCX, the latter indicating screened down corridor calls, will all be at the logic ONE level simultaneously during the scan slot of the floor of the discrete advanced car position, driving the output of NAND gate 246 low, the output of NAND gate 280 high, and the output terminal EIX low.

If the coincidence detected is a car call, and the car is enabled for the floor of the discrete advanced car position signal, the input signals CEN, strobed EQ1Z, and 3Z for NAND gate 248 will all be at the logic ONE level simultaneously during the scan slot of the floor of the discrete advanced car position, driving the output of NAND gate 248 low, the output of NAND gate 280 high, and output terminal EIX low.

When the elevator car starts a run, the logic circuit 96 provides a true or low FSC signal during the first complete scan of scan counter 80, starting at timing signal S200 and ending at timing signal S100, which is applied to input terminal FSC of call selector 92. This true or low FSC signal is inverted by inverter 284, applying a logic ONE to an input of NAND gate 286. Since the discrete advanced car position and the actual car position are the same at the start of a run, signal EQ1Z will appear in the time slot for the floor where the car is located. If there is an up corridor call at the floor where the car is located, a true corridor signal UCX will be applied to an input of AND gate 256. If the car is enabled for up calls, signal UCE will be true, and if the car is set for up travel, signal UPTR will be true, driving the output of NAND gate 256 low.

In a similar manner, if there is a down corridor call at the floor where the car is located, a true down corridor signal DCX will be applied to an input of NAND gate 266. If the car is enabled for down calls, signal DCE will be true, and if the car is set for down travel signal UPTR will be false or high, driving the output of NAND gate 256 low.

The outputs of NAND gates 256 and 266 are connected to inputs of NAND gate 288. If there is no call at the floor, these outputs will be high and the output of NAND gate 288 will be low. If one of the outputs of the NAND gates 256 or 266 goes low, indicating a call at the floor, the output of NAND gate 288 will go high. When the output of NAND gate 288 goes high during the first scan, the output of NAND gate 286 goes low, which is inverted by inverter 290 and applied to an input of a NAND gate 292. The other input of NAND gate 292 is connected to receive clock signal S4, which signal strobes the call at the floor through NAND gate

292 where it is applied to an input terminal $\overline{\text{CFLY}}$, which indicates a call at the floor. The output of NAND gate 292 is also applied to one of the set inputs of a first door flip-flop 294. Flip-flop 294 may be of the cross-coupled NAND gate type, having NAND gates 295 and 297.

Set inputs of the first door flip-flop 294, i.e., the inputs of NAND gate 295, are also connected to be responsive to the outputs of NAND gates 244, 246 and 248. Thus, a call at the floor, or a request to stop for a car call or a corridor call, will set the first door flip-flop 294, providing a logic ONE at the output of NAND gate 295, and a logic ONE at the input of NAND gate 296. The other input of NAND gate 296 is connected to input terminal DO, which is at the logic ONE level when the door open request is enabled. Thus, when NAND gate 296 is enabled by a high DO signal and flip-flop 294 is set, a second door flip-flop 298 will be set. Flip-flop 298 may be of the cross-coupled NAND gate type, having NAND gates 299 and 301. NAND gate 299 provides a logic ONE at its output, which is inverted by inverter 300 and applied to output terminal DOR. A low DOR signal is a request to open the doors of the car, which request is directed to door operator circuits 52 shown in FIG. 1. The door operator circuits may be conventional. When the non-interference or normal door open time times out, the door operator circuits 52 provide a low DORR signal at input terminal DORR, which resets the second door flip-flop 298. When the doors actually close, a low DCL signal, applied to input terminal DCL, initiated by a limit switch associated with the car and hatch doors, resets the first door flip-flop 294.

It will be noted that the second door flip-flop 298 may be set, initiating a door open request, by a low terminal slowdown signal $\overline{\text{TSD}}$, applied to input terminal $\overline{\text{TSD}}$, and connected to one of the set inputs of flip-flop 298. Thus, terminal slowdown, initiated by the speed pattern generator 48, as will be hereinafter described, will also initiate the opening of the car and hatch doors.

The output of inverter 300 is inverted by inverter 302 and connected to an input of each of the NAND gates 276 and 278, which also have inputs connected to receive up call enable and down call enable signals UCE and DCE, respectively. Thus, when the car is enabled for up calls and a door open request is initiated, the output of NAND gate 276 goes low, and this signal is inverted by inverter 304 and applied to an input of NAND gate 306. NAND gate 306 also has an input connected to receive the serial advanced car position signal EQ1Z. When the serial advanced car position signal EQ1Z goes high, the output of NAND gate 306 goes low, and this output is connected to output terminal HLU, which enables the up hall lantern for the floor of the serial advanced car position, and to output terminal UPRZ, which resets the up corridor pushbutton for the floor of the serial advanced car position. The hall lantern control 54 and corridor call control 46 shown in FIG. 1, which receives these enabling and reset signals, may be conventional.

In a similar manner, when the car is enabled for down calls, and a door open request is initiated, the output of NAND gate 278 goes low, and this signal is inverted by inverter 308 and applied to an input of NAND gate 310. The serial advanced car position signal EQ1Z is connected to another input of NAND gate 310, and when it is received, the output of NAND gate 310 goes

low, providing a low down hall lantern enable signal $\overline{\text{HLD}}$, and a low or true down corridor reset signal $\overline{\text{DNRZ}}$.

FIG. 9

FIG. 9 is a schematic diagram of a logic circuit which may be used for the logic circuit 96 shown in FIG. 3. The function of the logic circuit 96 is to receive the serial calls $\overline{\text{UCY}}$, $\overline{\text{DCY}}$ and $\overline{\text{CCY}}$ for the call selector 92, determine where a call is relative to the serial advanced car position EQ1Z, determine in which direction the car should travel and provide travel direction signal UPTR in response thereto, enable the car for up or down calls with enable signals UCE and DCE, respectively, request starting of the car with a true $\overline{\text{ACCX}}$ signal when it is idle, in response to a call for service, provide the first scan signal $\overline{\text{FSC}}$ for the call selector 92, provide a high or true EI signal when there is a call at the floor of the serial advanced car position, provide a true or low $\overline{\text{ACCX}}$ signal when a deceleration request is made by the synchronizer 94, and enable the hall lantern control with a true $\overline{\text{HLX}}$ signal.

More specifically, car and corridor calls are connected to selected inputs of NAND gates 320, 322, and 324, with the serial car calls, which are received at input terminal $\overline{\text{CCY}}$ being connected to an input terminal on all three of these NAND gates, the serial up corridor calls, which are received at input terminal $\overline{\text{UCY}}$, are connected to input terminals of NAND gates 322 and 324, and the serial down corridor calls, applied to input terminal $\overline{\text{DCY}}$, are connected to input terminals of NAND gates 320 and 324. In the absence of any calls, the outputs of all three of these NAND gates will be low. A car call $\overline{\text{CCY}}$ will drive the outputs of all three of these NAND gates high. An up corridor call $\overline{\text{UCY}}$ will drive the outputs of NAND gates 322 and 324 high. A down call $\overline{\text{DCY}}$ will drive the outputs of NAND gates 320 and 324 high.

The outputs of NAND gates 320, 322, and 324 are connected to selected inputs of NAND gates 326, 328, 330 and 332, with the output of NAND gate 320 being connected to an input of NAND gate 330, the output of NAND gate 322 connected to an input of NAND gate 328, and the output of NAND gate 324 connected to inputs of NAND gates 326 and 332.

NAND gate 326 also has an input connected to input terminal SAC, which receives a high or true SAC signal from comparator 82 in FIG. 6 when the scan counter 80 is scanning above the floor position of the serial advanced car position.

NAND gate 328 also has inputs connected to input terminal S4, which receives clock signals during each scanning slot, as shown in FIG. 7, to input terminal EQ1Z from comparator 82 which provides the serial advanced car position in the appropriate scanning slot, and to the output of a NAND gate 374 via inverter 323. The output of inverter 323 is high when a request is made to accelerate the car, as will be hereinafter explained.

NAND gate 330 also has inputs connected to the output of inverter 323, to input terminal EQ1Z, and to input terminal S4.

NAND gate 332 also has an input connected to input terminal SBC, which is true when comparator 82 indicates the scan counter 80 is scanning below the floor of the serial advanced car position signal EQ1Z.

The outputs of NAND gates 326, 328, 330 and 332 are connected to selected inputs of a "call above" flip-flop 333, and a "call below" flip-flop 335. The call above flip-flop 333 includes two cross-coupled NAND gates 334 and 336, with inputs of NAND gate 334 being connected to outputs of NAND gates 326 and 328. An input of NAND gate 336 is connected to input terminal S300 via inverter 342, which resets the call above flip-flop 330 during scanning slot 00 of the scan counter 80.

The call below flip-flop 335 includes two cross-coupled NAND gates 338 and 340, with inputs of NAND gate 338 being connected to outputs of NAND gates 330 and 332. An input of NAND gate 340 is connected to input terminal S300 via inverter 342, to also reset the call below flip-flop 335 during scanning slot 00.

The call above flip-flop 333 is set, triggering the output of NAND gate 334, referred to as signal CA, to a logic ONE level, by the output of NAND gate 326 going low, which indicates the scan counter 80 is scanning above the floor of the serial advanced car position, and while scanning there an up or down corridor call or car call was detected. When the output signal CA of NAND gate 334 goes high, the output of NAND gate 336, referred to as signal $\overline{CA}$, goes low. The call above flip-flop may also be set by the output of NAND gate 328 going low, which indicates that there is a request to accelerate, and a car or up corridor call at the floor of the car (the floors of the serial advanced car position and the actual car position are the same). When the call above flip-flop is set during the scan cycle of scan counter 80, it is reset by signal S300 during scanning slot 00.

The call below flip-flop 335 is set, triggering the output of NAND gate 338, referred to as signal CB, to a logic ONE level, and the output of NAND gate 340, referred to as $\overline{CB}$, to a logic ZERO level, by the output of NAND gate 332 going low. This indicates that the scan counter 80 is scanning below the floor position of the serial advanced car position, and while scanning there an up or down corridor call, or car call, was detected. The call below flip-flop 335 may also be set by the output of NAND gate 330 going low, indicating that there is a request to accelerate the car, and that there is a down corridor or car call at the floor where the car is located.

The CA and $\overline{CA}$ outputs of the call above flip-flop 333 are connected to inputs of NAND gates 344 and 346, respectively, and the $\overline{CB}$ and CB outputs of the call below flip-flop 335 are connected to inputs of NAND gates 334 and 346, respectively. Inputs of NAND gates 344 and 346 are also connected to input terminal S200, which provides a clock pulse during scanning slot 00, and also to input terminal DOR, which is high when there is no request to open the car door by the call selector 92. Thus, when the call above flip-flop 333 is set, signal CA is at the ONE logic level, the call below flip-flop 335 is not set, signal $\overline{CB}$ is at the ONE logic level, and there is no request to open the car door, signal DOR is at the ONE logic level, and the output of NAND gate 344 will go low when the clock signal S200 is received during scanning slot 00.

In a similar manner, when the call below flip-flop 335 is set, signal CB will be at the ONE logic level, the call above flip-flop 333 is not set, signal CA will be at the ONE logic level, and there is no request to open the car

door, signal DOR will be at the ONE logic level, and the output of NAND gate 346 will go low when the clock signal S200 is received.

If there are calls above and below the car, neither of the NAND gates 344 and 346 will switch to the low output level, as $\overline{CB}$ and CA will both be ZERO.

The outputs of NAND gates 344 and 346 are connected to selected inputs of a travel direction flip-flop 350. Travel direction flip-flop 350 includes cross-coupled NAND gates 352 and 354, with NAND gate 352 having an input connected to the output of NAND gate 344, and NAND gate 354 having an input connected to the output of NAND gate 346.

NAND gate 352 also has inputs connected to input terminals $\overline{SUT}$ and BOTTOM. Input terminal $\overline{SUT}$, for example, may be responsive to an attendant pushbutton which when depressed to indicate that up travel is desired, will provide a signal $\overline{SUT}$ at the logic ZERO level. Input terminal BOTTOM is responsive to a limit switch in the hatchway which provides a signal at the logic ONE level when the car is within 18 inches of the bottom landing. An inverter 356 inverts the BOTTOM signal before it is applied to NAND gate 352.

NAND GATE 354 also has inputs connected to input terminals $\overline{SDT}$ and TOP. Input terminal $\overline{SDT}$, for example, may be responsive to an attendant pushbutton, which is depressed when down travel is desired, to provide a signal $\overline{SDT}$ at the logic ZERO level. Input terminal TOP is responsive to a limit switch in the hatchway which provides a signal at the logic ONE level when the car is within 18 inches of the top landing. An inverter 358 inverts the signal TOP before it is applied to NAND gate 354.

The output of NAND gate 352 of the travel direction flip-flop 350, which is termed signal 81U, is connected to one input of a two input NAND gate 360. The remaining input of NAND gate 360 is connected to the output of inverter 358. The output of NAND gate 360, termed UPTR, is inverted by an inverter 362 and applied to an output terminal UPTR. Output terminal UPTR, which is connected to the speed pattern generator 48, is high when up travel is requested, and low when down travel is requested.

In the operation of the travel direction circuits of FIG. 9, it will be noted that the travel direction flip-flop 350 will be set to provide a true 81U signal by either the attendant pushbutton signal $\overline{SUT}$, or when the car is within 18 inches of the bottom landing, or when the output of NAND gate 344 goes low. Further, the travel direction flip-flop 350 will be set to provide a low 81U signal by the attendant pushbutton $\overline{SDT}$, or when the car is within 18 inches of the top landing, or when the output of NAND gate 346 goes low.

If there are calls below and above the car location, or a call at the floor during first scan, neither of the NAND gates 344 or 346 can go low, as $\overline{CA}$ and $\overline{CB}$ will both be at the logic ZERO level. Thus, the travel direction flip-flop 350 will not be triggered, and the car will maintain the travel direction it is presently taking. If we assume the car is travelling upwardly, it will continue in the upward direction until (a) there are no further calls for service ahead of its travel direction, or (b) it reaches the top landing. When the car reaches a top landing, the input terminal TOP will go high, flip-flop 350 will trigger, and the output of NAND gate 360 will go high. The output of NAND gate 360 will go high even though flip-flop 350 does not trigger for some rea-

son, due to an input of NAND gate 360 being connected to input terminal TOP via inverter 358. If the car is not at the top landing and there are no calls ahead of its upward travel, but there are calls below, the output of NAND gate 346 will go low, triggering flip-flop 350 to provide a low 81U signal, and driving the output of NAND gate 360 high.

If we assume the car is travelling downwardly, it will continue in the downward direction until (a) there are no further calls for service ahead of its travel direction, or (b) it reaches the bottom landing. When the car reaches the bottom landing, input terminal BOTTOM will go high, triggering flip-flop 350 to provide a true 81U output signal, and the output of NAND gate 360 will be driven low. If there are no calls ahead of its downward travel direction and it is not at the bottom landing, but there are calls above, the output of NAND gate 344 will go low, triggering flip-flop 350 to provide a true 81U signal, which drives the output of NAND gate 350 low.

The up and down corridor call enabling circuits of logic circuit 96 include NAND gates 364 and 366, and inverters 368 and 370, which circuits are responsive to an input terminal BYPS, which is responsive to car weight. When the car weight exceeds a predetermined amount, a true or low signal is applied to input terminal BYPS.

NAND gates 364 and 366 each have an input connected to input terminal BYPS. NAND gate 364 also has an input connected to the output terminal UPTR, while NAND gate 366 also has an input terminal connected to the output UPTR of NAND gate 360. If the car weight is below the predetermined magnitude, and the signal UPTR is high, the output of NAND gate 364 will go low, which is inverted by inverter 368 and applied to output terminal UCE as a high or true signal, indicating the car is enabled for up corridor calls. In a similar manner, if the car weight is below the predetermined magnitude and the signal UPTR is low or true, the output of NAND gate 366 will go low, which is inverted by inverter 370 and applied to output terminal DCE as a high or true signal, indicating the car is enabled for down corridor calls.

If the car weight exceeds the predetermined magnitude, signal BYPS will go low, and both NAND gates 364 and 366 will be blocked, and output terminals UCE and DCE will both be at the ZERO logic level. As hereinbefore explained, output terminals UCE and DCE are connected to the call selector circuit 92 shown in detail in FIG. 8.

When the elevator car is idle, a call in the system will initiate a true request to accelerate signal ACCX, in the direction requested by the travel direction circuits just described. The circuits which generate the ACCX signal include flip-flops 380, 383 and 384, NAND gates 374, 386, 388, 390, 391, 392 and 394, and inverters 396, 398 and 400.

Flip-flop 380 includes cross-coupled NAND gates 402 and 404 with inputs of NAND gate 402 being connected to the CA and CB outputs of the call above and call below flip-flops 333 and 335, respectively. NAND gate 402 also has an input connected to the output of NAND gate 391. NAND gate 391 has one input connected to input terminal EQ1Z, and another input connected to input terminal CEN. Any call will set flip-flop 380 to provide a logic ONE at the output of NAND gate 402, which output signal will be referred to as sig-

nal NCS. Also, since signal CEN is a logic ONE for a floor for which the car is not enabled, as described relative to call selector 92, if the floor of the serial advanced car position indicated by signal EQ1Z and a floor for which the car is not enabled coincides, it appears that there is a call in the system and the flip-flop 380 will also be set. This prevents the car from accidentally stopping at a floor for which it is not enabled. The flip-flop 380 is reset during scanning slot 00 by clock signal S300 which is connected to an input of NAND gate 404.

The NCS output signal of NAND gate 402 is connected to inputs of NAND gates 386 and 392. The output of NAND gate 404 is connected to an input of NAND gate 388. When a call is detected in the system and flip-flop 380 is set, the true NCS signal is gated through NAND gate 386 during scan slot 00 by clock signal S200, which is connected to the other input of NAND gate 386. The output of NAND gate 386 goes low when the S200 clock pulse is received, setting flip-flop 382 to provide a logic ONE signal NC at the output of NAND gate 406. The reset input of flip-flop 382, i.e., an input terminal of NAND gate 408, is connected to the output of NAND gate 388. The inputs of NAND gate 388 are connected to the output of NAND gate 404 of flip-flop 380, to the input terminal S200 to receive the S200 clock pulse, and input terminal DOR which is high in the absence of a request to open the car door. Thus, flip-flop 382 is reset by NAND gate 388, in the absence of a door open request DOR, but not until flip-flop 380 has been reset by clock signal S300.

The set output NC of flip-flop 382 is connected to an input of NAND gate 410 of flip-flop 384, to an input of NAND gate 390, and also to an input of a NAND gate 414 which is associated with the first scan function, as will be hereinafter explained. When the NC signal goes high at clock signal S200 it enables flip-flop 384, and it enables NAND gate 390. NAND gate 390 also has an input connected to input terminal S100, to receive a clock pulse during scanning slot 00. Clock signal S100, which appears a full scan period after flip-flop 382 is triggered at clock signal S200, triggers NAND gate 390 to provide a low output, triggering flip-flop 384 to drive the RUN output of NAND gate 410 low, and the RUN output of NAND gate 412 high. The RUN output of flip-flop 384 is connected to an input of NAND gate 414, and the RUN output of flip-flop 384 is connected to an input of NAND gate 392.

Flip-flop 380 is not reset at the clock pulse S300, due to the call in the system so the NCS input to NAND gate 392 is high when the RUN output of flip-flop 384 goes high at S100. Inputs of NAND gate 392 are also connected to input terminal S100 and IDLE. Therefore, when signals NCS, RUN and S100 are all high when the car is idle, the output of NAND gate 392 goes low, forcing the output of NAND gate 394 high, which is inverted by inverter 398 to a low or true signal ACCX. Signal ACCX which is a request to accelerate, is applied to the speed pattern generator 48.

The output of NAND gate 394 is also connected to an input of NAND gate 374, and the output of NAND gate 374 is also connected to an input of NAND gate 394, providing a low ACCY output signal from NAND gate 374, in the absence of a deceleration request signal DEC. Thus, NAND gate 374 maintains the low ACCX signal, even though NAND gate 392 goes high

at the termination of clock pulse S100 until signal $\overline{DEC}$ goes low.

The first scan signal $\overline{FSC}$ is provided for a complete scan period at the start of a run, just prior to the setting of the run flip-flop 384. When the NC output of flip-flop 382 goes high, enabling the run flip-flop 384, RUN is high which signal is applied to an input terminal of NAND gate 414, and since the high NC signal is also applied to an input of NAND gate 414, the $\overline{FSC}$ signal immediately goes low and remains low from clock signal S200, which triggered flip-flop 382, until clock signal S100, which triggers the run flip-flop 384, driving RUN low, and $\overline{FSC}$ high. At clock signal S200, flip-flop 382 is reset by NAND gate 388, and the resetting of flip-flop 382 resets flip-flop 384.

Another function of logic circuit 96 is to provide an EI signal indicating a call at the floor of the serial advanced car position, when a request for stop signal $\overline{EIX}$ is generated by the call selector 92. The circuit for generating signal EI includes input terminals $\overline{EIX}$, $\overline{CEN}$, S4, EQ1Z, S200, $\overline{PCR}$ and $\overline{DECS}$, flip-flops 420, 422 and 424, inverters 400, 426, 428 and 430, and NAND gate 432. Flip-flop 420 includes cross-coupled NAND gates 434 and 436, with an input of NAND gate 434 being connected to input terminal $\overline{EIX}$. An input terminal of NAND gate 434 is also connected to the output of NAND gate 432. An input of NAND gate 436 is connected to input terminal S200 via inverter 426. An input of NAND gate 436 is also connected to flip-flop 424.

Flip-flop 422 is of the JK type, which has its J input connected to the output of NAND gate 436 via inverter 436, its clock input C connected to receive clock signals S100, its K input grounded, and its Q output connected to output terminal EI via inverter 430.

Flip-flop 424 includes cross-coupled NAND gates 438 and 440, with an input of NAND gate 424 connected to input terminal $\overline{PCR}$, an input of NAND gate 440 connected to input terminal $\overline{DECS}$, and the output terminal of NAND gate 438 connected to the CLEAR input of flip-flop 422 and an input of NAND gate 436 of flip-flop 420.

NAND gate 432 has inputs connected to the RUN output of flip-flop 384, to input terminal EQ1Z, to input terminal S4, and to input terminal $\overline{CEN}$ via inverter 400. Thus, a true RUN signal which coincides with a high serial advanced car position signal EQ1Z, for a floor for which the car is enabled ($\overline{CEN} = 1$) results in the output of NAND gate 432 going low at clock signal S4. The output of NAND gate 432 is connected to an input of NAND gate 434 of flip-flop 420.

When input terminal $\overline{EIX}$ goes low, flip-flop 420 is set, providing a logic ONE at the output of inverter 428 and at the J input of flip-flop 422. At clock signal S100, the Q output of flip-flop 422 will go low, and the inverter 430 inverts this low signal to a true EI signal. The EI signal is applied to synchronizer 94, which will be hereinafter explained.

The reset flip-flop 424, which includes cross-coupled NAND gates 438 and 440, resets flip-flops 420 and 422 when a request is made to decelerate the car, i.e., signal $\overline{DECS}$ goes low. The reset flip-flop 424 is reset when the floor of the serial advanced car position is changed, indicated by signal $\overline{PCR}$ going low. Flip-flop 420 may also be reset by clock signal S200.

In addition to flip-flop 420 being set by a true $\overline{EIX}$ request for stop, the output of NAND gate 432 going low

has the same effect, and this occurs, as hereinbefore stated, when a true or high RUN signal coincides with the serial advanced car position signal for a floor which the car is enabled.

A hall lantern enable signal $\overline{HLX}$ is provided by a circuit which includes NAND gates 441, 443, 445 and 447. NAND gate 441 has inputs connected to the output of NAND gate 324, the output of NAND gate 360, and input terminal SBC. The output of NAND gate 441 is connected to an input of NAND gate 445. NAND gate 443 has inputs connected to the output of NAND gate 324, output terminal UPTR, and input terminal SAC. The output of NAND gate 443 is connected to an input of NAND gate 445. NAND gate 447 has an input connected to the output of NAND gate 445 and to the input terminal DOR. The output of NAND gate 447 is connected to output terminal $\overline{HLX}$.

In the operation of the hall lantern enable circuit, if there are no calls in the system, the output of NAND gate 324 will be low, forcing the outputs of NAND gates 441 and 443 high. This forces the output of NAND gate 445 low and the output of NAND gate 447 high, providing a high $\overline{HLX}$ signal which may be used to suppress the hall lantern circuits. If there is any call in the system, the output of NAND gate 324 will be high. If the scan counter is scanning below the position of the advanced car position, signal SBC will be high, and if the car is set for down travel signal UPTR will be high, and the output of NAND gate 441 will go low. This forces the output of NAND gate 445 high, and if there is no request to open a door, signal DOR will also be high, forcing the output of NAND gate 447 low, which provides a low $\overline{HLX}$ which may be used to enable the hall lantern circuits. If there is a call in the system, NAND gate 324 will be high, and if the scan counter is scanning above the car, signal SAC will be high, and if the car is set for up travel signal UPTR will be high. This forces the output of NAND gate 443 low, and the output of NAND gate 445 goes high. In the absence of a request to open the door, signal DOR will be high, and NAND gate 447 will have a low output, providing a low output signal $\overline{HLX}$, which again may be used to enable the hall lantern circuits.

FIGURE 10

FIG. 10 is a schematic diagram of a synchronizer circuit which may be used for the synchronizer 94 shown in FIG. 3. The function of the synchronizer circuit 94 is to receive the signal EI from the logic circuit 96, which indicates that there is a call at the floor of the advanced car position, and the signal EQ2 from comparator 76 in FIG. 5, which indicates when the advanced car position is equal to the floor level. If the signal EQ2 is received by the synchronizer and no call for that floor has been registered, i.e., the synchronizer has not received a high EI signal from the logic circuit 96, the signal EQ2 blocks a later arriving EI signal from having any circuit effect. The car thus continues to travel at the same rate, and the indexer 78 provides a pulse up or pulse down signal $\overline{PU}$ or $\overline{PD}$ for the reversible counter and for the synchronizer, which pulse resets the synchronizer and enables it to register an EI signal for the next discrete advanced car position up until the time the next EQ2 pulse is received. When a signal EI has been registered when the EQ2 pulse is received, the EQ2 pulse initiates the deceleration request signal DEC.

More specifically, FIG. 10 includes a circuit for providing a single pulse E2 in response to the equality pulse EQ2. This one-shot type circuit includes NAND gates 450 and 452, and flip-flops 454, 456 and 458. The flip-flops may be of the cross-coupled NAND gate type, with flip-flop 454 having NAND gates 460 and 462, flip-flop 456 having NAND gates 464 and 466, and flip-flop 458 having NAND gates 468 and 470.

Input terminal EQ2 is connected to an input of NAND gate 450 and to an input of NAND gate 462 of flip-flop 454. The output of NAND gate 450 is connected to an input of NAND gate 460. The output of NAND gate 462 is connected to an input of NAND gate 466 of flip-flop 456, and also to an input of NAND gate 452. The output of flip-flop 456 is connected to another input of NAND gate 452. The output of NAND gate 452 is connected to an input of NAND gate 470 of flip-flop 458. Another input of NAND gate 470 is connected to receive a signal DECS, which, as will be hereinafter explained, is a request to decelerate. The output of flip-flop 458 is connected to inputs of NAND gate 450, NAND gate 464 of flip-flop 456, and to an input of NAND gate 452. An input of NAND gate 452 is also connected to receive the deceleration request signal DECS. The output of NAND gate 452 provides the signal E2 when the equality signal EQ2 is received.

Flip-flop 458 is reset by either of the terminal slowdown signals TDS or TSD via an AND gate 472 which has inputs connected to input terminals TDS and TSD, and an output terminal connected to an input terminal of NAND gate 468. Terminal slowdown signal TDS is generated by the min/max decoder 88 shown in FIG. 5, and terminal slowdown signal TSD is generated by the speed pattern generator 48, as will be hereinafter explained.

Flip-flop 458 may also be reset by a signal PU or PD from the indexer 78. This reset circuit includes input terminals PU, PD and S200, inverters 476, 478 and 480, flip-flop 482, NAND gate 484, and an output terminal PCR. Flip-flop 482 may be of the cross-coupled NAND gate type including NAND gates 486 and 488.

An input of NAND gate 488 of flip-flop 482 is connected to input terminal S200 via an inverter 476, which provides a clock pulse during scanning slot 00. Inputs of NAND gate 486 are connected to input terminals PU and PD. The output of NAND gate 486 of flip-flop 482 is connected to an input of NAND gate 484, and via inverter 480 to output terminal PCR. Since PU or PD occurs at clock pulse S100, setting flip-flop 482, and clock pulse S200 resets flip-flop 482, signal PCR is low or true each time the indexer 78 provides an output, with signal PCR being true from clock pulse S100 to clock pulse S200.

NAND gate 484 also has an input connected to input terminal S100 via inverter 478. The output of NAND gate 484 is connected to an input of NAND gate 468 of flip-flop 458.

The operation of the circuit which provides a signal EI pulse for each equality signal EQ2 is as follows. The various logic levels indicated in FIG. 10 are those just prior to receiving a true or low EQ2 signal. When EQ2 goes low, the EQ2 input to NAND gate 450 goes low and the output of NAND gate 450 goes high, enabling flip-flop 454. The low EQ2 input to NAND gate 462 of flip-flop 452 triggers flip-flop 454, thus "remembering" that the circuit received an equality signal EQ2. When

flip-flop 454 triggers, NAND gate 462 of flip-flop 454 outputs a logic ONE signal which enables flip-flop 456 and drives the output of NAND gate 452 low. The low output of NAND gate 452 triggers flip-flop 458, driving the output of NAND gate 468 low. The output of NAND gate 468 is connected to an input of NAND gate 452, driving the output of NAND gate 452 high, which is a true E2 signal. The low output of NAND gate 468 also triggers flip-flop 456, which "remembers" flip-flop 458 was triggered, and the output of NAND gate 452 is driven high to enable flip-flop 458. The low output of flip-flop 458 also blocks NAND gate 450.

If deceleration is requested, the DECS input to NAND gate 470 of flip-flop 458 will go low, blocking flip-flop 458 from being reset. If deceleration is not requested, EQ2 will go back to the logic ONE level. A true or low signal PU or PD will be provided when clock pulse S100 occurs, and flip-flop 482 will be set, changing the output of NAND gate 486 to a logic ONE. NAND gate 484 is thus driven low at the end of clock pulse S100, which resets flip-flop 458 and the E2 output of NAND gate 452 goes back to logic ZERO level. As hereinbefore stated, terminal slowdown, as evidenced by a low or true TDS or TSD signal, will also reset flip-flop 458.

When flip-flop 458 resets, it also enables flip-flop 456, and since EQ2 is back to the logic ONE level, NAND gate 450 is driven low by the high input from flip-flop 458. This resets flip-flop 454, and flip-flop 454 resets flip-flop 456, maintaining the logic ONE output of NAND gate 452 since the input from flip-flop 454 is now at the logic ZERO level. Flip-flop 482 resets at clock pulse S200, terminating the true PCR signal. The circuit is back to its original status, awaiting another true EQ2 signal.

Synchronizer 94 also includes input terminals IDLE, S4, D45, CFLY and EI, output terminals DEC, DECS, and DO, flip-flops 490 and 492, NAND gates 494, 496, 498, 500, 502, 504, 506 and 508, and inverters 510, 512 and 514. Flip-flops 490 and 492 may be of the cross-coupled NAND gate type, with flip-flop 490 having NAND gates 516 and 518, and flip-flop 492 having NAND gates 520 and 522.

Input terminals IDLE, S4 and D45 are connected to input terminals of NAND gate 494. Input terminal IDLE is a logic ONE when the car is idle with the brakes applied, S4 is a clock pulse which occurs during each scanning slot, and a high D45 signal indicates that the doors should close. Input terminal D45 is also connected to an input of NAND gate 516 of flip-flop 490. An input of NAND gate 518 of flip-flop 490 is connected to input terminal CFLY, which is low when there is a call at the floor during the first scan, as described relative to the call selector 92 shown in FIG. 8. The output of flip-flop 490 is connected to inputs of NAND gate 494 and NAND gate 508.

Input terminal EI is connected to an input of NAND gate 496, to an input of NAND gate 500, and via inverter 510, to an input of NAND gate 506. The remaining input of NAND gate 500 is connected to the output of NAND gate 502, and the output of NAND gate 500 is connected to an input of NAND gate 502. Other inputs of NAND gate 502 are connected to the output of AND gate 472, to the output of NAND gate 452, and to the output of NAND gate 504. The output of NAND gate 504 is also connected to an input of NAND gate 506. NAND gate 504 also has inputs connected to the

output of AND gate 472, to the output of NAND gate 452, and to the output of NAND gate 506.

NAND gate 496, which as already described, has inputs connected to the output of NAND gate 502 and to the input terminal EI, also has an input connected to the output of NAND gate 452. The output of NAND gate 496 is connected to an input of NAND gate 508. NAND gate 508 also has inputs connected to the output of AND gate 472, to the output of NAND gate 516 of flip-flop 490, and to the output of inverter 512. The output of NAND gate 508 is connected to output terminal DEC, which is the request to decelerate signal, and to an input terminal of NAND gate 498. NAND gate 498 also has an input connected to input terminal S100. The output of NAND gate 498 is thus the deceleration request synchronized with the clock pulse S100, and it is connected to an input of NAND gate 522 of flip-flop 492. The output of NAND gate 522 of flip-flop 492 is connected to output terminal DECS via inverter 512, which is the synchronized deceleration request. The output of inverter 512 is connected to output terminal DO via inverter 514, which is the door open request enable signal.

In describing the operation of synchronizer 94 it will be assumed that the car is moving, with the logic levels shown in FIG. 10 being those prior to receiving true EQ2 and EI signals. When signal EI goes high or true before signal EQ2 goes low or true, the EI input to NAND gate 496 goes high, the EI input to NAND gate 500 goes high, driving the output of NAND gate 500 low, which blocks NAND gate 502 in its present state of providing a high output. The EI output to NAND gate 506 goes low, switching NAND gate 506 to provide a high output, which provides a high input to NAND gate 504.

Now, when signal E2 goes high upon receiving the equality signal EQ2, NAND gate 496 has all high inputs, switching its output low, which causes NAND gate 508 to switch to a high output. The output of NAND gate 508 is connected to output terminal DEC, which is thus high, providing a true request to decelerate signal DEC. The high output of NAND gate 508 is also applied to NAND gate 498, and when clock pulse S100 is received, the output of NAND gate 498 goes low to set flip-flop 492, providing a true DECS output signal, and a true DO output signal, which are synchronized deceleration and door open enable requests, respectively. When the car stops and opens its door in response to the deceleration request and door open enable request, the IDLE signal goes to a logic ONE, and when the non-interference time expires and signal D45 goes to a logic ONE requesting the door to close, NAND gate 494 provides a low output which resets flip-flop 492.

When signal EQ2 goes low before signal EI goes high, E2 goes high applying a logic ONE to the inputs of NAND gates 502, 504 and 496. NAND gate 502 switches its output low, which blocks NAND gate 496, and NAND gate 500. Thus, if signal EI were to occur in the short time between timing signals S100 and S200 (the indexer 78 operates at S200 if no EI signal by the time of S100), it would have no circuit affect, as NAND gate 500 is blocked, and NAND gate 496 is blocked.

If there is a call at the floor during the first scan prior to the car making a run, as hereinbefore explained, signal CFLY will be true, and this prevents acceleration

and issues a door open request by a circuit which includes flip-flop 490. The low or true CFLY signal sets flip-flop 490, enabling flip-flop 492 by switching the output of NAND gate 494 high, and switching the output of NAND gate 508 high, which, as hereinbefore explained, provides a high DEC signal, a low DECS signal, and a high DO signal.

FIGURE 11

FIG. 11 is a diagram which illustrates the corridor calls that the floor selector 34 allows the car to consider. Each of the floors of a 30 floor building are shown, with blocks associated with the floors 2 through 30 for receiving down calls, and with blocks associated with the floors 1 through 29 for receiving up calls. The blocks for the up and down calls are shown twice, with the first showing being associated with a car 530 travelling downwardly (UPTR=0), which has an advanced car position at the 17th floor, and the second showing being associated with a car 530' travelling upwardly (UPTR=1), which has an advanced car position at the 17th floor.

In the case of car 530 travelling downwardly, the car can consider down calls at the 17th floor and below it through the second floor, while it may consider up calls from the 16th floor to the first floor. The blocks associated with the floors and direction of the calls which the car may consider are cross-hatched. As explained relative to logic circuit 96, the car 530 will answer all down calls ahead of it, and if there are no down calls it will travel to the lowest registered up call. Thus, the car 530 is considering the down calls ahead of it, and when there are no further down calls, it considers the up calls for the floors below its advanced car position.

When the car 530' is travelling upwardly, it considers all up calls ahead of it, including the floor of its advanced car position, and when there are no further up calls, it considers all down calls for all of the floors ahead of it, and it travels to the highest requested down call before stopping and reversing its travel direction.

FIGURE 12

FIG. 12 is a block diagram of a speed pattern generator which may be used for the speed pattern generator 48 shown in FIG. 1. The speed pattern generator 48 provides a signal for the motor controller 50 which controls the speed of the drive motor 20, and thus the movement of the car 12. In elevator systems, the speed and position of the car must be precisely controlled for the safety and comfort of the passengers, while being responsive to calls for service at any time.

The speed pattern generator 48 shown in FIG. 12 continues the concept of the floor selector 34, hereinbefore described, in that the prior art electromechanical model of the elevator system is not required in order to provide signals for the operation thereof. As will be hereinafter explained, the speed pattern generator of FIG. 12 is a time optimum control system, moving the elevator car from one point to another in minimum time, while directly controlling the rate of change of acceleration, commonly called jerk, subject to maximum limitations placed on acceleration and speed.

The speed pattern generator 48 receives signals ACCX and UPTR from the floor selector 34, responsive to a request for acceleration, and travel direction request, respectively, which signals are processed in logic circuit 540 to provide signals DGU and DGD for

the car direction relays, acceleration signal ACC, speed signals SPS1 or SPS2 for a time ramp generator circuit 542, and a start signal START for a driver circuit 552.

The time ramp generator 542 provides a time dependent signal TRAN which for elevator systems having a maximum car speed of about 500 feet/min. may be used to control the acceleration, full speed, deceleration and landing phases of a car. For elevator systems which operate the cars above this speed, the time dependent speed reference signal TRAN is used only for the acceleration, full speed and transition between full speed and maximum deceleration phases of the run, with the speed pattern generator 48 automatically switching to distance dependent signals for the maximum deceleration and landing phases of the run.

A reversible counter 544 receives the distance pulses NLC from counter 70 shown in FIG. 5. Counter 544 is responsive to signal MXVM from the time ramp generator, which goes to logic zero when maximum speed of the car is reached, and signal ACC from logic circuit 540 goes to the logic ZERO level when deceleration is requested. These signals program counter 544 to (a) count up in response to the NLC distance pulses while the car is accelerated, to (b) stop counting when the car reaches maximum speed (MXVM goes to ZERO), which thus stores the distance to go to a landing, and to (c) count down when the deceleration is initiated (ACC goes to ZERO).

The output of counter 544 is applied to a distance slowdown circuit 546, which provides a speed reference signal DSAN proportional to the square root of the distance to go to the landing. The square root of the distance to go to the landing provides constant deceleration for the elevator car, with the switching from the time dependent signal TRAN to the distance dependent signal DSAN being accomplished by switches 548 and 550 and a driver circuit 552 which provides switching signals TRSW and DSSW at the proper time for operating switches 548 and 550, respectively. The switching between the speed reference signals will be described in this application as a direct and complete switch from one signal to the other. However, it is preferable that transitional switching be used, which progressively mixes or blends the signals to be switched to provide a smooth transition between the signals and limit jerk in the event of a mismatch between them. Apparatus for performing this transitional switching of signals is disclosed in copending application Ser. No. 13,660, filed Feb. 24, 1970, now U.S. Pat. No. 3,651,892 which is assigned to the same assignee as the present application.

When the car is within a predetermined distance of the floor at which it is to stop, such as 10 inches, a signal HT1 from a hatch transducer is applied to a switching arrangement 554, which is also responsive to the car travel direction, signals UP and DOWN. Signal UP is true when the car is travelling upwardly, and signal DOWN is true when the car is travelling downwardly. Switching arrangement 554 provides a speed reference signal HTAN for a switch 556, which receives a switching signal HTS from driver 552 at the proper time to switch from the distance speed reference signal DSAN to the distance speed reference signal HTAN. Again, transitional switching is preferably used, using analog switches to switch between the two speed reference signals. The development of the hatch transducer signal

HT1 is described in the hereinbefore mentioned U.S. Pat. No. 3,207,265.

The pulse detector 64 shown in FIG. 1 generates pulses in response to pickup 60 on the elevator car and slowdown blades 62 mounted in the hatch near the terminals. These pulses, referred to as PLSDP pulses, along with a signal from a tachometer on the drive motor 20, are applied to a terminal slow down circuit 558. Terminal slowdown circuit 558 detects car overspeed near a terminal, and when overspeed is detected, it provides a speed reference signal TSAN for stopping the car at the terminal the car is approaching. Signal TSAN is switched into circuit effect by switch 560, which receives a switching signal TSD from driver 552. If the overspeed condition detected by terminal slowdown circuit 558 exceeds a predetermined magnitude, a signal TOVSP is generated which is applied to emergency stopping control (not shown), which may be conventional.

The signals from the analog switches driven by the driver 552 are applied to a summing amplifier 562, which provides a speed reference signal SRAT for the motor controller 50, shown in FIG. 1, which may be conventional.

FIG. 13

FIG. 13 is a schematic diagram of a logic circuit that may be used for the logic circuit 540 shown in FIG. 12. Logic circuit 540 includes input terminals UPTR, ACCX, A, and SPSL. Input terminal UPTR receives a signal from logic circuit 96 responsive to travel direction of the car, with the signal UPTR being a logic ONE for up travel, and a logic ZERO for down travel. Input terminal ACCX receives a signal from logic circuit 96 responsive to a request for acceleration. Signal ACCX is true or at the logic ZERO level as soon as the brake relay A (not shown) is picked up, and it remains true until the car is requested to initiate slowdown. Input terminal A is connected to be responsive to the brake relay A, and is at the logic ZERO level when the brake is set, and at the logic ONE level when the brake is picked up. Input terminal SPSL may simply be a manual selector switch, which is set to select a desired maximum car speed, or it may be an automatic switch which, for example, is in one position during the high speed part of a run, and in a second position to select a lower car speed prior to landing.

Logic circuit 540 also includes output terminals DGU, DGD, ACC, SPS1 and SPS2. Output terminals DGU and DGD are connected to the "go up" and "go down" interface relays, respectively, which set the travel direction preference for the car, output terminal ACC is connected to the reversible counter 70 in floor selector 34, to the time ramp generator 542, to reversible counter 544, and to the distance slowdown circuit 546. Output terminals SPS1 and SPS2 are connected to the time ramp generator 542.

Logic circuit 540 also includes NAND gates 564, 566 and 570, AND gates 576 and 578, inverters 568, 572 and 574, and a flip-flop 580.

Input terminal UPTR is connected directly to an input of NAND gate 564, and via inverter 568 to an input of NAND gate 566. Input terminal ACCX is connected, via inverter 572, to inputs of NAND gates 564, 566 and 570. Input terminal A is connected, via inverter 574 to an input of NAND gate 570. The outputs

of NAND gates 564, 566 and 570 are connected to output terminals $\overline{DGU}$, $\overline{DGD}$ and ACC.

Input terminal SPSL is connected to the D input of flip-flop 580, which may be of the positive edge triggered D type. The clock input of flip-flop 580 is connected to output terminal ACC. The Q and $\overline{Q}$ outputs of flip-flop 580 are connected to inputs of AND gates 576 and 578, respectively. The output terminal ACC is connected to input terminals of AND gates 576 and 578.

In the operation of logic circuit 540, a true UPTR signal enables NAND gate 564, while a false or low UPTR signal enables NAND gate 566. When a request for the car to accelerate is made, signal $\overline{ACCX}$ goes low, which is inverted to a logic ONE by inverter 572, and either NAND gate 564 or NAND gate 566, depending upon which one has been enabled by signal UPTR, outputs a logic ZERO or true signal to its associated output terminal. Assuming that the car is set for up travel, UPTR will be high, enabling NAND gate 564. When the request is made to accelerate the car, NAND gate 564 will provide a logic ZERO to output terminal DGU, which drives the specific interface relay which sets the car for up travel.

When a request is made by the floor selector 34 to start and accelerate the car, signal $\overline{ACCX}$ goes low, and if the brake A is set, signal $\overline{A}$ will be low. Inverters 572 and 574 invert the low $\overline{ACCX}$ and $\overline{A}$ signals to switch NAND gate 570 to provide a low output, driving output terminal ACC high via inverter 575. A true ACC signal indicates a request has been made to accelerate the car, and the car is available, i.e., idle with the brake applied.

When signal ACC goes high it enables AND gates 576 and 578, and clocks the setting selected by the speed selector switch SPSL to the outputs of flip-flop 580, which "remembers" the speed selection. If the Q output is high, AND gate 576 outputs a high signal to its output terminal SPS1. If the $\overline{Q}$ output is high, AND gate 578 outputs a true signal to its output terminal SPS2.

Output terminal START is connected to the output of inverter 572, which, when terminal START goes high indicates a request to start the car has been made. Output terminal START is connected to the driver circuit 552.

FIG. 14

FIG. 14 is a schematic diagram of a time ramp generator which may be used for the time ramp generator 542 shown in FIG. 12. Time ramp generator 542 is a new and improved arrangement for providing at least the speed reference pattern for the acceleration and full speed phases of the run, and in relatively low speed elevator systems it may be used to provide the speed reference pattern for a complete run.

The time ramp generator 542 provides a speed reference signal which includes control over the maximum rate of change of acceleration, hereinafter termed "jerk," in the pattern itself. Regardless of how fast the car responds to the reference speed signal, the jerk in the car speed cannot exceed the maximum jerk built into the reference pattern.

Basically, the time ramp generator 542 generates a speed reference pattern which is jerk controlled, by double integration of a current signal which is representative of the jerk itself. With this arrangement, jerk, which passengers are more aware of than acceleration

or speed, is directly controlled, and is not subject to inaccuracies due to tolerances and drift in the circuit components used to perform mathematical calculations. The acceleration is indirectly controlled by integrating the jerk signal, and the car speed is indirectly controlled by integrating the acceleration signal, but small errors in acceleration and car speed due to circuit inaccuracies do not result in passenger discomfort, as might errors in control of jerk.

The measure of jerk for acceleration and deceleration is provided by positive and negative currents, respectively, with these currents being subject to an analog switch, which is switched in response to a feedback circuit which controls maximum acceleration and deceleration, as well as maximum speed. The switching rate of the analog switch when maximum acceleration or deceleration, or maximum speed, is reached, is too rapid for the car to respond thereto, and this switching averages the jerk to ZERO during these periods. During the transition periods between zero speed and maximum acceleration, between maximum acceleration and maximum speed, between maximum speed and maximum deceleration, and between maximum deceleration and zero speed, the analog switch is set by the feedback signal to apply the positive or negative current to the first integrator without switching, to provide a speed pattern reference during these transitional periods with an accurate directly controllable amount of jerk built into the speed pattern by the magnitudes of the positive and negative currents.

More specifically, the time ramp generator 542 includes input terminals SPS1, SPS2 and ACC, being output terminals TRAN, MINA, and MXVM. Input terminals SPS1, SPS2 and ACC are connected to logic circuit 540. Output terminal TRAN provides at least the acceleration and full speed portions of the speed pattern for the motor controller, output terminal MINA, which provides a true signal during maximum deceleration, is connected to the driver circuit 552, and output terminal MXVM, which provides a true signal when the speed pattern is at its maximum value, is connected to the counters 544 and 70, with the latter counter being hereinbefore described and shown in FIG. 5. FIG.

Time ramp generator 542 includes means 582 for directly representing jerk or rate of change of acceleration, such as adjustable positive and negative voltage sources 584 and 586, and an analog switch 587. The positive voltage source 584 is connected to a terminal 588 through the switch 587 and a voltage 589, and a negative voltage source 586 is connected to terminal 588 via a resistor 591. Thus, the value and direction of the current at terminal 588 may be controlled by opening and closing switch 587. The operation of switch 587 is controlled by a feedback circuit which includes conductor 590, with the switch 587 closing when the conductor 590 is at the logic ONE level, and opening when the conductor 590 is at the logic ZERO level.

The current at terminal 588 is a direct representation of jerk, and since its magnitude is set by the adjustable voltage sources 584 and 586, the jerk in the speed reference pattern to be developed will not exceed the preset jerk magnitude.

Terminal 588 is connected to first integrating means 592, such as an operational amplifier having a capacitor 593 in its feedback loop. If an operational amplifier is used, as illustrated in FIG. 14, terminal 588 is connected to its inverting input, and the non-inverting

input is grounded. Since the integral of jerk or rate of change of acceleration is acceleration, or deceleration, the output of the first integrator 592, at terminal 594, is representative of acceleration or deceleration.

Terminal 594 is connected to second integrating means 596, which may be an operational amplifier having an capacitor 595 in its feedback circuit, with terminal 594 connected to the inverting input thereof via resistor 597. The non-inverting input is grounded. The integral of acceleration or deceleration is speed, and thus the output of the second integrating means is representative of the speed. The output terminal 598 of the second integrating means 596 is connected to the output terminal TRAN.

Limits on acceleration, deceleration and speed with the direct and automatic control of jerk, are built into the speed reference pattern TRAN by acceleration and speed feedback circuits which control the switching of switch 587.

The speed feedback circuit compares the signal at the output terminal 598 of the second integrator 596 with a reference signal. The speed signal from terminal 598 is inverted by inverting means 600, which may be an operational amplifier with a resistor 606 in its feedback loop. Terminal 598 is connected to the inverting output of the operational amplifier via the resistor 608, and the non-inverting input is grounded through a resistor 604. The feedback and input resistors 606 and 608, respectively, are of like value, to provide an amplifier having a gain of -1.

The output terminal 602 of inverting means 600 is connected to first comparator means 610, which may be an operational amplifier, with output terminal 602 connected to the inverting input of the operational amplifier. The non-inverting input of the first comparator 610 is connected to a reference voltage via inverting means 612, speed demand selector means 614, and an analog switch 616.

Analog switch 616 includes first and second switches 618 and 620 driven by signals applied to input terminals SPS1 and SPS2, respectively. The signals SPS1 and SPS2 are provided by logic circuit 540, hereinbefore described. The outputs of the first and second switches 618 and 620 are connected to selected inputs of the speed demand selector 614, with each being connected to one end of a predetermined resistor thereof, such as resistors 622 and 624, respectively, which have a magnitude selected to provide predetermined car speeds. The other ends of the speed selector resistors, including a conductor 625 which has no additional resistance added thereto, and therefore represents the maximum speed selection, are connected in common to output terminal 628 of the speed demand selector 614. Output terminal 628 of the speed demand selector 614 is connected to the input of inverter means 612. Inverter means 612 may be an operational amplifier having a feedback resistor 630, with terminal 628 of speed demand selector 614 connected to the inverting input of the operational amplifier via a resistor 632. The feedback and input resistors 630 and 632, respectively, are of like value to provide a gain of -1. The non-inverting input of the operational amplifier is grounded via resistor 634. The output of inverter 612 appears across resistor 638 at terminal 636. Terminal 636 is connected to the non-inverting input of comparator 610. When the speed input to comparator 610 from terminal 602 is less than the reference input at input terminal 636,

the output of comparator 610 is positive, and this output is inverted by inverter 638 to appear at terminal 640 at the logic ZERO level. When the speed input to comparator 610 from terminal 602 exceeds the reference input at input terminal 636, the output of comparator 610 is negative, and this output is inverted by inverter 638 to appear at terminal 640 at the logic ONE level. Thus, terminal 640 is a logic ONE when the speed input exceeds the reference input and a logic ZERO when the reference input exceeds the speed input.

The acceleration feedback circuit from terminal 594 consists of two separate loops or circuits, one for acceleration, and one for deceleration. The circuit for acceleration includes inverter means 642 and comparator means 644. Inverter means 642 may be an operational amplifier having a feedback resistor 646, with the inverting input connected to terminal 594 via resistor 648. The non-inverting input is connected to ground via resistor 650. The feedback and input resistors 646 and 648, respectively, are of like value, to provide a gain of -1.

Output terminal 652 of inverter 643 is connected to the inverting input of inverter 600 through a resistor 653, which is large compared with the value of resistor 608, such as about 10 times larger. Thus, the acceleration and speed feedback loops are interconnected, with the value of the connecting resistor 653 being selected to prevent overshoot of the maximum speed during the transition from maximum acceleration to zero acceleration and maximum speed.

Output terminal 652 of inverter means 642 is also connected to the non-inverting input of comparator 644, and the inverting input of comparator 644 is connected to the selector arm 654 of an acceleration demand selector 656. Selector arm 654 is connected to a predetermined resistor of the acceleration demand selector, such as resistor 658, which has a value which provides the desired acceleration. When the acceleration input to comparator 644 from terminal 652 exceeds the reference input from the acceleration demand selector 656, the output of comparator 644 is positive, which is inverted by inverter 660 to appear at terminal 662 at the logic ZERO level. When the reference input exceeds the acceleration input, the output of comparator 644 is negative, which is inverted by inverter 660 to appear at terminal 662 at the logic ONE level. Thus, terminal 662 is at the logic ONE level when the reference exceeds the acceleration input, and at the logic ZERO level when the acceleration input exceeds the reference level.

Terminals 640 and 662, responsive to speed and acceleration, respectively, are connected to inputs of a NAND gate 664. Thus, either speed or acceleration, by providing a logic ZERO at terminals 640 and 662, respectively, can force the output of NAND gate 664 to the logic ONE level. The output of NAND gate 664 is connected to an input of NAND gate 666. The other input of NAND gate 666 is responsive to the deceleration feedback loop, as will be hereinafter explained, while the output of NAND gate 666 is connected to the feedback conductor 590, and thus the switching of NAND gate 666 controls the ON-OFF state of analog switch 582.

The feedback loop responsive to deceleration includes a comparator 668, which may be an operational amplifier having its non-inverting input connected to

terminal 594, and its inverting input connected to the selector arm 654 of the acceleration demand selector 656. Thus, during deceleration, the acceleration demand selector 656 controls the deceleration portion of the speed pattern. The output of comparator 668 is inverted by inverter 670, and the output of inverter 670 is connected to a terminal 672 which is connected to an input of NAND gate 666 and to output terminal MINA. Signal MINA is true during maximum deceleration.

The output of comparator 668 is positive when the deceleration input from terminal 594 exceeds the reference input, and negative when the reference input exceeds the deceleration input. Thus, terminal 672 is at the logic ONE level when the reference exceeds the deceleration input, and at the logic ZERO level when the deceleration input exceeds the reference input. As will be hereinafter explained, terminal 672 will be at the logic ONE level, except during deceleration. Thus, except during deceleration, NAND gate 666 acts as an inverter for the output of NAND gate 664, with the acceleration or speed inputs to NAND gate 664 controlling the switching of the feedback switch 587. Once deceleration is initiated, the output of NAND gate 664 is at the logic ONE level, enabling the NAND gate 666 to be controlled by the deceleration feedback from terminal 672.

As will be explained during the description of the operation of the time ramp generator 542, the output of comparator 610 switches rapidly during the maximum speed portion of the speed reference signal. In order to provide a definite signal which indicates that the maximum speed phase of the speed reference signal is taking place, a memory circuit 670 is provided which is connected to input terminal ACC and to terminals 662 and 640 which are responsive to the acceleration and speed feedback, respectively. The output of memory circuit 670 is connected to output terminal MXVM, which provides a low or true signal only during the maximum speed phase of the speed reference signal TRAN.

Memory circuit 670 includes a NAND gate 672 which has an input connected to terminal 640 via an inverter 674, and an input connected to an output from a flip-flop 676 via an inverter 678. Flip-flop 676 may be of the cross-coupled NAND gate type, having NAND gate 680 and 682. NAND gate 680 has an input connected to terminal 662, and NAND gate 682 has an input connected to input terminal ACC.

The output of NAND gate 672 is connected to a flip-flop 684. Flip-flop 684 may be of the J-K type, which, with positive logic, operates to set Q to the logic ONE level with a low input to the PRESET terminal, and sets Q to the logic ZERO level with a low input to the CLEAR terminal. The output of NAND gate 672 is connected to the PRESET input, the input terminal ACC is connected to the CLEAR input, the J, C and K inputs are grounded, and the Q output is connected to output terminal MXVM via inverter 686. The operation of the memory circuit 670 will be described after the operation of the time ramp generator in developing the speed reference pattern is described.

FIG. 15

FIG. 15, which includes FIGS. 15A and 15B, is a graph which illustrates waveforms at various circuit points of the time ramp generator 542 shown in FIG.

14. FIG. 15 will be referred to while describing the circuit operation of the time ramp generator 542.

It will first be assumed that the elevator car is at rest and there is no demand for service. Thus, signals SPS1, SPS2 and ACC will be at the logic ZERO level. With zero volts into operational amplifier 612, there will be zero volts at its output 636, as indicated in FIG. 15B at 689 of the waveform for operational amplifier 612. If switch 587 is open, as indicated at 690 on the "open-closed" graph of switch 587 in FIG. 15A, current will flow out of the inverting input of the first integrator 592 and the output of the first integrator 592 will start to go positive, as indicated at 692 of the waveform for the output of the first integrator 592. When the output of the first integrator 592 goes positive, the output of the second integrator 596 will go negative, as indicated at 694 of the curve for the second integrator 596. The output of the operational amplifier 600 will thus go positive, as indicated at 696. The positive output of operational amplifier 600 is applied to the inverting input of comparator 610 (FIG. 15B), and it is compared with the ZERO input at the non-inverting input from operational amplifier 612. Since the speed signal from operational amplifier 600 exceeds the speed reference signal from operational amplifier 612, the output of comparator 610 goes negative, as indicated at 698 on the curve for comparator 610. The negative output of comparator 610 is inverted to the logic ONE level by inverter 638, indicated at 700 for the graph for inverter 638, which is applied to an input of NAND gate 664.

The acceleration demand selector 656 is providing a positive voltage at the inputs of comparators 668 and 644. Since the car is not accelerating or decelerating at this time, the reference voltage exceeds the acceleration and deceleration signals and the outputs of comparators 668 and 644 are negative, as indicated at 702 and 704, respectively, on the graphs associated with these comparators. The negative output of comparator 668 is inverted to the logic ONE level by inverter 670, as indicated at 706 of the graph for inverter 670, and the negative output of comparator 644 is inverted by inverter 660 to the logic ONE level, indicated at 708 of the graph for inverter 660. The logic ONE output of inverter 660 is applied to the other input of NAND gate 664, and the logic ONE output of inverter 670 is applied to an input of NAND gate 666.

Thus, when the car is at rest and switch 587 is open, both inputs of NAND gate 664 go high, driving the output of NAND gate 664 from the logic ONE level, indicated at 710, to the logic ZERO level, indicated at 712. When the output of NAND gate 664 goes low, the output of NAND gate 666 is switched from the logic ZERO level, indicated at 714, to the logic ONE level, indicated at 716. When the output of NAND gate 666 goes high, analog switch 587 closes, as indicated at 718 (FIG. 15A).

When the analog switch 587 closes, the jerk current will flow into the inverting input of the first integrator 592, driving the output of the first integrator 592 negative, as indicated at 720. The output of the second integrator 596 thus starts to go positive, indicated at 722, and the output of operational amplifier 600 starts to go negative, as indicated at 724. The inverting input of speed comparator 610 will thus become less than the ZERO input from the speed reference circuit, and the output of comparator 610 will go positive, indicated at 726 (FIG. 15B). This positive output of comparator

610 is inverted to the logic ZERO level by inverter 638, indicated at 728, the output of NAND gate 664 is driven high at 730, the output of NAND gate 666 is driven low by the two high inputs, indicated at 732, and the analog switch 587 opens as indicated at 734 (FIG. 15A). This switching of the analog switch 587 occurs at a very rapid rate which is determined by the threshold of comparator 610 and the characteristics of the integrators 592 and 596. The switching rate, which will usually be greater than 1 KHz., is much too fast for the car to respond thereto, so it has no adverse affect on the car movement. The rapid switching of switch 587 is illustrated in the waveforms of FIGS. 15A and 15B as being a low rate in order to more clearly illustrate how the condition of switch 587 affects the various circuit actions.

The rapid switching of analog switch 587 continues, due to the speed feedback and comparator 610, while the car is at rest with no request to accelerate, which phase of the car operation will be referred to as phase I. The various phases of a complete run are indicated at the top of FIG. 15A.

Phase II is initiated when there is a request to accelerate the car, signalled by ACC and either SPS1 or SPS2 switching from a logic ZERO level to a logic ONE level at 736. For purposes of example, it will be assumed that the speed selector switch is set to provide a true SPS1 signal when the ACC signal does true. A true SPS1 signal closes analog switch 618 and the output of operational amplifier 612 goes negative at 738 (FIG. 15B). Since the output of operational amplifier 600 is near ZERO, it is more positive than the negative output of operational amplifier 612, and the output of comparator 610 goes negative, indicated at 740. The output of inverter 638 goes to a logic ONE level, indicated at 742, the output of NAND gate 664 goes to the logic ZERO level, indicated at 744, the output of NAND gate 666 goes to the logic ONE level, indicated at 746, and the analog switch 587 closes, indicated at 748 (FIG. 15A).

The rapid switching of analog switch 587 which averaged jerk to ZERO and also maintained the acceleration and speed signals at ZERO, now ceases, and switch 587 remains closed until the selected acceleration demand is reached. When switch 587 closes, the positive input to the inverting input of operational amplifier 592 drives the output of the operational amplifier negative with a slope 750 determined by the pre-selected jerk magnitude. Thus, the output of operational amplifier 592, which is the first integral of jerk, provides the acceleration pattern, and the rate of change of this acceleration pattern cannot exceed the preselected value.

The linearly decreasing output of operational amplifier 592 is integrated by the second integrator or operational amplifier 596, to provide a smooth curved transition 751 from zero to a predetermined speed when maximum acceleration is reached.

Operational amplifier 642 inverts the output of the second integrator 592, and applies a positive signal, indicated at 752, to the non-inverting input of comparator 644. The increasing magnitude of the positive signal 752 is compared with the constant positive acceleration demand signal applied to the other input of comparator 644, and when the acceleration signal 752 exceeds the acceleration reference, at point 754, the output of comparator 644 switches from the negative voltage level 704 to a positive voltage level 756. Inverter

660 switches from the logic ONE level 708 to the logic ZERO level 758. The output of NAND gate 664 thus goes from the logic ZERO level to the logic ONE level at 760, the output of NAND gate 666 goes low at 762, and switch 587 opens at 764. This ends phase II and initiates phase III of the run.

In phase III, the acceleration is held constant by rapid switching of switch 587 due to comparator 644. The car speed, indicated by the output of the second integrator 596, however, is increasing due to the constant acceleration. When the car speed reaches the selected speed demand, phase III is terminated and phase IV is initiated.

More specifically, when switch 587 opens at 764, operational amplifier 592 starts to go less negative, operational amplifier 642 starts to go less positive, dropping below the acceleration demand reference level, and the output of comparator 644 goes negative. The output of inverter 660 goes to a logic ONE, NAND gate 664 goes low, and the output of NAND gate 666 goes high to close switch 587. This drives the acceleration signal higher than the acceleration reference signal, again opening the switch 587. This rapid switching of switch 587 continues, holding the output of operational amplifier 592 at a predetermined maximum negative level 766, and the output of operational amplifier 642 at the predetermined positive level 754. The constant negative input into the second integrator 596 causes the output of the second integrator 596 to increase linearly during phase III, indicated at 768, although switching at the same rapid rate as switch 587. Inverter 600 inverts the output of the second integrator 596, and applies a negative signal 770 to comparator 610. When the decreasing signal 770 reaches the negative speed reference level at the other input to comparator 610, indicated at point 771 on the graph for inverter 600, the output of comparator 610 switches from a negative to a positive level at 772. The output of inverter 638 switches to a logic ZERO level at 774, the output of NAND gate 664 goes high at 776, the output of NAND gate 666 goes low at 778, and the analog switch 587 opens at 780. This ends phase III.

It will be noted that the positive input to inverter 600 in the speed feedback circuit from the second integrator 596 is aided during phase III by the positive output from inverter 642 in the acceleration feedback circuit. This interaction of the acceleration and speed feedback circuits causes the output of inverter 600 to reach the speed demand level at 771 slightly faster than it would without such interaction, and while it overshoots the speed reference level, it prevents overshoot of the speed reference pattern 596 during the transition from the period of increasing car speed to the period of constant car speed during phase IV.

When switch 587 opens at 780 to end phase III and start phase IV, the output of the first integrator 592 linearly increases from the constant negative level 766 towards zero along line 782. The slope of line 782, and thus the rate of change of acceleration is determined by the preselected jerk setting.

The second integrator 596 provides a smooth, curved transition 784 from the linearly increasing portion 768 to a constant portion 786. As the output from the second integrator 596 smoothly flattens out, the aid from inverter 642 received by inverter 600, determined by the value of resistor 653, is reduced to zero along line 788, enabling the output of inverter 600 which over-

shoots the speed reference level, to return to the speed demand level at the time the speed pattern 596 is arriving at the speed reference level. Thus, during phase IV, the portion 790 of the output of inverter 600 is slightly below the reference level. When the output of inverter 600 increases to the reference level, comparator 610 switches from a positive to a negative output at 792 which in turn drives inverter 638 high, NAND gate 664 low, and NAND gate 666 high, to close switch 587 and end phase IV.

Phase V consists of rapid switching of analog switch 587 in response to comparator 610, to maintain the output of the second integrator 596 constant at the level 786. When the switch 587 closes at the start of phase V, the output of the first integrator 592 becomes negative, the output of the second integrator 596 becomes more positive, the output of inverter 600 becomes more negative, and when it reaches the speed reference level, the output of comparator 610 goes positive, inverter 638 goes to logic ZERO, the outputs of NAND gates 664 and 666 go high and low, respectively, and gate 587 opens at 796. This starts the chain of events which closes switch 587, causing a rapid switching of analog switch 587 during phase V, which maintains the car speed constant.

Phase V is terminated when a request is made by the floor selector to stop the car at the floor of the advanced car position, signified by signals ACC and SPS1 going to the logic ZERO level at 800. This starts phase VI, which is a smooth transition from a maximum constant speed to maximum deceleration. When signal SPS1 goes to ZERO, the speed demand input to operational amplifier 612 goes to ZERO, and the output of operational amplifier 612 switches from the speed demand reference level 738 to zero at 802. Since the car speed is above the reference level, the output of comparator 610 goes positive at 804, driving the output of inverter 638 low at 806, and the output of NAND gate 664 high at 808. The other input to NAND gate 666, from the deceleration feedback circuit is still a logic ONE, and NAND gate 666 switches low at 810 to open switch 587 at 812.

When switch 587 opens at 812, the output of the first comparator increases from zero along a curve 814, which has a slope determined by the jerk setting. The output of the second integrator 596 smoothly drops from the maximum speed level 786 to a slower speed along curve 816. When the deceleration of the car reaches the deceleration demand level, signified by portion 814 of the acceleration signal at the output of the first integrator 592 reaching the magnitude of the acceleration demand reference, comparator 668 switches its output from a negative level 702 to a positive level 818. Inverter 670 switches to the logic ZERO level at 820, the output of NAND gate 666 goes high at 822, and switch 587 closes at 824. This ends phase VI, and starts phase VII, which is the constant deceleration phase of the run.

When switch 587 closes at the start of phase VII, the output of the first integrator 592 drops, and when it drops below the deceleration reference level, the output of comparator 668 switches to a negative output, inverter 670 goes to a logic ONE, the output of NAND gate 666 goes to logic ZERO, and switch 587 opens. This then starts the chain of events which recloses the switch 587, and switch 587 switches rapidly between its open and closed states to maintain the output of the

first integrator at the selected maximum positive value 826. The constant positive output of the first integrator 592 causes the second integrator 596 to decrease linearly along a curve 828, and inverter 600 increases towards zero. The increase in the output of inverter 600 towards zero along curve portion 830 is aided by the negative portion 832 of the output of inverter 642, causing the curve 830 to reach the ZERO level ahead of the output of the second integrator 596, preventing overshoot of the speed pattern beyond the reference level in the same manner hereinbefore described relative to phase IV. When curve portion 830 reaches the threshold of comparator 610, at point 834, the output of comparator 610 switches from a positive to a negative level at 836, the output of inverter 638 switches to a logic ONE level at 838, the output of NAND gate 664 goes to logic ZERO at 840, the output of NAND gate 666 goes high at 842, and the feedback switch 587 closes at 844, to end phase VII and initiate phase VIII.

Phase VIII is the transition from maximum deceleration to zero car speed. When switch 587 closes at the start of phase VIII, the output of the first integrator 592 decreases along curve 846, with a constant slope determined by the jerk setting, the second integrator provides a smooth curved transition 848 from maximum deceleration towards zero car speed, and the combination of the outputs of the second comparator and operational amplifier 642, the latter of which is increasing towards ZERO along curve 850, prevents operational amplifier 600 from dropping back to the reference level until the car comes to a smooth stop at 852. When the car stops, phase VIII is terminated, and phase I is initiated.

The memory circuit 670 provides a false or high MXVM signal until comparator 610 indicates maximum velocity has been reached, at which time, as indicated in FIG. 15B, signal MXVM switches true or low at point 854. When the car is at rest, the output of inverter 660 is high, which enables flip-flop 676, and the signal ACC is low, which sets flip-flop 676 to provide a logic ONE level at the output of NAND gate 682, which is inverted to the logic ZERO level by inverter 678. NAND gate 672 thus supplies a logic ONE to the PRESET input of flip-flop 684. The low ACC signal applied to the CLEAR input of flip-flop 684 sets flip-flop 684 to provide a logic ZERO at the Q output, which is inverted to a logic ONE at output terminal MXVM. When acceleration is requested, signal ACC goes to logic ONE, enabling flip-flops 676 and 684. When maximum acceleration is reached, inverter 660 goes low at 758 to switch flip-flop 676, and inverter 678 now provides a logic ONE to one of the inputs of NAND gate 672. When the comparator 610 switches positive to indicate maximum speed has been reached, inverters 638 and 674 apply a logic ONE to the other input of NAND gate 672, and the output of NAND gate 672 goes low, switching flip-flop 684 to provide a high Q output, which is inverted to a low or true MXVM signal. When signal ACC goes to ZERO, flip-flop 676 is switched again, to cause NAND gate 672 to output a logic ONE, and the logic ZERO at the CLEAR input switches flip-flop 684 to provide a low Q output, which is inverted to provide a high MXVM signal, as indicated at 856 in FIG. 15B.

FIG. 16

FIG. 16 is a graph which presents the jerk, accelera-

tion and speed curves shown in FIG. 15, except without the rapid switching shown in FIG. 15. The jerk curve represents the input to the first comparator 592 from terminal 588. During the rapid switching of the switch 587, the jerk is averaged to zero. When the switch is closed, positive jerk restraint is applied, and when it is open negative jerk restraint is applied.

The speed curve, i.e., the output of the second comparator 596, may be used for the complete run of the car for relatively low speed elevator systems, as it provides a speed pattern for all phases of a run. On high speed elevator systems, above about 500 ft./min., the speed pattern provided by the time ramp generator would not be accurate enough during the deceleration and landing phases of the run. Thus, as shown in FIG. 12, the speed pattern generator 58 includes, in addition to the time ramp generator 542, a distance slowdown circuit 546, and a hatch transducer circuit 554. As shown in FIG. 16, the speed pattern signal SRAT from the speed pattern generator 48 may be a composite signal, including a portion 860 from the time ramp generator which includes phases I through VI, a portion 862 from the distance slowdown circuit 546, which includes phase VII, and a portion 864 from the hatch transducer circuit 554, which includes phase VIII.

FIGURE 17

FIG. 17 is a schematic diagram of a reversible counter and a distance slowdown circuit which may be used for the reversible counter 544 and distance slowdown circuit 546 shown in block form in FIG. 12. The distance slowdown circuit shown in FIG. 17 is a new and improved arrangement for accurately bringing the car to the landing or leveling zone, despite long term drift of circuit constants. The driver circuit 552 switches the source of the speed pattern from the time ramp generator 542 to the distance slowdown circuit 546 when signal MINA goes to ZERO, indicating that maximum deceleration has been reached. Just prior to this time, the distance slowdown circuit shown in FIG. 17 is automatically calibrated, but not for the position of the car at that time. The distance slowdown circuit is calibrated for the count which represents the point where the car will be when the speed pattern should transfer from the distance slowdown circuit to the hatch transducer circuit. This is the only point that extreme accuracy is required, and by calibrating the distance slowdown circuit for this specific distance to the floor, which calibration occurs just before the circuit is utilized, the distance slowdown circuit need not be designed to maintain freedom from drift over a long period of time, and the resulting apparatus may therefore be constructed more economically.

More specifically, the counter 544 shown in FIG. 17 includes input terminals IDLE, MXVM, ACC, and NLC, and output terminals NL1 through NL12, and NL16. Input terminal IDLE receives a high or true signal when the car is idle, ready to make a run, input terminal MXVM receives a low or true signal from the time ramp generator 542, when the car is in the maximum speed portion of its run, input terminal ACC receives a high or true signal when a request is made to accelerate the car and the brake relay is picked up, and it remains true until the car is requested to slow down, and input terminal NLC receives distance pulses; such as one distance pulse for each one-half inch of car

travel, from the reversible counter 70 in the floor selector 34.

Counter 544 includes reversible counting means 870, such as a binary counter, having a sufficient bit capacity to count to the maximum distance in terms of the standard increment, over which the elevator car is accelerated. For example, three synchronous 4-bit UP/DOWN binary counters 872, 874 and 876 may be cascaded to provide a 12-bit counter sufficient to count to about 170 feet, using 0.5 inch for each pulse, but any number of bits may be used, depending upon the requirements of the specific application.

The CARRY and BORROW outputs of counter 872 are connected to the UP and DOWN inputs of counter 874, respectively, and the CARRY and BORROW outputs of counter 874 are connected to the UP and DOWN inputs of counter 876. The CLEAR inputs of counters 872, 874 and 876 are connected to the input terminal which receives the IDLE signal. When the IDLE signal is true or high, all outputs are forced to the low level.

The UP and DOWN inputs of counter 872 are connected to receive NLC pulses via a circuit which includes input terminals NLC and MXVM, inverters 902 and 904, and NAND gates 906, 908, 910 and 912.

NAND gate 906 has an input connected directly to input terminal MXVM, and another input connected to input terminal NLC via inverter 902. NAND gate 908 has an input connected to input terminal NLC via inverter 902, and another input connected to the BORROW output terminal of counter 876, which output terminal is at the logic ONE level, except when the counter 876 counts down and reaches zero. The outputs of NAND gates 906 and 908 are connected to inputs of NAND gates 910 and 912, respectively. NAND gate 910 also has an input connected to input terminal ACC, and NAND gate 912 has an input connected to input terminal ACC via an inverter 904. The outputs of NAND gates 910 and 912 are connected to the UP and DOWN inputs, respectively, of counter 872.

The A, B, C and D outputs of counter 872 are connected to inputs of NAND gates 878, 880, 882 and 884, respectively, the A, B, C and D outputs of counter 874 are connected to inputs of NAND gates 886, 888, 890 and 892, respectively, and the A, B, C and D outputs of counter 876 are connected to NAND gates 894, 896, 898 and 900, respectively. The B, C and D outputs of counter 874 and the A, B, C and D outputs of counter 876 are also connected to inputs of a NAND gate 948 via inverters 950, 951, 952, 953, 954, 955 and 956, respectively. The output of NAND gate 948 is connected to an output terminal NL16.

NAND gates 878, 880, 882, 884, 886, 888, 890, 892, 894, 896, 898 and 900 also each have an input connected to the output terminal 999 of a circuit which includes input terminal ACC, the BORROW output of counter 876, inverters 914 and 916, an AND gate 918, a NAND gate 920, and a monostable multivibrator 922. The AND gate 918 has one input connected to input terminal ACC via inverter 914, and another input connected to the BORROW output of counter 876. The output of AND gate 918 is connected to inputs of the NAND gate 920 and of the monostable multivibrator 922. Another input of NAND gate 920 is connected to the output of the monostable multivibrator 922. The output of NAND gate 920 is connected to output terminal 999 via inverter 916.

The outputs of NAND gates 882 and 886 are connected to inputs of NAND gates 928 and 932, respectively. NAND gates 928 and 932 also have inputs connected to terminal 999. The outputs of NAND gates 928 and 932 are connected to output terminals NL3 and NL5, respectively. The remaining NAND gates 878, 880, 884, 888, 890, 892, 894, 896, 898 and 900 are connected to output terminals NL1, NL2, NL4, NL6, NL7, NL8, NL9, NL10, NL11 and NL12, respectively, via inverters 924, 926, 930, 934, 936, 938, 940, 942, 944 and 946, respectively.

In the operation of counter 544 it will be assumed that the elevator car is idle and ready to make a run, in which case input terminal IDLE receives a true or high signal which forces the 12 outputs of counter 870 to the logic ZERO level. When the car is requested to accelerate, the signal IDLE goes to logic ZERO, enabling counter 870, the accelerate signal ACC goes to the logic ONE level, and the time ramp generator 542 provides the speed pattern which initiates car movement. When the car starts to move, an NLC pulse is provided at input terminal NLC for each standard increment of car travel, such as 0.5 inch. Input terminal MXVM is at the logic ONE level, since the car is not at maximum speed, and the BORROW output B of counter 876 provides a signal which is at the logic ONE level. Thus, both NAND gates 906 and 908 are gated by the NLC pulses. During acceleration, signal ACC is at the logic ONE level, which gates the NLC pulses through NAND gate 910 to the count up input of counter 872. The inverter 904 inverts the true ACC signal to block NAND gate 912. When the car reaches maximum speed, MXVM goes to logic ZERO, as hereinbefore described and shown in the graph of FIG. 15, which blocks NAND gate 906 and prevents the NLC pulses from reaching the counter 870.

When signal ACC goes to logic ZERO, requesting deceleration, signal MXVM goes back to logic ONE but NAND gate 910 is now blocked by the low ACC signal. The inverter 904 inverts the low ACC signal and passes the NLC pulses through NAND gate 912 to the count down input of counter 872. Thus, the output of counter 870 has a count at its output terminals which continuously registers the distance to go to the floor. It stops counting the NLC pulses when the car stops accelerating, and it counts down when the car starts decelerating. With like rates of acceleration and deceleration, the counter accurately registers the distance to go to the floor of the advanced car position when the signal ACC goes to logic ZERO.

When the counter 870 counts down to the binary number representing 32, which indicates the car is 16 inches from the floor at which it is to land, the B, C and D outputs of counter 874 and the A, B, C and D outputs of counter 876 will be at the logic ZERO level. These ZERO outputs are inverted by inverters 950, 951, 952, 953, 954, 955 and 956 to switch NAND gate 948 and provide a low NL16 signal, indicating the car is within 16 inches of the floor at which it is to stop.

When slowdown is initiated, the distance slowdown circuit 546 shown in FIG. 17 provides a speed pattern responsive to the square root of the signal having the magnitude proportional to the distance to go to the floor, with the speed pattern transferring from the time ramp generator 542 to the distance slowdown circuit 546 through the operation of analog switches 548 and 550 and driver 552 shown in FIG. 12. Thus, the output

of counter 870 is not used until slowdown is initiated, and it is then used until the speed pattern switches from the output of the distance slowdown circuit 546 to the output of the hatch transducer circuit 554 when the car is a predetermined distance from the floor, which for purposes of example will be assumed to be 10 inches. When the car is slowing down to land and it is 10 inches from the floor, it is important, in order to avoid a jerky landing, that the output voltages of the distance slowdown circuit 546 and the hatch transducer circuit 554 match when the transfer is made at the 10 inch point by the analog switches 550 and 556. In order to insure a good match, the square root device used in the distance slowdown circuit would have to have an accuracy of ± 0.05 percent. A square root device with this accuracy, however, would be relatively costly to manufacture.

FIG. 17 illustrates a new and improved distance slowdown circuit which provides the necessary accuracy at the 10 inch transfer point, without the necessity of using a highly accurate, high cost square root device. An inexpensive square root device, such as an operational amplifier with a low cost analog multiplier in its feedback loop, will hold its calibration over the period of time that it takes to decelerate an elevator car and bring it to a stop at a landing. This characteristic, along with the fact that the output of the reversible counter 870 is only used during the slowdown phase of the elevator run, is used to provide a low cost distance slowdown circuit which will give the required 0.05 percent accuracy at the 10 inch transfer point when the transfer is made.

More specifically, the reversible counter 544 is modified to output the binary signal 10100 for number 20, which represents the transfer distance 10 inches, prior to the deceleration stage of the run, and then switch over to provide the actual count of the counter 870 when deceleration is requested.

When the signal ACC is low, AND gate 918 has two logic ONE inputs, one from the BORROW output of counter 876, and one from input terminal ACC via inverter 914. The monostable multivibrator 922, such as Texas Instrument SN 74121, has its Q output connected to an input of NAND gate 920, and thus is providing an output at the logic ONE level. The two logic ONE inputs to NAND gate 920 provide a logic ZERO output, which is inverted to the logic ONE level by inverter 916. Thus, terminal 999 is at the logic ONE level, which enables NAND gates 873 through 900 and NAND gates 928 and 932.

When the car is requested to accelerate, signal ACC goes high, AND gate 918 switches low, NAND gate 920 switches high, and inverter 916 provides a logic ZERO at terminal 999. NAND gates 878 through 900 all provide a logic ONE at their outputs, which signals are inverted by inverters 924, 926, 930, 934, 936, 938, 940, 942, 944 and 946 to the logic ZERO level. NAND gates 928 and 932, however, provide outputs at the logic ONE level. Thus, when signal ACC is high, output terminals NL1 through NL12 output the binary number for 20 or 10100, representing the 10 inch transfer point. When the signal ACC goes low, the output of AND gate 918 again goes high, which triggers the monostable multivibrator 922 to provide a low pulse of predetermined duration, which thus holds NAND gate 920 high and terminal 999 low for the duration of the

monostable pulse, for reasons which will be hereinafter explained.

Should the counter 870 for some reason count down to ZERO before reaching the 10 inch transfer point, the distance slowdown circuit would take the square root of ZERO, which is ZERO, and the speed pattern would be at ZERO voltage and the car would not run. However, with the arrangement shown in FIG. 17, wherein the BORROW output of counter 876 is connected to an input of AND gate 918, the counter 544 will be forced to output a binary count of 20 when the counter 870 counts down to and reaches zero. If the car has not reached the 10 inch transfer point, this count will provide a voltage output from the distance slowdown circuit, running the car in the same direction as its previous travel direction until the transfer point or the floor is reached. The BORROW output of counter 876 goes to ZERO when the counter 876 counts down to zero, which starts the same sequence described when the signal ACC went to ZERO.

The distance slowdown circuit 546 shown in FIG. 17 includes a digital to analog converter 960, inverter means 962, a square root device 964, inverter means 966 and 968, and a sample and hold circuit 970.

The digital to analog converter 960 is a linear converter which provides a predetermined unidirectional output voltage when its input terminals NL1 through NL12, which are connected to the like numbered output terminals of counter 544, are all at the logic ONE level, and proportionally less voltage as the binary count is reduced.

The output of converter 960 is applied to inverter means 962, which may be an operational amplifier having a resistor 972 in its feedback loop. The output of converter 960 is connected to the inverting input of operational amplifier 962 via resistor 973, and its non-inverting input is connected to ground via a resistor 974. The output of operational amplifier 962 is connected to square root device 964 via a selector 976, which includes a selector arm 978 and a plurality of resistors 980. Selector 976 is used to provide a choice in deceleration characteristics.

The square root device 964 may be of any suitable type, such as an operational amplifier 982 having an analog multiplier 984 and resistor 986 in its feedback loop. The selector 976 is connected to the inverting input of operational amplifier 982, and the non-inverting input is connected to an adjustable voltage source 988. Thus, if the source 988 is adjusted to zero, in the absence of a voltage from operational amplifier 962, the output of operational amplifier 982 and the output of multiplier 984 will be zero, as the inputs are balanced. If the output of operational amplifier 962 increases from zero to $-X$ volts, the output of the multiplier 984 will be $+X$ volts, in order to keep the inputs of operational amplifier 982 balanced, and the input to the multiplier 984 must therefore be the $\sqrt{X}$ volts. If the source 988 is not adjusted to ZERO, the output of the operational amplifier 982 will be proportional to the square root of the input from the operational amplifier 962, with a bias added thereto depending upon the setting of the adjustable voltage source 988.

The output from operational amplifier 982, which as hereinbefore stated is proportional to the square root of the input thereto, is applied to inverter means 966 via resistor 989. Inverter means 966 may be an operational amplifier having its inverting input connected to

resistor 989, a resistor 990 in its feedback loop which is equal to resistor 989 in magnitude in order to provide a gain of -1 , and its non-inverting input connected to ground via resistor 992.

The output of operational amplifier 966 is connected to inverting means 968 via resistor 994. Inverting means 968 may be an operational amplifier having its inverting input connected to resistor 994, its non-inverting input connected to ground via resistor 996, and a resistor 998 in its feedback loop which is equal in magnitude to resistor 994, to provide a gain of -1 . The output of operational amplifier 968 provides the speed pattern voltage during slowdown, and is thus connected to output terminal DSAN.

A selector 1000 may be provided to add a bias voltage to the input of operational amplifier 968, to select different deceleration characteristics. Selector 1000, for example, may include a source voltage 1002 selectively connected to one of the plurality of resistors 1004 via a selector arm 1006.

The sample and hold circuit 970 includes comparator means 1008, which may be an operational amplifier having Zener diodes 1010 connected in its feedback loop, and its inverting input connected to a reference voltage which includes a source 1012 of unidirectional potential and a resistive divider circuit 1014. The reference voltage is selected to be equal to the desired value of the output voltage DSAN when the count of the counter 544 reaches the magnitude which indicates the car is at the distance to the floor where the hatch transducer takes over in supplying the speed reference pattern. As hereinbefore used as an example, the reference voltage would be the voltage which should appear at the output terminal DSAN when the count of counter 870 is the binary number for 20, representing a distance of 10 inches from the floor. The non-inverting input of operational amplifier 1008 is connected to the output terminal DSAN, via resistor 1016, which provides the necessary feedback information as to the value of the signal DSAN, and the affect of the sample and hold circuit on the signal DSAN.

Any deviation of the output voltage at terminal DSAN from the reference voltage provided by source 1012 and divider 1014, results in the output of operational amplifier 1008 changing in the direction necessary to balance the inputs. The sample and hold circuit 970 is operatively connected to sample the voltage appearing at terminal DSAN, when the car is accelerating and during the constant speed portion of its run. This is the time that the counter 544 is outputting the binary number for 20 representing the switchover distance from the distance slowdown circuit 546 to the hatch transducer circuit 554. During this time, the calibration voltage necessary to force the voltage at output terminal DSAN to equal the reference voltage is developed and stored. Just prior to the counter 544 changing from the forced output count to the actual count of counter 870, the feedback portion of the sample and hold circuit is disconnected from the storage portion, such that the calibration voltage for the switchover point may be maintained during the distance slowdown without being affected by the output of counter 544 when it switches to the count of counter 870. This bias or calibration voltage for the switchover point between the distance slowdown signal DSAN and the hatch transducer signal HTAN has no adverse affect on the operation of the car while it is decelerating from its maxi-

imum speed to the switchover point, as its value is insignificant when the output count of counter 544 is relatively high. The calibration voltage only becomes important when the countdown nears the switchover distance, and it assures transfer between the distance slowdown and hatch transducer signals without a discontinuity which would cause a jerky landing.

The proper sequencing of the sample and hold circuit 970 with the output of counter 544 may be accomplished by using a high ACC signal to activate the sample and hold circuit, and to disconnect the feedback portion of the sample and hold circuit from the storage portion when the ACC signal goes low at the time deceleration is requested. This is when the monostable multivibrator 922 becomes important, as it delays the switching of the counter 544 from its forced to its actual count when the ACC signal goes low, for a time sufficient for the sample and hold, in response to the low ACC signal, to disconnect the sampling function from its holding function.

The circuit functions of the sample and hold circuit 970 may be provided by an inverter 1018, a PNP transistor 1020, an NPN transistor 1022, two N-channel field effect transistors 1024 and 1026, and a capacitor 1028. The emitter electrode of transistor 1020 is connected to input terminal ACC via the inverter 1018 and a resistor 1030, the base of transistor 1020 is connected to ground, and its collector electrode is connected to the base electrode of transistor 1022. The emitter electrode of transistor 1022 is connected to its base electrode via resistor 1032 and to a source 1033 of negative unidirectional potential. The collector of transistor 1022 is connected to the gate electrode G of field effect transistor 1024. The gate electrode G of field effect transistor 1024 is also connected to the output of comparator 1008 via resistor 1036. The source S of transistor 1024 is connected to the output of comparator 1008, and its drain D is connected to the gate of transistor 1026. The capacitor 1028 is connected from the interconnected drain and gate electrode of transistors 1024 and 1026 to ground. The drain of transistor 1026 is connected to a source 1037 of positive unidirectional potential, and its source is connected to the inverting input of operational amplifier 986 via resistor 1038, and to the source 1033 of negative unidirectional potential via resistor 1034.

When input terminal ACC goes high, counter 544 switches to its forced count, as hereinbefore described, and inverter 1018 cuts off transistors 1020 and 1022, providing a zero voltage between the source and gate of transistor 1024, switching the channel of transistor 1024 to its low impedance condition. Thus, the output of comparator 1008, which goes to the value necessary to balance its inputs, is effectively connected to charge capacitor 1028. Capacitor 1028, connected to the gate of transistor 1026, causes transistor 1026 to conduct in accordance with the magnitude of the charge on capacitor 1028, and apply a calibration voltage to the inverting input of operational amplifier 986. When the output of operational amplifier 986 is equal to the reference voltage at the inverting input of comparator 1008, the charge on capacitor 1028 becomes stabilized, as does the calibration voltage applied to the inverting input of operational amplifier 986.

When the signal ACC goes low when deceleration is requested, inverter 1018 applies a positive voltage to transistor 1020, causing it to conduct and provide base

drive for transistor 1022. Transistor 1022 conducts and connects the gate of transistor 1024 to the source 1033 of negative unidirectional potential, switching transistor 1024 to its high impedance condition, and effectively disconnecting the output of comparator 1008 from the capacitor 1028. The monostable multivibrator 922 holds the counter 544 at its forced count for a time sufficient to enable the capacitor 1028 to become isolated from the output of comparator 1008. The capacitor 1028 remains charged during slowdown, with very little leakage due to the high input impedance of transistor 1026, while biasing transistor 1026 to provide the calibration voltage necessary to match the output of operational amplifier 986 with the output of the hatch transducer at the distance from the floor where the speed pattern switches from the distance slowdown circuit to the hatch transducer circuit.

This calibration of the distance slowdown circuit, prior to each slowdown of the elevator car, enables a low cost square root device 964 to be used, as the intermittent calibration takes care of long term drift associated with the lower cost square root devices. These lower cost square root devices are very stable for short periods of time, such as the time required to decelerate a high speed elevator car from its maximum speed to rest. Further, the calibration of the distance slowdown circuit is made in the low range of the output voltage, the least accurate region for a square root computing device.

The calibration of the distance slowdown circuit prior to each deceleration phase of a run of an elevator car, while primarily to reduce the cost of the square root device, has other advantages, as it allows the accuracy of the analog to digital converter to be relaxed. At the larger signal values, the error of the digital to analog converter 960 is roughly halved by taking the square root of its output, and at the lower signal values the calibration compensates for drift in the digital to analog converter. Special recalibration of the distance slowdown circuit 546 after the initial factory calibration, is eliminated, since recalibration occurs automatically during each run of the elevator car.

FIG. 18

Elevator safety codes require that a redundant and independent means be provided for slowdown of the car in the vicinity of the terminal floors. This terminal slowdown means provides the functions of monitoring for possible loss of control, and in the event loss of control is detected, it provides an auxiliary speed pattern for the motor controller which brings the car to a stop. The prior art terminal slowdown devices commonly utilize two series of cam actuated switches, one series located on the selector carriage, and the other series on the elevator car. As the elevator car moves towards a terminal floor, a cam located in the shaft opens the switches on the car in sequence. If the selector carriage is moving properly, as required for normal car slowdown, there is a corresponding contact closing on the selector. Should the selector fail to move, a monitoring circuit initiates terminal slowdown. An auxiliary slowdown pattern is generated by a cam driven distance sensor located on the top of the car. While this prior art arrangement is effective, it requires a delicate adjustment of the slanted cam which drives the switches and distance sensors on the car. The deflection of the sensors arm is small compared with the very long distances

required to slow the car, making it necessary to use two cams and two sensors in some high speed elevator systems.

FIG. 18 is a schematic diagram of a terminal slowdown circuit which may be used for the terminal slowdown circuit 558 shown in block form in FIG. 12, which circuit eliminates the series of cam operated switches and distance sensor used in the prior art. In general, the terminal slowdown circuit 558 shown in FIG. 18 utilizes notched plates disposed in the hatchway, one near each terminal, such as the notched plate 62 shown in FIG. 1, and the notched plate 1040 shown in FIG. 19. Plate 1040 has a series of holes or openings 1042 spaced such that a photoelectric or magnetic detector located on the car can detect their presence and initiate pulses for the terminal slowdown circuit 558. The holes or openings 1042 are spaced such that if the car is slowing down with a constant rate of deceleration, the time elapsed as the car travels from one opening to the next stays constant. If the car is not decelerating, or the deceleration rate of the car is not within acceptable limits, the time between the spaced openings will be shorter than normal, and a monitoring circuit in the terminal slowdown circuit 558 will detect this overspeed condition and cause the car to initiate terminal slowdown.

The same blade 1040 used to detect overspeed is used to generate the auxiliary speed pattern when an overspeed condition is detected. The difference between the rate at which the pulses are provided in response to a detector passing the blade 1040, and a predetermined rate corresponding to the maximum allowable slowdown rate, gives the speed error. The spacing of the openings in the blade sets the predetermined slowdown rate, with any deviation from the slowdown rate automatically providing an unbalance which is converted to a unidirectional speed error signal. This speed error signal may be used to directly feed the motor controller. Alternatively, the speed error signal may be added to the actual speed of the car, measured by such means as a conventional tachometer, to obtain a speed pattern which may be directly substituted for the normal speed pattern.

More specifically, the terminal slowdown circuit 558 shown in FIG. 18 includes a slowdown blade 1040 having spaced notches or openings 1042 therein, with the spacing between successive openings being selected to provide a predetermined speed profile which substantially matches the normal deceleration rate of the elevator car. FIG. 19 illustrates a typical speed profile curve 1043.

While it is preferable that the slowdown blade 1040 be mounted in the hatchway near the terminal which it is to monitor for overspeed, with the pick-up device on the car, it would also be suitable to mount the blade on the car with a pick-up device disposed adjacent to the terminal to be monitored.

Pick-up means 1044 is provided for detecting the presence of the notches or holes 1042. Pick-up means 1044 may be of any suitable type, such as the photoelectric device illustrated in FIG. 18 which includes a source 1046 of electromagnetic radiation directed towards and spaced from a detector 1048, such that the discontinuities of the blade 1040 pass therebetween when the car is travelling in the hatchway. The source 1046, for example, may be a light emitting diode, a glow lamp, a neon lamp, or the like, and the detector

1048 may be a phototransistor, a photodiode, a photoresistor, or the like. The pick-up means 1044 may also be of the magnetic type, using proximity detector principles, which requires a single coil, or transformer principles which uses two coils.

Detector 1048 includes means for generating pulses as the discontinuities of the blade 1040 and detector 1048 move relative to one another, which pulses are applied to input terminal PLSDP of the terminal slowdown circuit 558. The PLSDP pulses are amplified in amplifier 1050 and applied to a monostable multivibrator 1052. The output of the monostable multivibrator 1052 is a series of constant width pulses spaced according to the rate pulses are received from the amplifier 1050. The pulses from the monostable multivibrator 1052 are used to gate a switch 1053, which has one side connected to a positive source 1055 of unidirectional potential via resistor 1057, and its other side is connected to ground. Switch 1053 may be a transistor, or the like. A low pass filter amplifier 1054 is connected to the junction 1051 between the switch 1053 and resistor 1057. The filter amplifier 1054 may be an operational amplifier having its inverting input connected to junction 1051 via resistor 1059. Its non-inverting input is connected to a source 1061 of positive unidirectional potential via an adjustable resistor 1063. Parallel connected capacitor 1065 and resistor 1067 are connected in the feedback loop of the operational amplifier.

In the absence of a pulse from the monostable multivibrator 1052, switch 1053 is open, and the positive source 1055 is connected to the inverting input of filter amplifier 1054. When a pulse is received from the monostable multivibrator 1052, switch 1053 closes to connect the inverting input of filter amplifier 1054 to ground. When the slowdown of the car is normal, the low pass filter amplifier provides a constant unidirectional output voltage which is adjusted to zero, as there is no speed error. If the speed of the car exceeds the predetermined speed profile, the pulse rate applied to switch 1053 increases, which increases the relative time the switch 1053 is connected to ground, making the effective input voltage less positive and the output voltage of the filter amplifier 1054 more positive.

The output of the low pass filter amplifier 1054 is applied to comparator means 1056, such as an operational amplifier, with the output of the low pass filter 1054 being connected to the non-inverting input of the operational amplifier 1056. A reference voltage V_1 comprising a source 1058 of unidirectional voltage and a voltage divider 1060, is applied to the inverting input of operational amplifier 1056. The magnitude of the reference voltage V_1 is the magnitude which would be developed by the low pass filter when the elevator car is exceeding a selected maximum allowable speed as it approaches the terminal. Thus, when the output of the low pass filter 1054 is below the reference voltage, the output of the operational amplifier 1056 will be negative, or at the logic ZERO level. When the output of the low pass filter reaches the magnitude of the reference voltage, the output of the operational amplifier 1056 will switch to a positive polarity, or logic ONE level, which is inverted by inverter 1049, providing a low or true signal at output terminal SPSW, which terminal is connected to the driver circuit 552 shown in FIG. 12. A true SPSW signal indicates an overspeed condition near a terminal.

The output of low pass filter amplifier 1054 is connected to a second comparator 1062, which may be an operational amplifier, with the output of filter amplifier 1054 connected to the non-inverting input of operational amplifier 1062. The inverting input of operational amplifier 1062 is connected to a reference voltage V_2 which includes a source 1064 of unidirectional potential and a voltage divider 1066. The reference voltage V_2 applied to the operational amplifier 1062 is higher than the reference voltage V_1 applied to operational amplifier 1056, with its magnitude being selected to represent the car speed at which an emergency stop of the elevator car should be initiated. In the event of an emergency stop, the elevator car should not be restarted until maintenance personnel have had an opportunity to check the installation. Therefore, if comparator 1062 is switched to a positive output by the output of the filter amplifier 1054 reaching the reference voltage level of comparator 1062, a memory circuit 1068 may be triggered to retain the emergency stop signal until it is reset by maintenance personnel. A memory circuit which may be used includes a flip-flop 1070 having cross-coupled NAND gates 1072 and 1074, an inverter and a normally open reset pushbutton 1082. The output of comparator 1062 is applied to an input of NAND gate 1072 via inverter 1076, the output of NAND gate 1072 is connected to an output terminal TOVSP, which is connected to emergency stop means (not shown), and an input of NAND gate 1074 is connected to ground 1080 via pushbutton 1082.

Under normal circuit conditions, flip-flop 1070 is enabled with a logic ONE at the input of NAND gate 1074, due to the open pushbutton, and the output of comparator 1062, being low, applies a logic ONE to the input of NAND gate 1072 via inverter 1076. The output terminal TOVSP is thus at the logic ZERO level. If an emergency overspeed condition is detected by comparator 1062, switching its output positive or high, flip-flop 1070 is triggered to provide a high or true signal at output terminal TOVSP. The flip-flop will remain in this condition until pushbutton 1082 is manually actuated to reset the flip-flop 1070.

FIGS. 20A and 20B are graphs which plot voltage versus time and illustrate the operation of terminal slowdown circuit 558 during a normal approach to a terminal, and during an overspeed approach, respectively. In FIG. 20A, the square wave 1084 represents the voltage input to the filter amplifier 1054, and the line 1086 represents the output voltage of the filter amplifier 1054. As illustrated, the square pulses 1084, which are the complement of the square wave output of the monostable multivibrator 1052, are being produced by the monostable multivibrator at a constant rate, which when passed through filter 1054 provides a unidirectional signal 1086 having a magnitude of substantially zero volts. The magnitudes of the reference voltages V_1 and V_2 applied to comparators 1056 and 1062 are indicated in FIG. 20, but the slowdown, being normal, provides a voltage 1086 which is below these reference levels.

FIG. 20B, on the other hand, illustrates an overspeed condition near the terminal. Instead of the PLSDP pulses being generated at a predetermined constant rate, the rate is too fast, or increasing which results in the square wave input voltage to the filter amplifier, represented by curve 1084', being at zero or ground for successively greater periods of time. This results in a

lower average input voltage, which increases the output voltage of the filter amplifier along curve 1086'. When the overspeed condition, compared with the built in speed profile of the slowdown blade 1040, is great enough, the output voltage of the filter amplifier 1054, which is the speed error voltage V_{SE} , reaches the magnitude of the reference voltage V_1 , which generates a true SPSW signal for driver 552. If the overspeed condition is such that the speed error signal V_{SE} reaches the magnitude of the reference voltage V_2 , the emergency terminal overspeed signal TOVSP becomes true, which is used to initiate an emergency stop of the elevator car.

An important feature of the terminal slowdown circuit 558 is the fact that the same blade 1040 which is used to monitor and detect an overspeed condition near the terminal, is also used to generate the auxiliary speed pattern when an overspeed condition is detected. The output of the low pass filter amplifier 1054 is the speed error, and while it may be applied to the motor controller, it is preferable to independently develop an auxiliary speed pattern signal TSAN, by adding the speed error voltage V_{SE} to a voltage representing the actual speed of the car, such as the output voltage of a tachometer, which may be called signal V_{TACH} . Since the speed error is equal to the speed pattern reference voltage minus the tach voltage, an auxiliary speed pattern reference voltage may be developed by adding the speed error voltage V_{SE} to the tach voltage V_{TACH} .

As illustrated in FIG. 18, the development of an auxiliary speed reference signal TSAN is accomplished by summing the speed error voltage V_{SE} with the tach voltage V_{TACH} in a summing amplifier 1090. Summing amplifier 1090 may be an operational amplifier having its non-inverting input connected to ground via resistor 1092, its inverting input connected to the speed error signal and tach signal via resistors 1094 and 1096, respectively. The tach output includes rectifier means 1098, such as a bridge rectifier, for providing a unidirectional voltage which may be summed with the unidirectional speed error voltage V_{SE} . The tach voltage V_{TACH} is negative, i.e., tied to the negative side of the bridge 1098. The speed error voltage V_{SE} will not exceed the tach voltage V_{TACH} , and thus the output signal TSAN will be positive.

FIG. 21

FIG. 21 is a schematic diagram of a driver circuit which may be used for the driver circuit 552 shown in block form in FIG. 12. While it is preferable that the speed pattern signals from the different sources hereinbefore described be mixed or blended together at the transition point between the signals, as disclosed in the hereinbefore mentioned U.S. Pat. No. 3,651,892, this blending or programmed transition between signals is not essential to the present invention and the driver 552 will be described without this feature. The calibration circuit hereinbefore described relative to the distance slowdown circuit 546 insures that the distance slowdown speed pattern signal DSAN will match the hatch transducer signal HTAN at transfer, without signal mixing, and this matching of signals occurs during landing where dissimilarities in the signals being switched would be the most noticeable to the passengers. Therefore, signal mixing is not essential in order to achieve comfortable operation of the elevator system described in this application.

More specifically, driver circuit 552 includes input terminals NL16, LAZO, MINA, START, TOP, BOTTOM, SPSW, and DCL, and output terminals DL2, TRSW, DSSW, HIS and TDS. Input terminal NL16 is connected to reversible counter 544, and, as hereinbefore described, signal NL17 is low or true when the car is landing and within 16 inches of the floor at which it is to stop. Input terminal LAZO is connected to a switch in the hatchway, which switch provides a low signal when the car is within 10 inches of a floor. Input terminal MINA is connected to the time ramp generator 542, and signal MINA goes low when the car reaches maximum deceleration during the slowdown portion of a run. Input terminal START is connected to logic circuit 540. The START signal, which is the same as ACCX, is high or true when a request is made to accelerate the car, and it remains true until the car is requested to stop at a floor. The TOP and BOTTOM input terminals are connected to switches in the hatchway, which provide high signals except when the car is within 18 inches of the top and bottom terminals, respectively. Input terminal SPSW is connected to the terminal slowdown circuit 558, with the SPSW signal being high except when car overspeed is detected near a terminal. Input terminal DCL is responsive to limit switches on the car and hatch doors, with signal DCL being high when both the car and hatch doors are closed.

Output terminal DL2 provides a low signal when the car is running, and a high signal when the car is landing and is in the landing zone, i.e., plus or minus 10 inches from the floor at which it is to stop.

Output signals TRSW, DSSW, and HIS, provide low or true signals at the appropriate times during a normal run in order to switch analog switches 548, 550 and 556, respectively, shown in FIG. 12, to provide the proper speed pattern signal for each portion of a car run. Output terminal TSD provides a low signal when an overspeed condition is detected near a terminal. Output terminal TSD is connected to analog switch 560 shown in FIG. 12, and also to various circuit points in the floor selector, hereinbefore described.

Driver circuit 552 includes NAND gates 1102, 1104, 1106, 1108, 1110, 1112, 1114 and 1116, inverters 1118, 1120, 1122, 1124, 1126 and 1128, and flip-flops 1130, 1132 and 1134. Flip-flops 1130, 1132 and 1134 may each be of the cross-coupled NAND gate type, with flip-flop 1130 including NAND gates 1136 and 1138, flip-flop 1132 including NAND gates 1140 and 1142, and flip-flop 1134 including NAND gates 1144 and 1146.

Input terminal NL16 is connected to an input of NAND gate 1102 via inverter 1118, and the output of gate 1102 is connected to an input of NAND gate 1136 of flip-flop 1130. Input terminal LAZO is connected to inputs of NAND gates 1102 and 1106 via inverters 1120 and 1122, respectively. The output of NAND gate 1106 is connected to an input of NAND gate 1140 of flip-flop 1132. Input terminal MINA is connected to an input of NAND gate 1144 of flip-flop 1134. The START input terminal is connected to inputs of NAND gates 1108 and 1110, with the outputs of gates 1108 and 1110 being connected to inputs of NAND gates 1138 and 1146 of flip-flops 1130 and 1134, respectively. The TOP and BOTTOM input terminals are connected to inputs of NAND gate 1104, and the output of gate 1104 is connected to an input of NAND gate

1106. The output of NAND gate 1106 is connected to an input of NAND gate 1136 of flip-flop 1130 and to an input of NAND gate 1140 of flip-flop 1132. Input terminal SPSW is connected to an input of NAND gate 1142 of flip-flop 1132. Input terminal DCL is connected to an input of NAND gate 1110. The output of NAND gate 1140 of flip-flop 1132 is connected to inputs of NAND gates 1108, 1102, 1112, 1114 and 1116, and also to output terminal TDS. The output of NAND gate 1138 of flip-flop 1130 is connected to an input of NAND gate 1144 of flip-flop 1134, to output terminal DL2 and an input of NAND gate 1116 via inverter 1124, and to inputs of NAND gates 1112 and 1114 via inverters 1124 and 1126. The output of NAND gate 1146 of flip-flop 1134 is connected to an input of NAND gate 1112, and via inverter 1128 to an input of NAND gate 1114. The outputs of NAND gates 1112, 1114 and 1116, are connected to output terminals TRSW, DSSW and HIS, respectively.

In the operation of driver circuit 552, it will be assumed that the elevator car is at the bottom terminal with the doors closed and no request to run. Signals NL16, LAZO, START and BOTTOM will be low, and signals MINA, TOP, SPSW, and DCL will be high. NAND gate 1138 of flip-flop 1130 has a low output, inverted to a logic ONE by inverter 1124 to provide a high DL2 signal. NAND gate 1146 of flip-flop 1134 has a low output, and NAND gate 1140 of flip-flop 1132 has a high output to provide a high TDS signal. Combining these outputs of flip-flops 1130, 1132 and 1134 in NAND gates 1112, 1114 and 1116, results in only NAND gate 1116 having two high inputs. Thus, signals TRSW and DSSW will be high and signal HIS will be low or true. Thus, the speed pattern will be under control of the hatch transducer, as required when the car is at a floor.

When a request is made to accelerate the car, signal ACCX from the floor selector 34 goes low, and logic circuit 540 of the speed pattern generator 48 generates a high START signal. When the START signal goes high, NAND gate 1108 switches to a low output, switching the output of NAND gate 1138 of flip-flop 1130 high, and providing a low DL2 signal, which corresponds to RUN. A high START signal also switches NAND gate 1110 to a low output, triggering flip-flop 1134 to provide a high output from NAND gate 1146. NAND gate 1112 now has all high inputs, providing a low TRSW signal, while NAND gate 1116 now has a low input, providing a high HIS signal. The switching of signals TRSW and HIS to their low and high states, respectively, switches analog gates 548 and 556 to their closed and open conditions, respectively, transferring the speed pattern from the hatch transducer circuit 554 to the time ramp generator circuit 542.

The car thus moves away from the bottom floor under the influence of the speed pattern from the time ramp generator, and signals NL16, LAZO and BOTTOM switch high.

When a request is made by the floor selector to stop the car at a floor, signal ACCX goes high and the signal START goes low. NAND gates 1108 and 1110 switch high, enabling flip-flops 1130 and 1134, respectively. Signal TRSW remains low, as the initial slowdown of the car from maximum speed to maximum deceleration remains under control of the time ramp generator.

When maximum deceleration is reached, signal MINA produced by the time ramp generator goes low, triggering flip-flop 1134 to provide a low output from NAND gate 1146, driving NAND gate 1112 high and NAND gate 1114 low. This operates analog switches 548 and 550 shown in FIG. 12 to transfer the speed pattern from the time ramp generator 542 to the distance slowdown circuit 546.

When the car reaches a point 16 inches from the floor at which it is going to stop, signal NL16 goes low, and when the car reaches 10 inches from the floor, signal LAZO goes low, switching NAND gate 1102 to a low output and triggering flip-flop 1130 to provide low output from its NAND gate 1138. This switches signal DL2 high, corresponding to land, and it switches NAND gates 1114 and 1116 to high and low outputs, respectively. The output signal DSSW and HIS go high and low, respectively, switching analog switches 550 and 556 to connect the hatch transducer signal HTAN to the summing circuit 562, which brings the car into the landing.

In the event an overspeed condition is detected near a terminal, terminal slowdown circuit 558 provides a SPSW signal, as hereinbefore described, which triggers flip-flop 1132 to provide a low output from NAND gate 1140. This provides a low TSD signal for analog switch 560, and it drives NAND gates 1112, 1114 and 1116 high, transferring the speed pattern from conventional control to the auxiliary speed pattern signal TSAN provided by the terminal slowdown circuit 558.

In summary there has been disclosed a new and improved speed pattern generator for elevator systems which may be used to provide a speed reference signal for a complete run, or only for certain phases thereof, depending on the maximum car speed. Signals representing maximum jerk are developed directly, and not inferentially, and the directly developed maximum jerk signals are incorporated into a time dependent speed reference pattern. Regardless of how fast the elevator control system responds, the preselected maximum jerk cannot be exceeded.

I claim as my invention.

1. A speed pattern generator for providing a jerk controlled, time dependent speed pattern signal, comprising:

- first means providing a step signal switchable between first and second magnitudes representative of maximum rate of change of acceleration,
- second means integrating said step signal to provide an acceleration signal,
- third means integrating said acceleration signal to provide a speed pattern signal,
- and fourth means for controlling the switching of said step signal in response to said acceleration signal and said speed pattern signal.

2. The speed pattern generator of claim 1 wherein the fourth means switches the step signal to a predetermined one of its first and second magnitudes during predetermined transitions between constant speed and constant acceleration portions of the speed pattern signal, and switches back and forth between the first and second magnitudes during portions of the speed pattern which provide constant parameters.

3. The speed pattern generator of claim 1 wherein the first and second magnitudes of the step signal provide first and second currents of opposite polarity.

4. The speed pattern generator of claim 3 wherein the fourth means controls the switching of the step signal to average the first and second currents to zero during the portions of the speed pattern which represent constant parameters.

5. The speed pattern generator of claim 1 wherein the fourth means includes acceleration and speed feedback loops connected to be responsive to the second and third means, respectively.

6. The speed pattern generator of claim 5 including means interconnecting the acceleration and speed feedback loops, such that the signal in the acceleration feedback loop modifies the signal in the speed feedback loop.

7. The speed pattern generator of claim 6 wherein the acceleration and speed feedback loops each include means providing reference signals, and comparator means which compares the feedback signal with a reference signal, and wherein the acceleration feedback signal modifies the speed feedback signal to reduce the time required for the speed feedback signal to reach the level of its reference signal.

8. The speed pattern generator of claim 1 wherein the fourth means includes acceleration reference and speed reference signals, acceleration and speed comparator means for comparing said acceleration reference and speed reference signals with the acceleration and speed pattern signals, respectively, and means for switching the step signal in response to said acceleration and speed comparator means.

9. The speed pattern generator of claim 8 wherein the speed pattern is initiated by a change in the magnitude of the speed reference signal from a first to a second magnitude.

10. The speed pattern generator of claim 9 wherein the speed pattern includes a slowdown phase, with the slowdown phase of the speed pattern being initiated by a change in the magnitude of the speed reference signal from its second to its first magnitude.

11. The speed pattern generator of claim 8 wherein the speed pattern signal includes a zero speed phase, a jerk controlled first transition phase, and a constant acceleration phase, with the first transition phase being initiated by a change in the magnitude of the speed reference signal and terminated by the acceleration comparator means when the acceleration signal reaches the level of the acceleration reference.

12. The speed pattern generator of claim 8 wherein the speed pattern signal includes a constant acceleration phase, a jerk controlled second transition phase, and a constant speed phase, and including means modifying the speed pattern signal applied to the speed comparator means with the acceleration signal, to cause the modified speed signal to reach the level of the reference signal earlier than would the unmodified speed signal, to enable the second transition phase to interconnect the constant acceleration and constant speed phases without overshoot.

13. The speed pattern generator of claim 8 wherein the speed pattern signal includes a constant speed phase, a jerk controlled their transition phase, and a constant deceleration phase, and wherein the comparator means includes a deceleration comparator, with the third transition phase being initiated by a change in the magnitude of the speed reference signal and terminated by the deceleration comparator when the acceleration signal reaches the level of the acceleration reference.

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14. The speed pattern generator of claim 8 wherein the speed pattern signal includes a constant deceleration phase, a jerk controlled fourth transition phase, and a zero speed phase, and including means modifying the speed pattern signal applied to the speed comparator means with the acceleration signal, to cause the modified speed signal to reach the level of the reference signal earlier than would the unmodified speed signal, to enable the fourth transition phase to smoothly interconnect the constant deceleration and zero speed phases.

15. A speed pattern generator for providing a jerk controlled, time dependent speed pattern signal for elevator motor control which controls the travel of an elevator car relative to a structure, comprising:

first means providing a step signal switchable between first and second magnitudes representing maximum jerk,

second means integrating said step signal to provide an acceleration signal,

third means integrating said acceleration signal to provide a speed pattern signal,

a speed feedback loop responsive to the speed pattern signal for providing a speed feedback signal, said speed feedback loop including speed reference means switchable between predetermined magnitudes, and speed comparator means connected to compare the speed feedback and speed reference signals and provide an output indicative of their relationship,

an acceleration feedback loop responsive to the acceleration signal for providing an acceleration feedback signal, said acceleration feedback loop including acceleration reference means, and first acceleration comparator means connected to compare the acceleration feedback signal and accelera-

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tion reference signal and provide an output indicative of their relationship,

logic means providing output signals responsive to the outputs of said speed and acceleration comparators,

and switching means connected to said logic means and said first means, switching the step signal to a selected magnitude in response to the output signal of the logic means during transitions between constant speed and constant acceleration to limit jerk during such transitions, and switching the step signal between its magnitudes at a rate which exceeds the response time of the elevator car, to maintain predetermined constant parameters during portions of the speed pattern when such parameters are to be kept constant.

16. The speed pattern generator of claim 15 including means modifying the speed feedback signal with the acceleration feedback signal, to reduce the time required for the speed feedback signal to reach the selected magnitude of the speed reference, and provide a jerk limited transition from a constant acceleration phase of the speed pattern to a constant speed phase without overshoot.

17. The speed pattern generator of claim 15 wherein the speed pattern signal includes acceleration and deceleration phases, the acceleration signal is of one polarity during the acceleration phase, and of the opposite polarity during the deceleration phase, and including second acceleration comparator means in the acceleration feedback loop connected to compare the deceleration signal with the acceleration reference signal and provide an output indicative of their relationship, and means connecting the output of said second acceleration comparator means to the logic means.

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